

Service Guide

**HP 16555A
110-MHz State/500-MHz
Timing Logic Analyzer**

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500-MHz Timing Logic Analyzer**

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The HP 16555A is a 110-MHz State/500-MHz Timing Logic Analyzer module for the HP 16500B Logic Analysis System. The HP 16555A offers high performance measurement capability.

Features

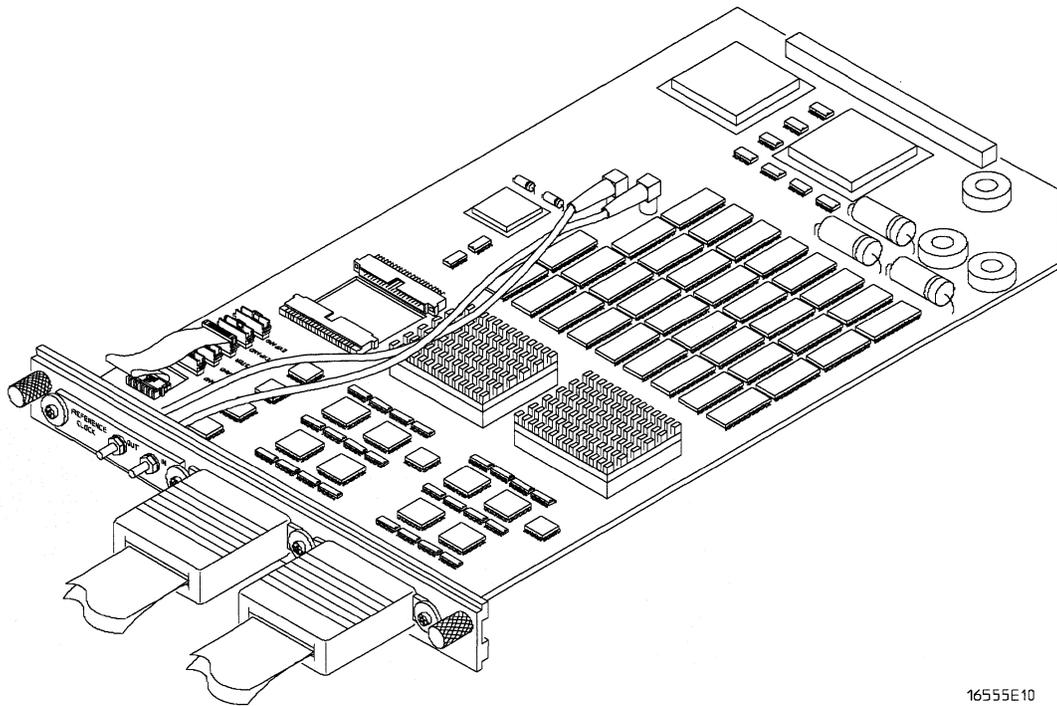
Some of the main features of the HP 16555A are as follows:

- 64 data channels
- 4 clock/data channels
- 1024K memory depth per channel
- 110 MHz maximum state acquisition speed
- 500 MHz maximum timing acquisition speed
- Expandable to 204 channels

Service Strategy

The service strategy for this instrument is the replacement of defective assemblies. This service guide contains information for finding a defective assembly by testing and servicing the HP 16555A state and timing analyzer module.

This module can be returned to Hewlett-Packard for all service work, including troubleshooting. Contact your nearest Hewlett-Packard Sales Office for more details.



16555E10

The HP 16555A Logic Analyzer

In This Book

This book is the service guide for the HP 16555A 110-MHz State/500-MHz Timing Logic Analyzer module. Place this service guide in the 3-ring binder supplied with your *HP 16500B Logic Analysis System Service Manual*.

This service guide is divided into eight chapters.

Chapter 1 contains information about the module and includes accessories for the module, specifications and characteristics of the module, and a list of the equipment required for servicing the module.

Chapter 2 tells how to prepare the module for use.

Chapter 3 gives instructions on how to test the performance of the module.

Chapter 4 contains calibration instructions for the module.

Chapter 5 contains self-tests and flowcharts for troubleshooting the module.

Chapter 6 tells how to replace the module and assemblies of the module and how to return them to Hewlett-Packard.

Chapter 7 lists replaceable parts, shows an exploded view, and gives ordering information.

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General Information

This chapter lists the accessories, the specifications and characteristics, and the recommended test equipment.

Accessories

The following accessories are supplied with the HP 16555A Logic Analyzer.

Accessories Supplied	HP Part Number
Probe Tip Assembly, Qty 4	01650-61608
Grabbers, Qty 4 packages	5090-4356
Extra Probe Leads, Qty 1 package	5959-9333
Extra Probe Grounds, Qty 4 packages	5959-9334
Probe Cable ID Clip, Qty 4	16500-41201
Probe Cables, Qty 2	16555-61606
Probe Cable and Pod Labels, Qty 1	01650-94310
Double Probe Adapter	16542-61607
Ferrite Core Assembly	16555-60001

Accessories Available

The accessories available for the HP 16555A are listed in the *Accessories for HP Logic Analyzers* brochure.

Specifications

The specifications are the performance standards against which the product is tested.

Minimum State Clock Pulse Width ¹	3.5 ns
Threshold Accuracy	± (100 mV + 3% of threshold setting)

Clock Scheme:

Single Clock, Single Edge:

Setup/Hold Time: ¹	0.0/3.5 ns through 3.5/0.0 ns, adjustable in 500-ps increments
Maximum State Speed	110 MHz ²
Minimum Master-to-Master Clock Time ¹	9.09 ns ²

Single Clock, Multiple Edges:

Setup/Hold Time: ¹	0.0/4.0 ns through 4.0/0.0 ns, adjustable in 500-ps increments
Maximum State Speed	100 MHz
Minimum Master-to-Master Clock Time ¹	10.0 ns

Multiple Clocks, Multiple Edges:

Setup/Hold Time: ¹	0.0/4.5 ns through 4.5/0.0 ns, adjustable in 500-ps increments
Maximum State Speed	100 MHz
Minimum Master-to-Master Clock Time ¹	10.0 ns

¹ Specified for an input signal $V_H = -0.9\text{ V}$, $V_L = -1.7\text{ V}$, and threshold = -1.3 V .

² An HP 16555A using operating system v2.xx has maximum state speed of 100 MHz and minimum Master-to-Master Clock Time of 10.0 ns for single-clock, single-edge clocking. 110-MHz single-clock state acquisition mode is available with operating system v3.00 or higher.

The version of the operating system software must be compatible with the programmable logic device that is the CPU interface. To verify the version of the programmable device, first locate the device, which is at the front of the HP 16555A board. If the programmable device has part number 16555-80001, then the device is compatible with operating system version v2.xx, and the maximum state acquisition speed is 100 MHz. If the device has part number 16555-80002 or higher, then the device is compatible with operating system v3.00 or higher, and the maximum state acquisition speed is 110 MHz for single-clock, single-edge clocking mode. The maximum state acquisition speed is 100 MHz for all other clocking modes.

Characteristics

The characteristics are not specifications, but are included as additional information.

	Full Channel	Half Channel *
Maximum State Clock Rate	110 MHz	Not applicable
Maximum Conventional Timing Rate	250 MHz	500 MHz
Channel Count per Card	68	34
Channel Count per Three-Card Module	204	102
Memory Depth	1024K	2048K

* Half channel mode is only available for timing analysis.

Supplemental Characteristics

Probes

Input Resistance	100 k Ω , \pm 2%
Input Capacitance	~ 8 pF
Minimum Voltage Swing	500 mV, peak-to-peak
Maximum Input Voltage	\pm 40 V
Threshold Range	\pm 6.0 V, adjustable in 50-mV increments

State Analysis

State/Clock Qualifiers	4
Time Tag Resolution *	8 ns
Maximum Time Count Between States	34 seconds
Maximum State Tag Count *	4.29×10^9

Timing Analysis

Sample Period Accuracy	0.01 % of sample period
Channel-to-Channel Skew	2 ns, typical
Time Interval Accuracy	\pm [sample period + channel-to-channel skew + (0.01%)(time reading)]

Triggering

Sequencer Speed	125 MHz, maximum
State Sequence Levels	12
Timing Sequence Levels	10
Maximum Occurrence Counter Value	1,048,575
Pattern Recognizers	10
Maximum Pattern Width	68 channels in a one-card configuration. 204 channels in a three-card configuration.
Range Recognizers	2
Range Width	32 bits each
Timers	2
Timer Value Range	400 ns to 500 seconds
Glitch/Edge Recognizers	2 (timing only)
Maximum Glitch/Edge Width	68 channels in a one-card configuration. 204 channels in a three-card configuration.

*Maximum state clock rate with time or state tags on is 110 MHz. When all pods are assigned to a state or timing machine, time or state tags halve the memory depth.

Measurement and Display Functions

Arming Each module can be armed by the RUN key, by the external PORT IN, or by another module via the Intermodule Bus (IMB).

Displayed Waveforms 24 lines maximum, with scrolling across 96 waveforms.

Measurement Functions

Run/Stop Functions Run Starts acquisition of data in specified trace mode.

Stop In single trace mode or the first run of a repetitive acquisition, STOP halts acquisition and displays the current acquisition data. For subsequent runs in repetitive mode, STOP halts acquisition of data and does not change the current display.

Trace Mode Single mode acquires data once per trace specification. Repetitive mode repeats single mode acquisitions until stop is pressed or until the time interval between two specified patterns is less than or greater than a specified value, or within or not within a specified range.

Indicators

Activity Indicators Provided in the Configuration and Format menus for identifying high, low, or changing states on the inputs.

Markers Two markers (X and 0) are shown as dashed lines on the display.

Trigger Displayed as a vertical dashed line in the Timing Waveform display and as line 0 in the State Listing display.

Data Entry/Display

Labels Channels may be grouped together and given a 6-character name. Up to 126 labels in each analyzer may be assigned with up to 32 channels per label.

Display Modes State listing, State Waveforms, Chart, Compare Listing, Compare Difference Listing, Timing Waveforms, and Timing Listings. State Listing, Timing Waveforms and Oscilloscope Waveforms can be time-correlated on the same displays.

Timing Waveform Pattern readout of timing waveforms at X or 0 marker.

Bases Binary, Octal, Decimal, Hexadecimal, ASCII (display only), Two's Complement, and User-defined symbols.

Symbols 1,000 maximum. Symbols can be downloaded over RS-232 or HP-IB.

Marker Functions

Time Interval The X and 0 markers measure the time interval between one point on a timing waveform and trigger, two points on the same timing waveform, two points on different waveforms, or two states (time tagging on).

Delta States (state analyzer only) The X and 0 markers measure the number of tagged states between one state and trigger or between two states.

Patterns The X and 0 markers can be used to locate the *n*th occurrence of a specified pattern from trigger, or from the beginning of data. The 0 marker can also find the *n*th occurrence of a pattern from the X marker.

Statistics X and 0 marker statistics are calculated for repetitive acquisitions. Patterns must be specified for both markers and statistics are kept only when both patterns can be found in an acquisition. Statistics are minimum X to 0 time, maximum X to 0 time, average X to 0 time, and ratio of valid runs to total runs.

Auxiliary Power

Power Through Cables 1/3 amp at 5 V maximum per cable

Operating Environment

Temperature Instrument, 0 °C to 55 °C (+32 °F to 131 °F).
Probe lead sets and cables,
0 °C to 65 °C (+32 °F to 149 °F).

Humidity Instrument, probe lead sets, and cables, up to
95% relative humidity at +40 °C (+122 °F).

Altitude To 4600 m (15,000 ft).

Vibration Operating: Random vibration 5 to 500 Hz,
10 minutes per axis, ≈ 0.3 g (rms).
Non-operating: Random vibration 5 to 500 Hz,
10 minutes per axis, ≈ 2.41 g (rms);
and swept sine resonant search, 5 to 500 Hz,
0.75 g (0-peak), 5 minute resonant dwell
at 4 resonances per axis.

Recommended Test Equipment

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part	Use*
Pulse Generator	110 MHz, 3.5 ns pulse width, < 600 ps rise time	HP 8131A Option 020	P,T
Digitizing Oscilloscope	≥ 6 GHz bandwidth, < 58 ps rise time	HP 54121T	P
Function Generator	Accuracy $\leq (5)(10^{-6}) \times$ frequency, DC offset voltage ± 6.3 V	HP 3325B Option 002	P
Digital Multimeter	0.1 mV resolution, 0.005% accuracy	HP 3458A	P
BNC-Banana Cable		HP 11001-60001	P
BNC Tee	BNC (m)(f)(f)	HP 1250-0781	P
Cable	BNC (m-m) 48 inch	HP 10503A	P
SMA Coax Cable (Qty 3)	≥ 18 GHz bandwidth	HP 8120-4948	P
BNC Coax Cable	BNC (m-m), >2 GHz bandwidth	HP 8120-1840	P
Adapter (Qty 4)	SMA(m)-BNC(f)	HP 1250-1200	P
Adapter	SMA(f)-BNC(m)	HP 1250-2015	P
Coupler	BNC (m-m)	HP 1250-0216	P
20:1 Probes (Qty 2)		HP 54006A	P
BNC Test Connector, 17x2 (Qty 1)**			P
BNC Test Connector, 6x2 (Qty 4)**			P,T

* A = Adjustment P = Performance Tests T = Troubleshooting

** Instructions for making these test connectors are in chapter 3, "Testing Performance."



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Preparing For Use

This chapter gives you instructions for preparing the logic analyzer module for use.

Power Requirements

All power supplies required for operating the logic analyzer are supplied through the backplane connector in the mainframe.

Operating Environment

The operating environment is listed in chapter 1. Note the non-condensing humidity limitation. Condensation within the instrument can cause poor operation or malfunction. Provide protection against internal condensation.

The logic analyzer module will operate at all specifications within the temperature and humidity range given in chapter 1. However, reliability is enhanced when operating the module within the following ranges:

- Temperature: +20 °C to +35 °C (+68 °F to +95 °F)
- Humidity: 20% to 80% non-condensing

Storage

Store or ship the logic analyzer in environments within the following limits:

- Temperature: -40 °C to + 75 °C
- Humidity: Up to 90% at 65 °C
- Altitude: Up to 15,300 meters (50,000 feet)

Protect the module from temperature extremes which cause condensation on the instrument.

To inspect the module

1 Inspect the shipping container for damage.

If the shipping container or cushioning material is damaged, keep them until you have checked the contents of the shipment and checked the instrument mechanically and electrically.

2 Check the supplied accessories.

Accessories supplied with the module are listed in chapter 1, "Accessories Supplied."

3 Inspect the product for physical damage.

Check the module and the supplied accessories for obvious physical or mechanical defects. If you find any defects, contact your nearest Hewlett-Packard Sales Office. Arrangements for repair or replacement are made, at Hewlett-Packard's option, without waiting for a claim settlement.

To prepare the mainframe

CAUTION

Turn off the mainframe power before removing, replacing, or installing the module.

CAUTION

Electrostatic discharge can damage electronic components. Use grounded wriststraps and mats when performing any service to this module.

1 Turn off the mainframe power switch, then unplug the power cord. Disconnect any input or output connections.

2 Plan your module configuration.

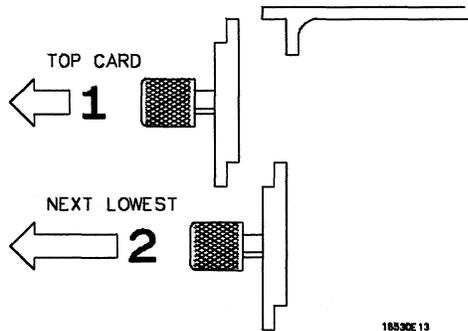
If you are installing a one-card module, use any available slot in the mainframe.

If you are installing a multicard module, use adjacent slots in the mainframe.

3 Loosen the thumb screws.

Cards or filler panels below the slots intended for installation do not have to be removed.

Starting from the top, loosen the thumb screws on filler panels and cards that need to be moved.



4 Starting from the top, pull the cards and filler panels that need to be moved halfway out.

CAUTION

All multicard modules will be cabled together. Pull these cards out together.

5 Remove the cards and filler panels.

Remove the cards or filler panels that are in the slots intended for the module installation.

Push all other cards into the card cage, but not completely in. This is to get them out of the way for installing the module.



Some modules for the Logic Analysis System require calibration if you move them to a different slot. For calibration information, refer to the manuals for the individual modules.

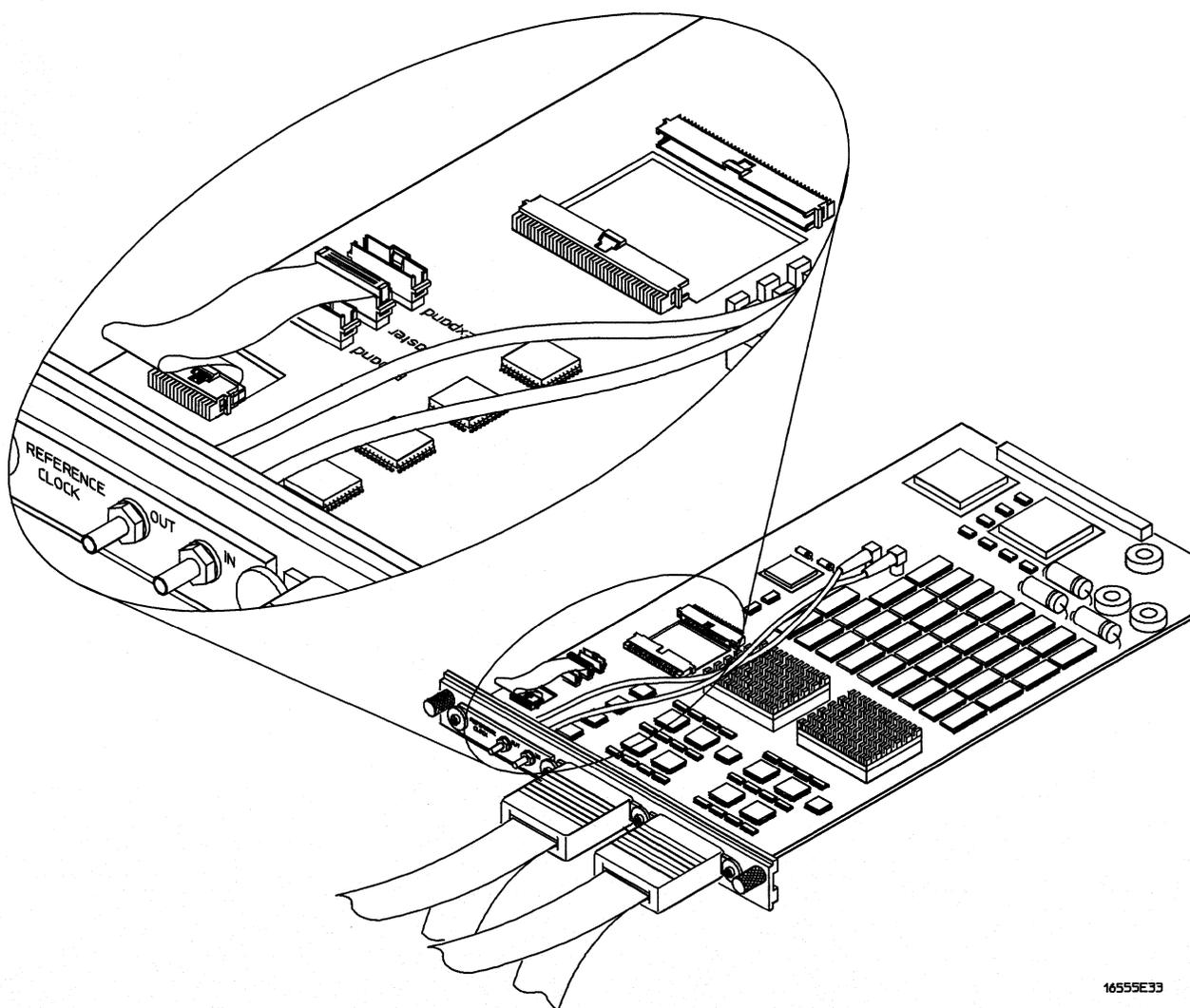
To configure a one-card module

- When shipped separately, the module is configured as a one-card module. The cables should be connected as shown in the figure.
- To configure a multicard module into one-card modules, remove the cables connecting the cards. Then connect the free end of the 2x10 cable to the connector labeled "Master" (J6) on each card (see figure below).

CAUTION

If you pull on the flexible ribbon part of the 2x10 cable, you might damage the cable assembly. Using your thumb and finger, grasp the ends of the cable connector. Apply pressure to the ends of the cable connector to disengage the metal locking tabs of the connector from the cable socket on the board. Then pull the connector from the cable socket.

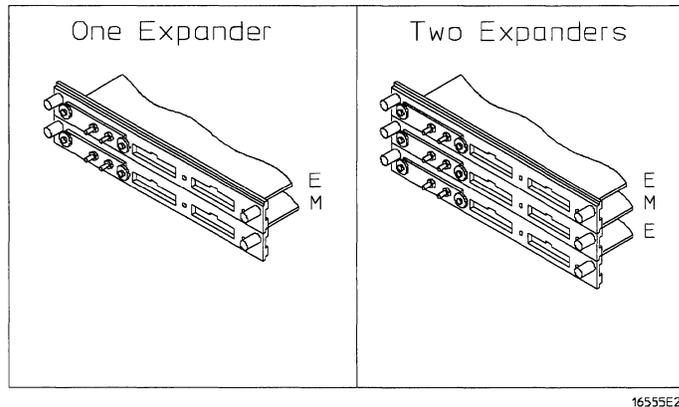
Save unused cables for future configurations.



16555E33

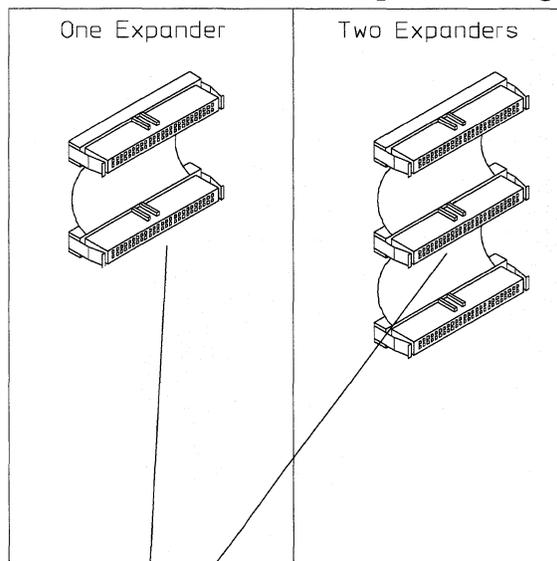
To configure a multcard module

- 1 Plan the configuration. Multicard modules can only be connected as shown in the illustration. Select the card that will be the master card, and set the remaining cards aside.



16555E23

- 2 Obtain two 2x25 cables from the accessory pouch that match the number of expanders being configured. The illustration shows the cables that are available and which cable is used in each expander configuration.

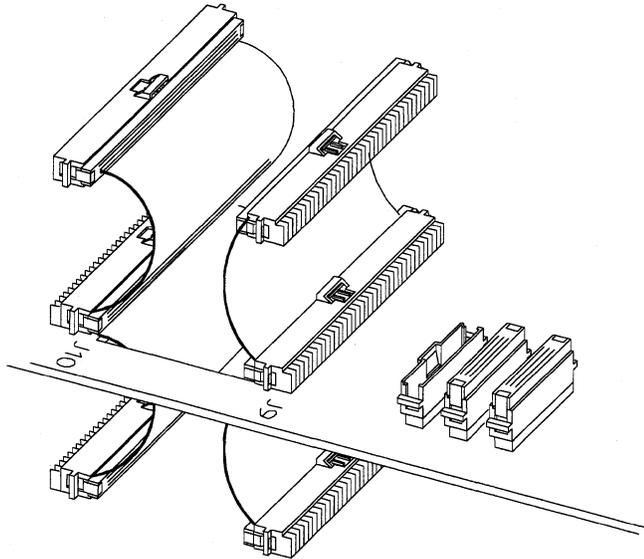


16555E24

This connector is plugged into the Master Card.

Preparing for Use
To configure a multicard module

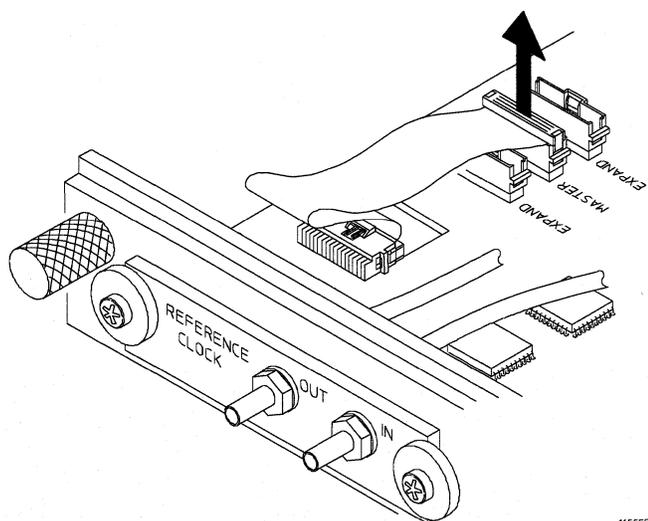
- 3 Look at the illustration in the previous step. The illustration shows which of the cable connectors is plugged into the master card. Plug one 2x25 cable into the master card J9. Observe which cable connector (as shown in the illustration) is plugged into J9. Follow the same procedure to connect the second 2x25 cable into the master card J10.



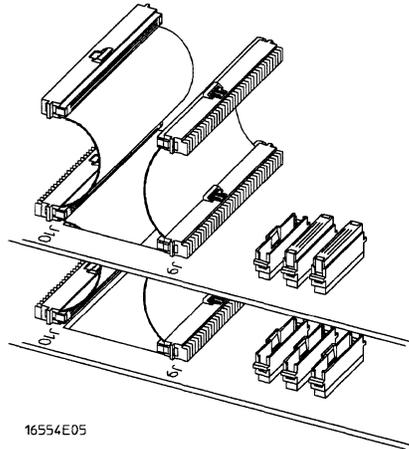
- 4 On the expander cards, disconnect the end of the 2x10 cable that is plugged into the connector labeled "Master."

CAUTION

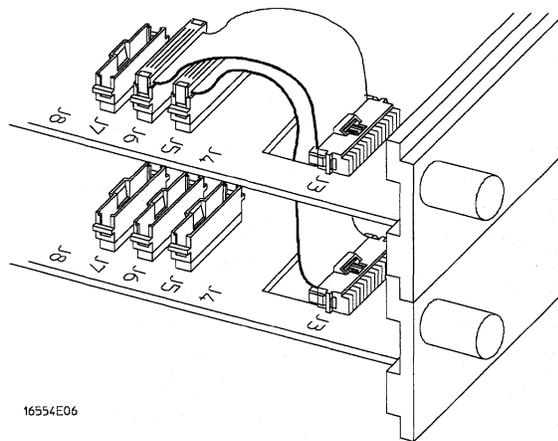
If you pull on the flexible ribbon part of the 2x10 cable, you might damage the cable assembly. Using your thumb and finger, grasp the ends of the cable connector. Apply pressure to the ends of the cable connector to disengage the metal locking tabs of the connector from the cable socket on the board. Then pull the connector from the cable socket.



- 5 Place the master card above an expander card, if one is used. Plug the 2x25 cables into J9 and J10 of the expander card.

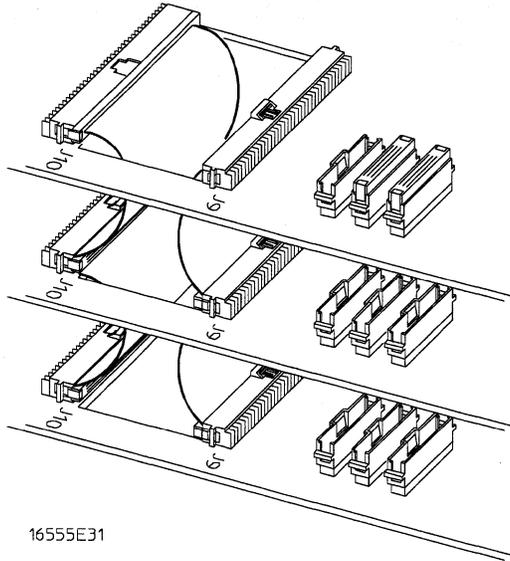


- 6 Feed the free end of the 2x10 cable of the expander cards through the access holes to the master card. Plug the 2x10 cable into J5 on the master card.

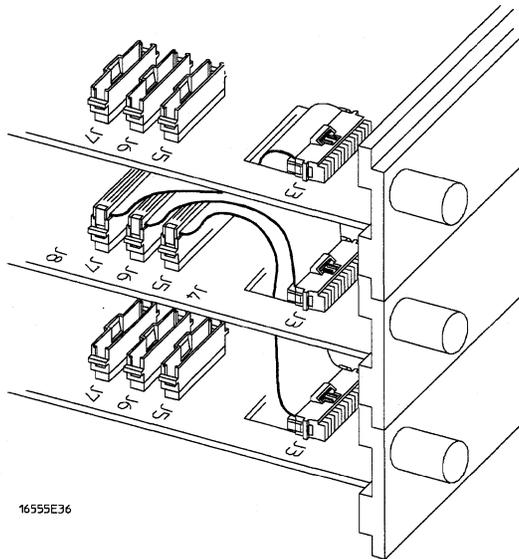


Preparing for Use
To configure a multicard module

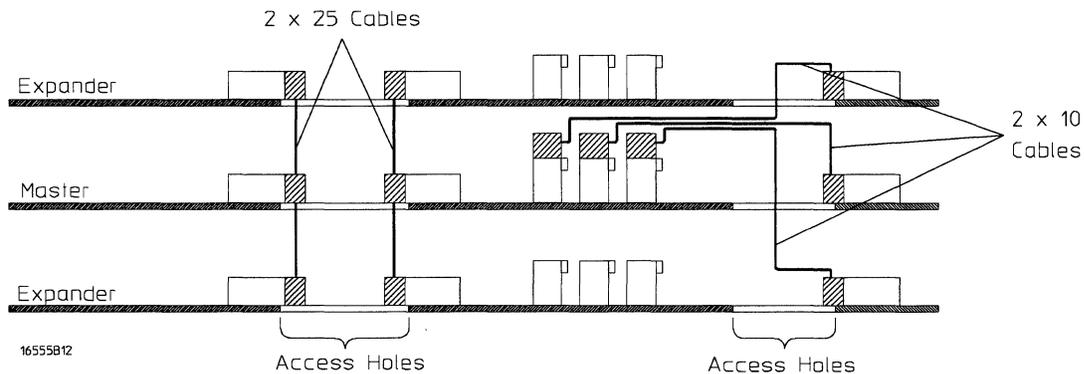
- 7 Place the remaining expander board on top of the master board. Feed the 2x25 cables that are plugged into the master card through the cable access holes of the expander card. Plug the 2x25 cables into J9 and J10 of the expander card.



- 8 Feed the free end of the 2x10 cables of the expander cards through the access holes to the master card. Plug the 2x10 cable into J7 on the master card.

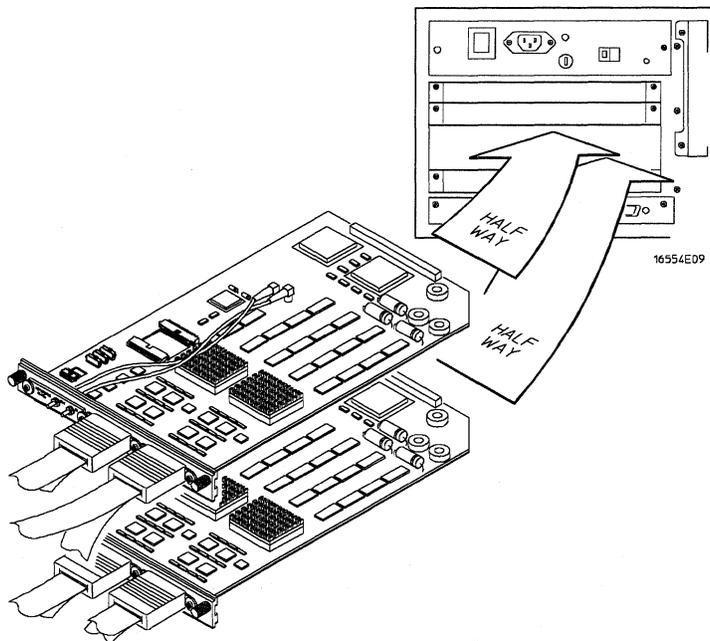


- 9 The following illustration shows the proper connection of the 2x25 cables and the 2x10 cables for a three card module. A two card module is configured in the same manner, with the expansion card above the master card. Make sure ALL cables are firmly seated.



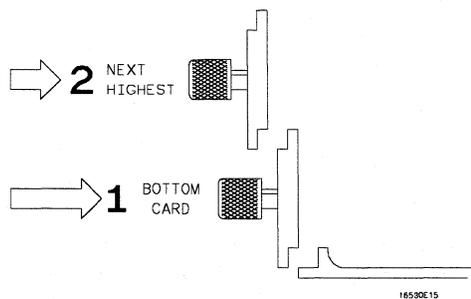
To install the module

- 1 Slide the cards above the slots for the module about halfway out of the mainframe.
- 2 With the probe cables facing away from the instrument, slide the module approximately halfway into the mainframe.



- 3 Slide the complete module into the mainframe, but not completely in.
Each card in the instrument is firmly seated and tightened one at a time in step 5.
- 4 Position all cards and filler panels so that the endplates overlap.
- 5 Seat the cards and tighten the thumbscrews.

Starting with the bottom card, firmly seat the cards into the backplane connector of the mainframe. Keep applying pressure to the center of the card endplate while tightening the thumbscrews finger-tight. Repeat this for all cards and filler panels starting at the bottom and moving to the top.



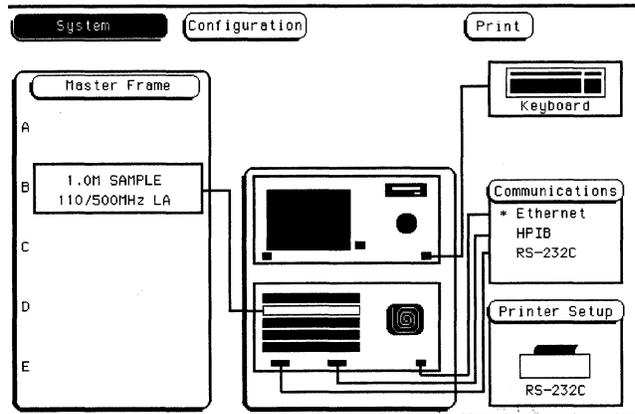
CAUTION

Correct air circulation keeps the instrument from overheating. For correct air circulation, filler panels must be installed in all unused card slots. Keep any extra filler panels for future use.

To turn on the system

- 1 Connect the power cable to the mainframe.
- 2 Turn on the instrument power switch.

When you turn on the instrument power switch, the instrument performs powerup tests that check mainframe circuitry. After the powerup tests are complete, the screen will look similar to the sample screen below.



To test the module

The logic analyzer module does not require an operational accuracy calibration or adjustment. After installing the module, you can test and use the module.

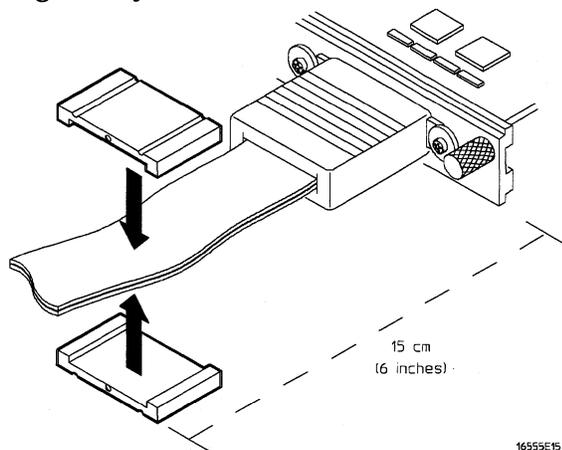
- If you require a test to verify the specifications, start at the beginning of chapter 3, "Testing Performance."
- If you require a test to initially accept the operation, perform the self-tests in chapter 3.
- If the module does not operate correctly, go to the beginning of chapter 5, "Troubleshooting."

To install the ferrites

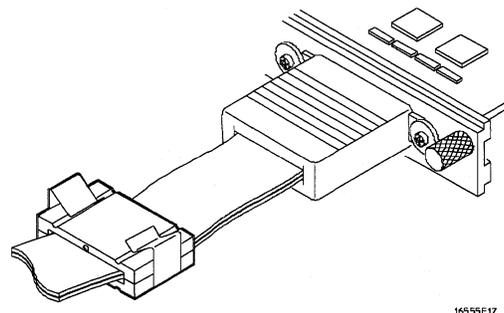
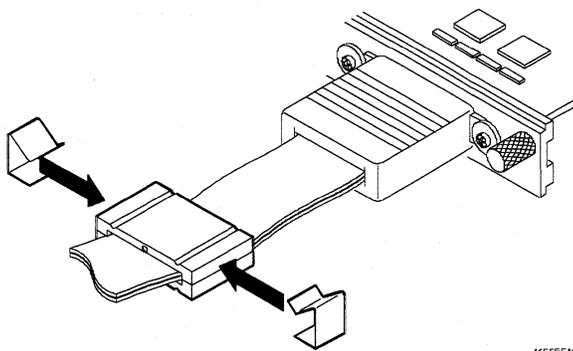
Ferrites are included in the HP 16555A accessory pouch for each logic analyzer cable (two pods). When properly installed, the ferrites reduce RFI emissions from the logic analyzer module.

In order to ensure compliance of the HP 16555A analyzer module to the CISPR 11 Class A radio frequency interference (RFI) limits, you must install the ferrite to absorb radio frequency energy. Adding or removing the ferrite will not affect the normal operation of the analyzer.

- 1 Place the ferrite halves on the logic analyzer cable like a clamshell around the whole cable. The ferrite should be no more than 15 cm (about 6 in) from the rear panel of the logic analyzer.



- 2 Insert the clamps onto the ends of the ferrites. The locking tab should fit cleanly in the ferrite grooves. When properly installed, the ferrite should appear on the logic analyzer cable as shown below on the right.



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Testing Performance

This chapter tells you how to test the performance of the logic analyzer against the specifications listed in chapter 1. To ensure the logic analyzer is operating as specified, software tests (self-tests) and manual performance tests are done on the modules. The logic analyzer is considered performance-verified if all of the software tests and manual performance tests have passed. The procedures in this chapter indicate what constitutes a "Pass" status for each of the tests.

Test Strategy

For a complete test, start at the beginning with the software tests and continue through to the end of the chapter. For an individual test, follow the procedure in the test.

One-card module

To perform a complete test on a one-card module, start at the beginning of the chapter and follow each procedure.

Multicard module

To perform a complete test on a multicard module, perform the software tests with the cards connected. Then, remove the multicard module from the mainframe and configure each card as a one-card module. Install the one-card modules into the mainframe and perform the one-card manual performance tests on each card. When the tests are complete, remove the one-card modules, reconfigure them into a multicard module, reinstall the module into the mainframe, then perform the final multi-card test. For removal instructions, see chapter 6, "Replacing Assemblies." For installation and configuration instructions, see chapter 2, "Preparing for Use."

Test Interval

Test the performance of the module at two-year intervals or if it is replaced or repaired.

Test Record Description

A performance test record for recording the results of each procedure is located at the end of this chapter. Use the performance test record to gauge the performance of the module over time.

Test Equipment

Each procedure lists the recommended test equipment. You can use equipment that satisfies the specifications given. However, the procedures are based on using the recommended model or part number.

Instrument Warm-Up

Before testing the performance of the module, warm-up the instrument and the test equipment for 30 minutes.

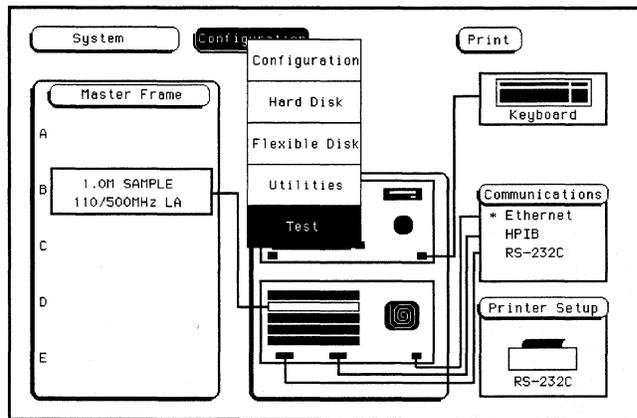
To perform the self-tests and make the test connectors

The self-tests verify the correct operation of the logic analyzer module. Self-tests can be performed all at once or one at a time. While testing the performance of the module, run the self-test all at once.

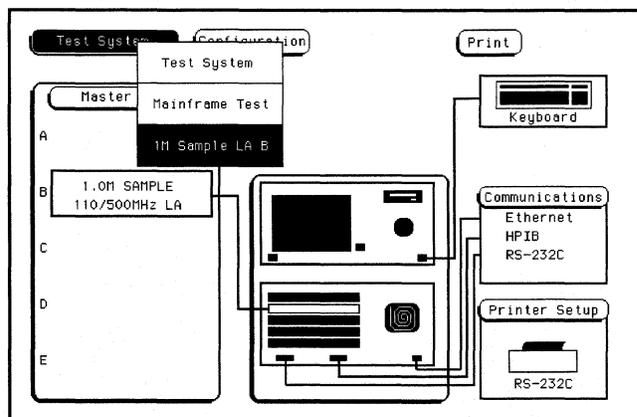
The test connectors connect the analyzer to the test equipment.

Perform the self-tests

- 1 Disconnect all inputs.
- 2 In the System Configuration menu, touch Configuration. In the pop-up, touch Test.

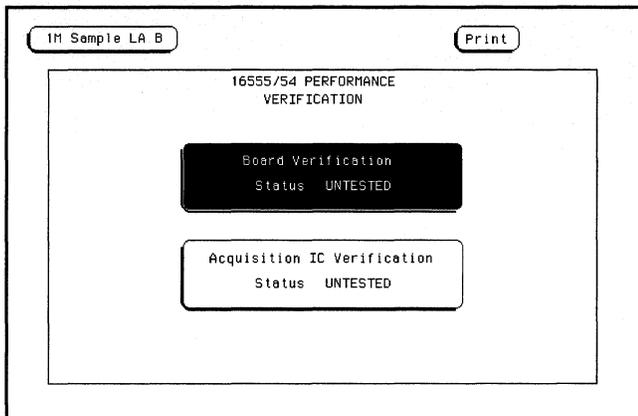


- 3 Touch the box labeled Touch Box to Load Test System.
- 4 On the test system screen, touch Test System. Select the 1M Sample LA module to be tested.



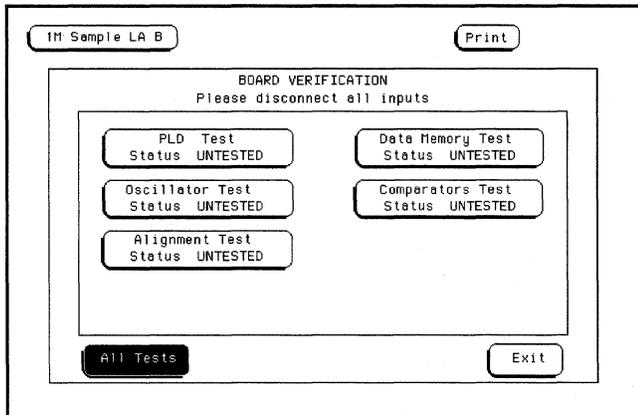
Testing Performance
To perform the self-tests and make the test connectors

5 In the Performance Verification menu, touch the field labeled Board Verification.



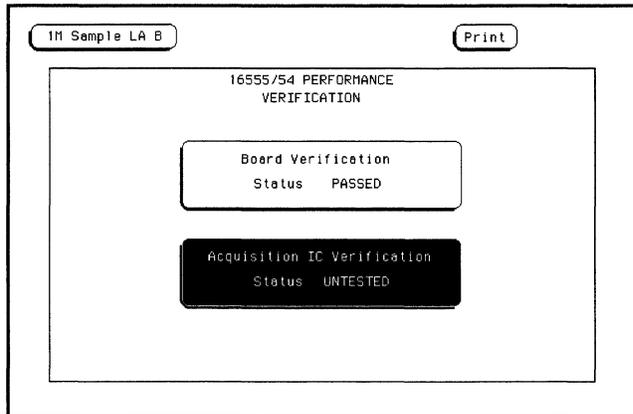
6 In the Board Verification menu, touch All Tests.

You can run all tests at one time by touching All Tests. To see more details about each test when troubleshooting failures, you can run each test individually. This example shows how to run all tests at once.



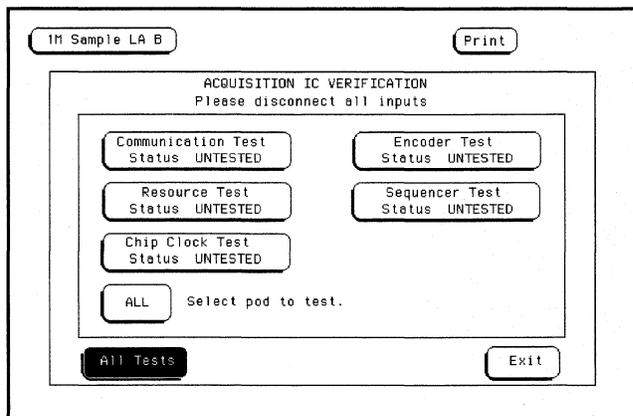
7 When the tests finish, the status will show Passed or Failed. Record the results of the Board Verification tests in the performance test record at the end of this chapter.

- 8 Touch Exit to leave the Board Verification menu. In the Performance Verification menu, touch the field labeled Acquisition IC Verification.



- 9 In the Acquisition IC Verification menu, touch All Tests.

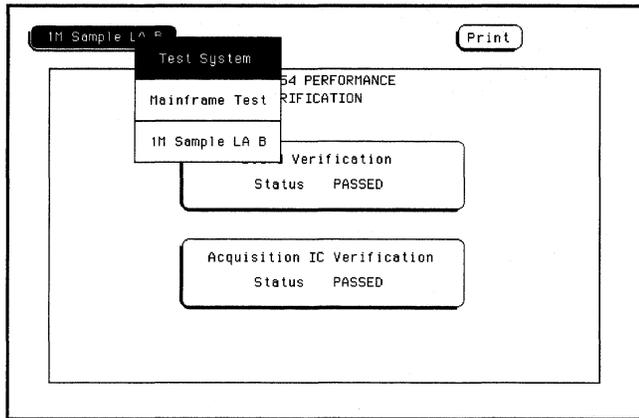
You can run all tests at one time by touching All Tests. To see more details about each test when troubleshooting failures, you can run each test individually. This example shows how to run all tests at once.



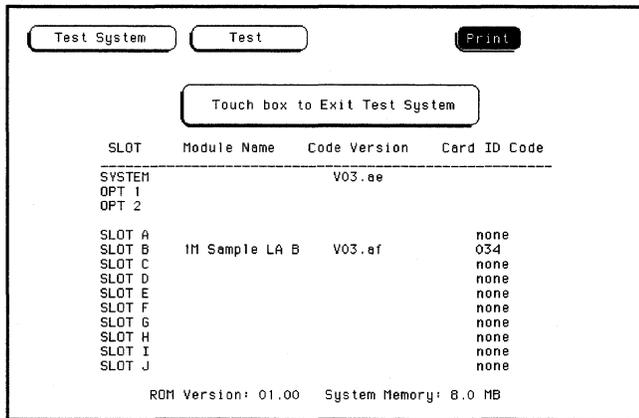
- 10 When the tests finish, the status will show Passed or Failed. Record the results of the Acquisition IC Verification tests in the performance test record at the end of this chapter.

Testing Performance
To perform the self-tests and make the test connectors

- 11 Touch 1M Sample LA. If more logic analyzer cards are to be tested, select the next card, then repeat the test. When all cards are tested, touch 1M Sample LA, then select Test System.



- 12 Touch Configuration, then select Test. In the Test menu, touch the box labeled Touch box to Exit Test System.

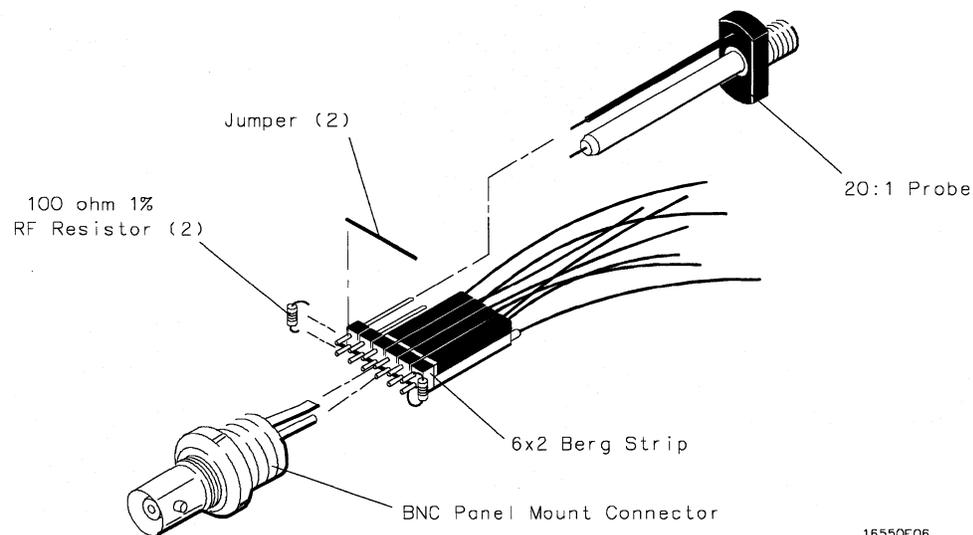


Make the test connectors

Materials Required

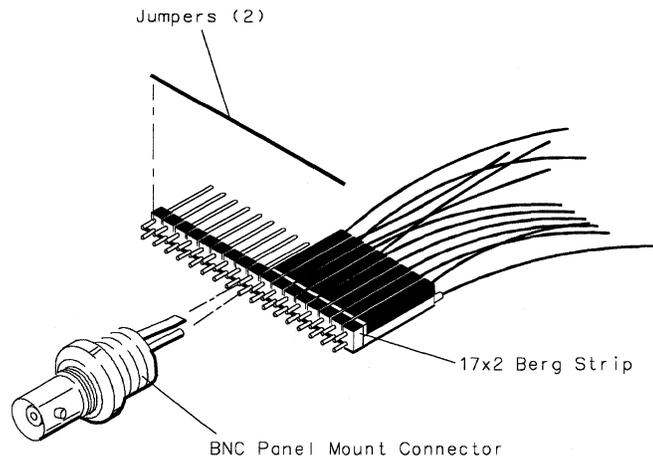
Description	Recommended Part	Qty
BNC (f) Connector	HP 1250-1032	5
100 Ω 1% resistor	HP 0698-7212	8
Berg Strip, 17-by-2		1
Berg Strip, 6-by-2		4
20:1 Probe	HP 54006A	2
Jumper wire		

- 1 Build four test connectors using BNC connectors and 6-by-2 sections of Berg strip.
 - a Solder a jumper wire to all pins on one side of the Berg strip.
 - b Solder a jumper wire to all pins on the other side of the Berg strip.
 - c Solder two resistors to the Berg strip, one at each end between the end pins.
 - d Solder the center of the BNC connector to the center pin of one row on the Berg strip.
 - e Solder the ground tab of the BNC connector to the center pin of the other row on the Berg strip.
 - f On two of the test connectors, solder a 20:1 probe. The probe ground goes to the same row of pins on the test connector as the BNC ground tab.



Testing Performance
To perform the self-tests and make the test connectors

- 2 Build one test connector using a BNC connector and a 17-by-2 section of Berg strip.**
 - a Solder a jumper wire to all pins on one side of the Berg strip.**
 - b Solder a jumper wire to all pins on the other side of the Berg strip.**
 - c Solder the center of the BNC connector to the center pin of one row on the Berg strip.**
 - d Solder the ground tab of the BNC connector to the center pin of the other row on the Berg strip.**



16550E05

To test the threshold accuracy

Testing the threshold accuracy verifies the performance of the following specification:

- **Clock and data channel threshold accuracy.**

Multicard modules must be reconfigured as one-card modules for this test.

These instructions include detailed steps for testing the threshold settings of pod 1. After testing pod 1, connect and test the rest of the pods one at a time. To test the next pod, follow the detailed steps for pod 1, substituting the next pod for pod 1 in the instructions.

Equipment Required

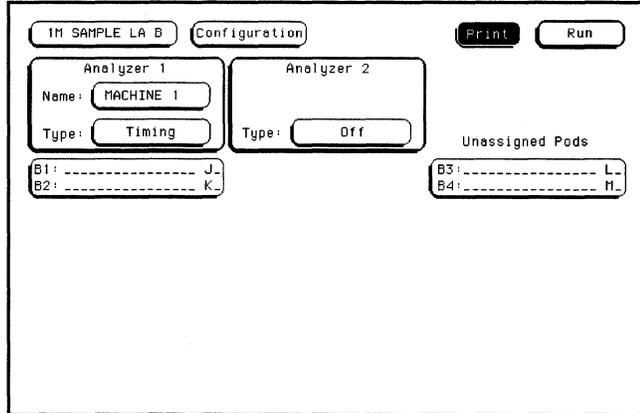
Equipment	Critical Specifications	Recommended Model/Part
Digital Multimeter	0.1 mV resolution, 0.005% accuracy	HP 3458A
Function Generator	DC offset voltage ± 6.3 V	HP 3325B Option 002
BNC-Banana Cable		HP 11001-60001
BNC Tee		HP 1250-0781
BNC Cable		HP 8120-1840
BNC Test Connector, 17x2		

Set up the equipment

- 1 Turn on the equipment required and the logic analyzer. Let them warm up for 30 minutes before beginning the test.
- 2 Set up the function generator.
 - a Set up the function generator to provide a DC offset voltage at the Main Signal output.
 - b Disable any AC voltage to the function generator output, and enable the high voltage output.
 - c Monitor the function generator DC output voltage with the multimeter.

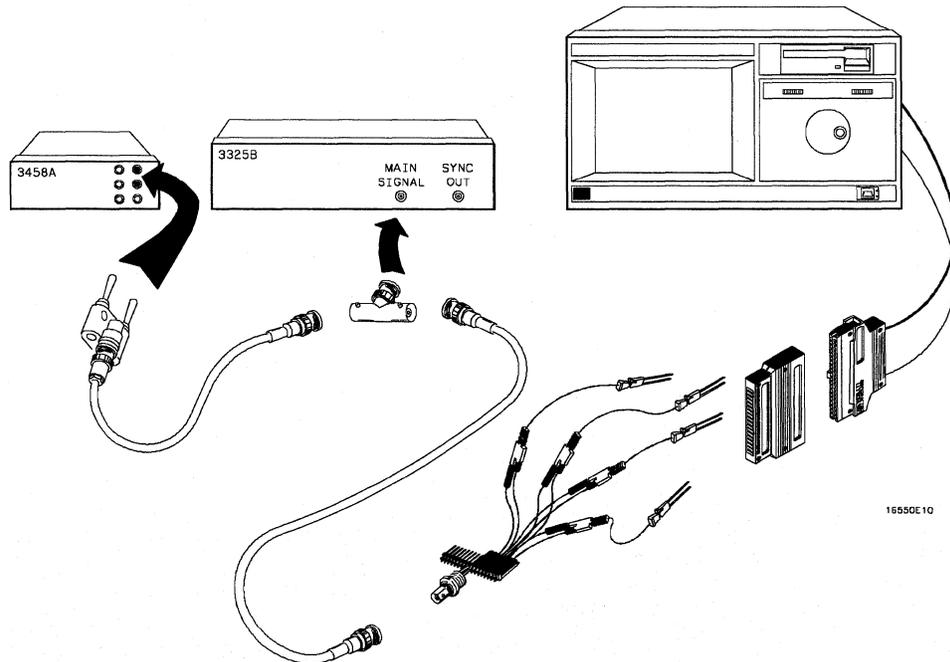
Set up the logic analyzer

- 1 In the System Configuration menu, touch System, then select 1M Sample LA.
- 2 In the Configuration menu, unassign Pod 3 and Pod 4. To unassign the pods, touch the Pod 3, Pod 4 field, then select Unassigned.



Connect the logic analyzer

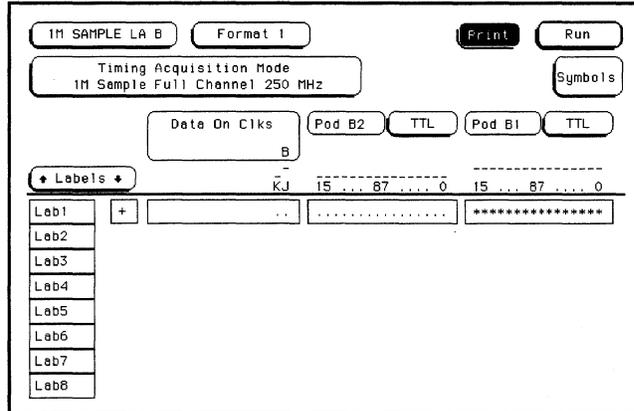
- 1 Using the 17-by-2 test connector, BNC cable, and probe tip assembly, connect the data and clock channels of Pod 1 to one side of the BNC Tee.
- 2 Using a BNC-banana cable, connect the voltmeter to the other side of the BNC Tee.
- 3 Connect the BNC Tee to the Main Signal output of the function generator.



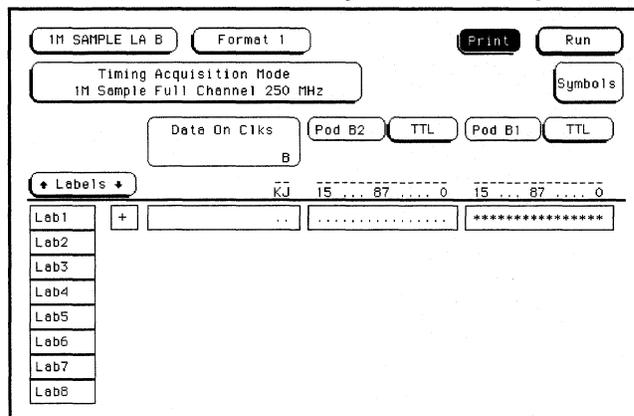
Test the TTL threshold

- 1 In the Configuration menu, touch Configuration, then touch Format. In the Format menu, touch the field to the right of Pod 1, then select TTL.
- 2 On the function generator front panel, enter 1.647 V \pm 1 mV DC offset. Use the multimeter to verify the voltage.

The activity indicators for Pod 1 should show all data channels and the J-clock channel at a logic high.



- 3 Using the Modify down arrow on the function generator, decrease offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic low. Record the function generator voltage in the performance test record.



Testing Performance
To test the threshold accuracy

- 4 Using the Modify up arrow on the function generator, increase offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic high. Record the function generator voltage in the performance test record.

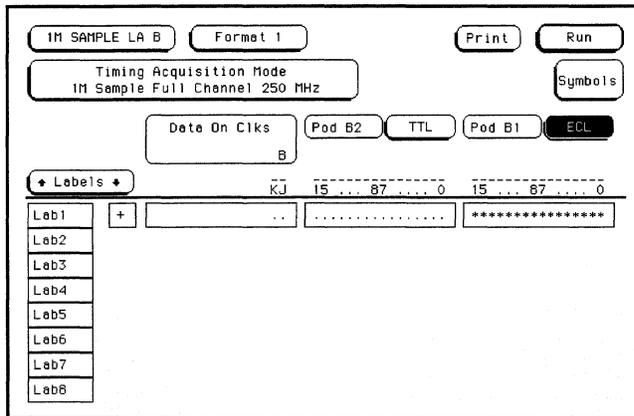
1M SAMPLE LA B		Format 1		Print		Run	
Timing Acquisition Mode						Symbols	
1M Sample Full Channel 250 MHz							
Data On Clks		Pod B2		TTL		Pod B1	
		B					
* Labels *		KJ		15 ... 87 ... 0		15 ... 87 ... 0	
Lab1	+		*****	
Lab2							
Lab3							
Lab4							
Lab5							
Lab6							
Lab7							
Lab8							

Test the ECL threshold

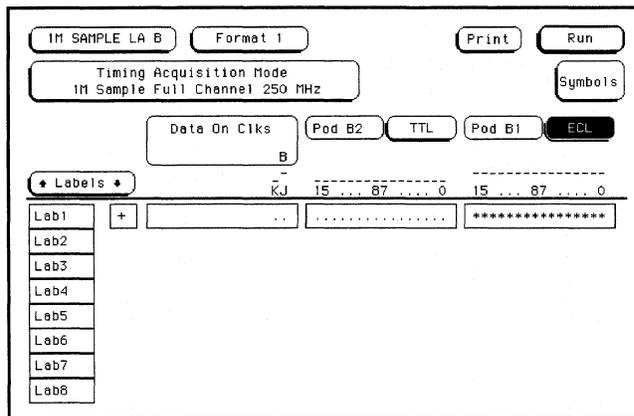
- 1 In the Format menu, touch the field to the right of Pod 1, then select ECL.
- 2 On the function generator front panel, enter $-1.159\text{ V} \pm 1\text{ mV}$ DC offset. Use the multimeter to verify the voltage.

The activity indicators for Pod 1 should show all data channels and the J-clock channel at a logic high.

- 3 Using the Modify down arrow on the function generator, decrease offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels are at a logic low. Record the function generator voltage in the performance test record.



- 4 Using the Modify up arrow on the function generator, increase offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels are at a logic high. Record the function generator voltage in the performance test record.

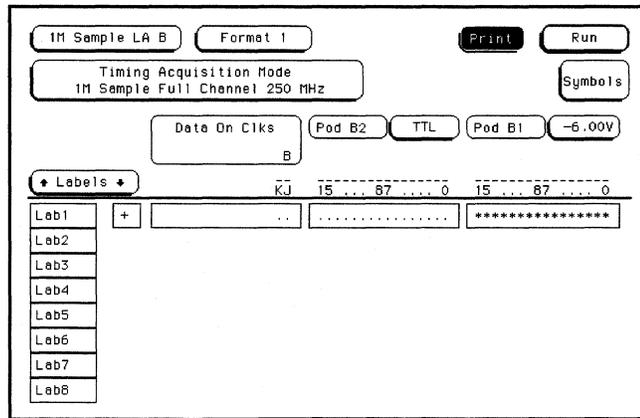


Test the – User threshold

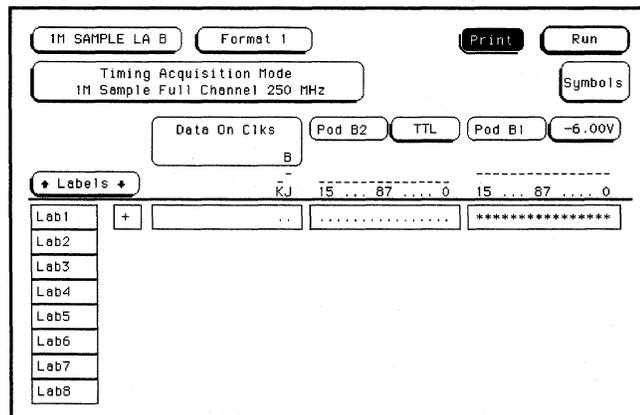
- 1 In the Format menu, touch the field to the right of Pod 1, then select User. In the pop-up menu, enter -6.00 V , then touch Done.
- 2 On the function generator front panel, enter $-5.718\text{ V} \pm 1\text{ mV}$ DC offset. Use the multimeter to verify the voltage.

The activity indicators for Pod 1 should show all data channels and the J-clock channel at a logic high.

- 3 Using the Modify down arrow on the function generator, decrease offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic low. Record the function generator voltage in the performance test record.

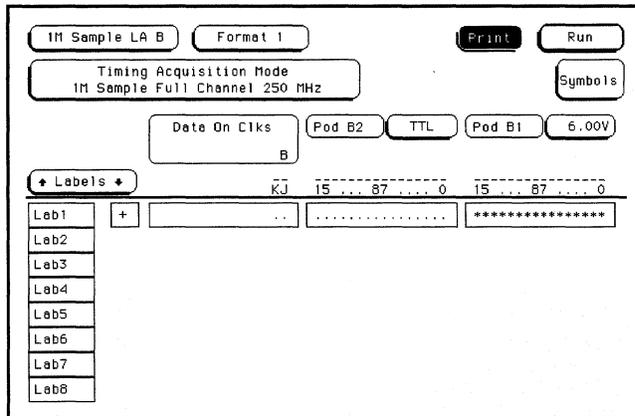


- 4 Using the Modify up arrow on the function generator, increase offset voltage in 1-mV increments until all activity indicators show the channels at a logic high. Record the function generator voltage in the performance test record.

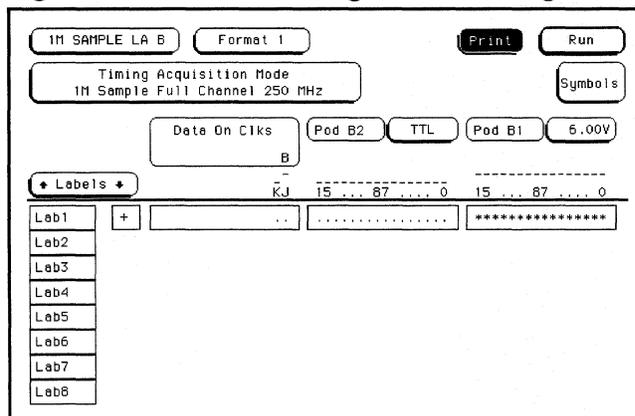


Test the + User threshold

- 1 In the Format menu, touch the field to the right of Pod 1, then select User. In the pop-up menu, enter +6.00 V, then touch Done.
- 2 On the function generator front panel, enter +6.282 V \pm 1 mV DC offset. Use the multimeter to verify the voltage.
The activity indicators for Pod 1 should show all data channels and the J-clock channel at a logic high.
- 3 Using the Modify down arrow on the function generator, decrease offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic low. Record the function generator voltage in the performance test record.



- 4 Using the Modify up arrow on the function generator, increase offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic high. Record the function generator voltage in the performance test record.

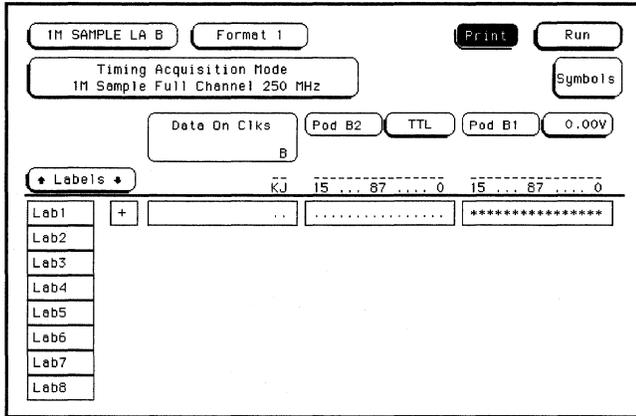


Test the 0 V User threshold

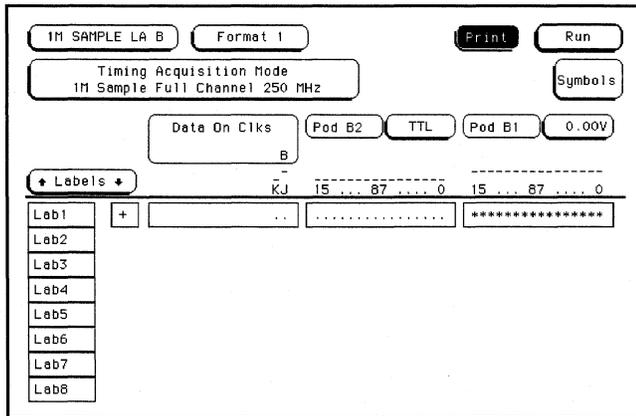
- 1 In the Format menu, touch the field to the right of Pod 1, then select User. In the pop-up menu, enter 0.00 V, then touch Done.
- 2 On the function generator front panel, enter +0.102 V \pm 1 mV DC offset. Use the multimeter to verify the voltage.

The activity indicators for Pod 1 should show all data channels and the J-clock channel at a logic high.

- 3 Using the Modify down arrow on the function generator, decrease offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic low. Record the function generator voltage in the performance test record.



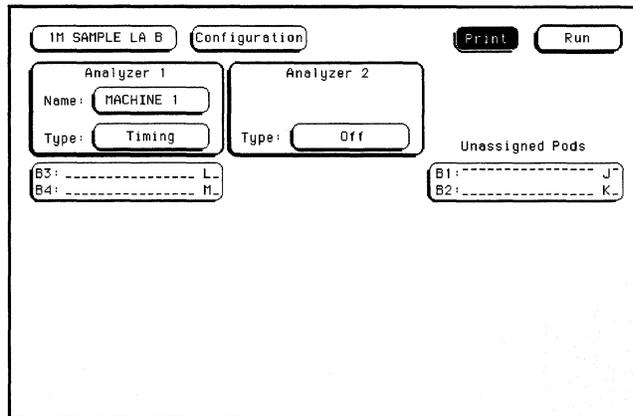
- 4 Using the Modify up arrow on the function generator, increase offset voltage in 1-mV increments until all activity indicators for Pod 1 show the channels at a logic high. Record the function generator voltage in the performance test record.



Test the next pod

Using the 17-by-2 test connector and probe tip assembly, connect the data and clock channels of the next pod to the output of the function generator.

- If you just finished testing Pod 1, connect the data and clock channels of Pod 2. Start with "Test the TTL threshold" on page 3-11, substituting Pod 2 for Pod 1.
- If you just finished testing Pod 2, connect the data and clock channels of pod 3. In the logic analyzer Configuration menu, unassign Pods 1 and 2, assign Pods 3 and 4 to Machine 1. Start with "Test the TTL threshold" on page 3-11, substituting Pod 3 for Pod 1.



- If you just finished testing Pod 3, connect the data and clock channels of Pod 4. Start with "Test the TTL threshold" on page 3-11, substituting Pod 4 for Pod 1.
- If you just finished testing Pod 4, you have completed the threshold accuracy test.

To test the single-clock, single-edge, state acquisition

Testing the single-clock, single-edge, state acquisition verifies the performance of the following specifications:

- Minimum master to master clock time.
- Maximum state acquisition speed.
- Setup/Hold time.
- Minimum clock pulse width.

Multicard modules must be reconfigured as one-card modules for this test.

This test checks a combination of data channels using a single-edge clock at three selected setup/hold times.

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part
Pulse Generator	110 MHz 3.5 ns pulse width, <600 ps rise time	HP 8131A option 020
Digitizing Oscilloscope	≥ 6 GHz bandwidth, <58 ps rise time	HP 54121T
Adapter	SMA(m)-BNC(f)	HP 1250-1200
SMA Coax Cable (Qty 3)		HP 8120-4948
Coupler (Qty 3)	BNC(m-m)	HP 1250-0216
BNC Test Connector, 6x2 (Qty 3)		

Set up the equipment

- 1 Turn on the equipment required and the logic analyzer. Let them warm up for 30 minutes before beginning the test if you have not already done so.
- 2 Set up the pulse generator according to the following table.

Pulse Generator Setup

Channel 1	Channel 2	Period
Delay: 0 ps	Doub: 9.05 ns *	18.1 ns *
Width: 3.5 ns	Width: 3.5 ns	
High: -0.9 V	High: -0.9 V	
Low: -1.7 V	Low: -1.7 V	
COMP: Disabled (LED off)	COMP: Disabled (LED off)	

* If running software version v2.xx, set Channel 2 Doub: 10 ns, and Period to 20 ns. 110-MHz single-clock state acquisition mode is available with operating system v3.00 or higher. For information on software version, refer to footnote on page 1-3.

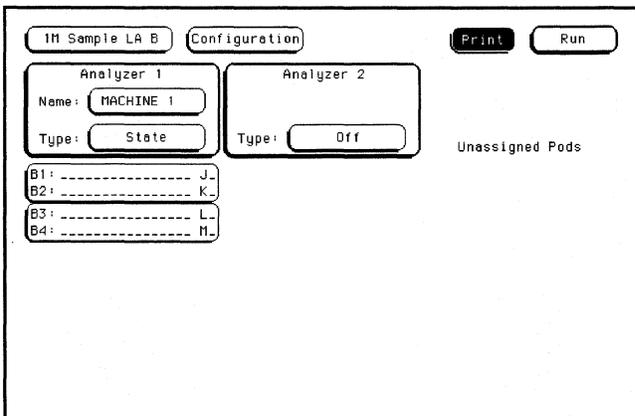
3 Set up the oscilloscope.

Oscilloscope Setup

Time Base	Display	Delta V	Delta t
Time/Div: 1.00 ns/div	avg	V markers on	T markers on
	# of avg: 16	marker 1 position: Chan 1	start on: Pos Edge 1
	screen: dual	marker 2 position: Chan 1	stop on: Neg Edge 1
Channel			
	Channel 1	Channel 2	
Display	on	on	
Probe Atten	20.00	20.00	
Offset	-1.3 V	-1.3 V	
Volts/Div	400 mV	400 mV	

Set up the logic analyzer

- 1 Set up the Configuration menu.
 - a In the System Configuration menu, touch System, then select 1M Sample LA.
 - b In the Configuration menu, assign all pods to Machine 1. To assign the pods, touch the pod fields, then select Machine 1.
 - c In the Analyzer 1 box, touch the Type field, then select State.

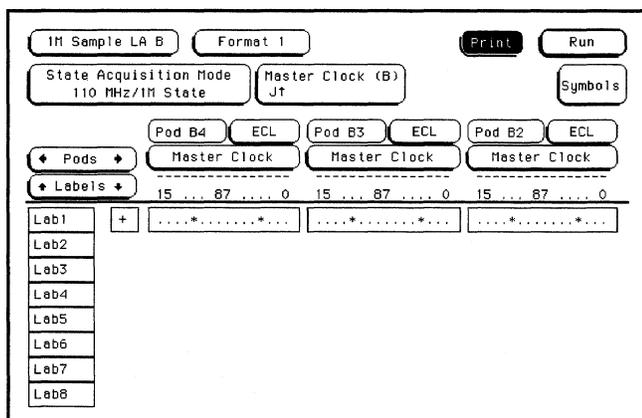


Testing Performance
To test the single-clock, single-edge, state acquisition

2 Set up the Format menu.

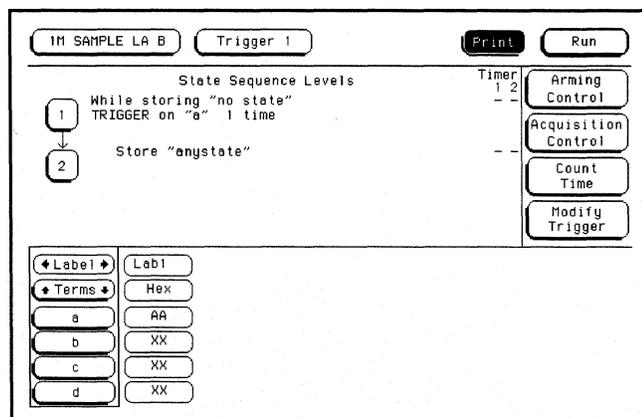
- a Touch Configuration, then select Format.
- b Touch the field to the right of each Pod field, then select ECL. The screen does not show all Pod fields at one time. To access more Pod fields, turn the knob.
- c Touch the field showing the channel assignments for one of the pods being tested. In the pop-up menu, touch Clear until all "." appear. Using the knob, move the cursor to the data channels to be tested (channel 11 and channel 3 of each pod). Touch the asterisk field to put asterisks in the channel positions, activating the channels, then touch Done. Follow this step for the remaining three pods.
- d Touch the State Acquisition Mode field, then select 110MHz/1M State.*

*110-MHz single-clock state acquisition mode is only available with operating system v3.00 or higher. Refer to page 1-3.



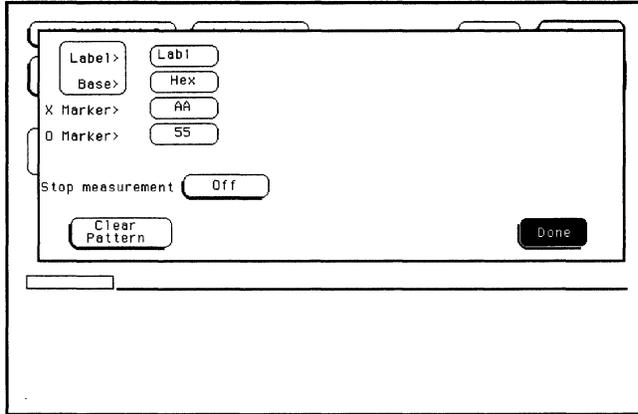
3 Set up the Trigger menu.

- a Touch Format, then select Trigger. In the Trigger menu, touch Modify Trigger, then select Clear Trigger, then select All.
- b Touch the Count Off field. In the Count menu, touch Off. In the pop-up, select Time, then touch Done to exit.
- c Touch the Acquisition Control field. In the Acquisition Control menu, touch Trigger Position then touch Start. Touch Memory Length, and at the numeric keypad, enter "4096" and Touch Done. Touch Done to exit the menu.
- d Touch the field labeled "1" under the State Sequence Levels. Touch the field labeled "anystate," then select "no state." Touch Done.
- e Touch the pattern recognizer "a." In the pop-up menu, type "AA," then touch Done.

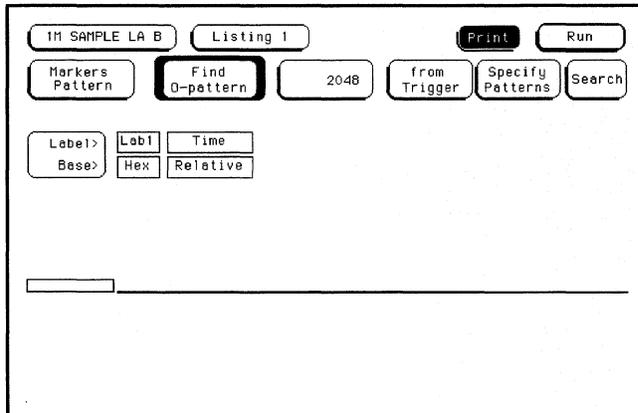


4 Set up the Listing menu.

- a** Touch Trigger, then select Listing.
- b** Touch the Markers field, then select Pattern.
- c** Touch Specify Patterns. Select the X Marker > field. At the numeric keypad, enter "AA." Select the O Marker > field. At the numeric keypad, enter "55." Touch Done.



- d** Touch the Find X-pattern occurrences field. At the numeric keypad, enter "2047." Touch Done.
- e** Touch the Find X-pattern field. The field should toggle to Find O-pattern. Touch the Find O-pattern occurrences field. At the numeric keypad, enter "2048." Touch Done.

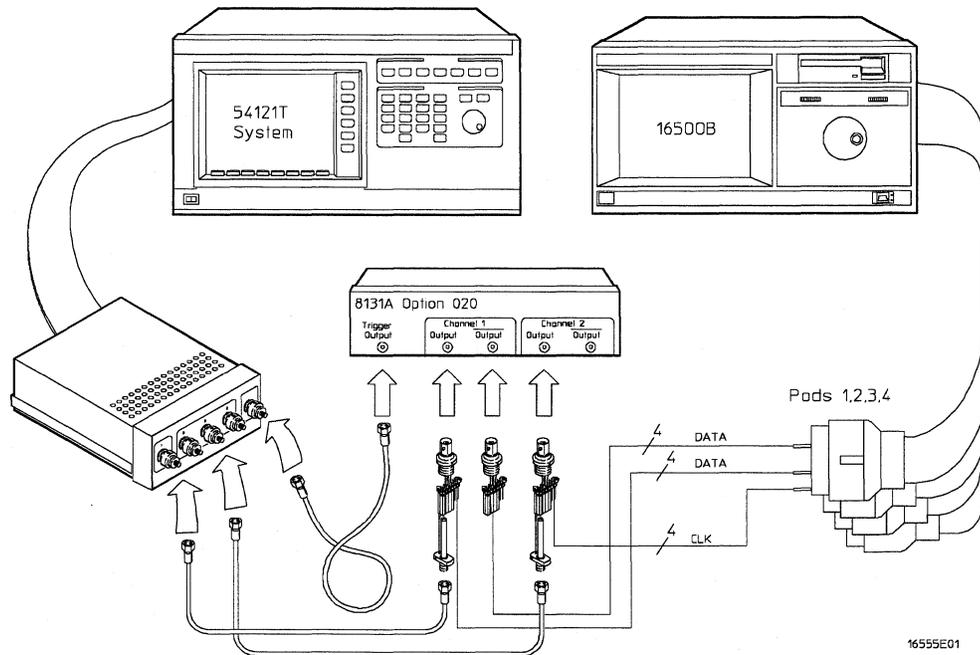


Connect the logic analyzer

- 1 Using the 6-by-2 test connectors, connect the logic analyzer clock and data channels listed in the table below to the pulse generator.
- 2 Using SMA cables, connect channel 1, channel 2, and trigger from the oscilloscope to the pulse generator.

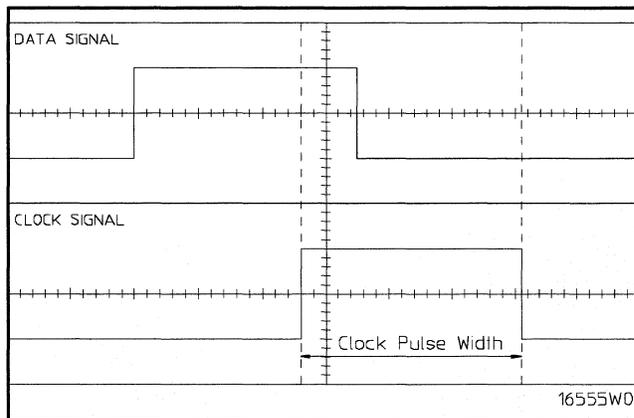
Connect the Logic Analyzer to the Pulse Generator

Connect to HP 8131A Channel 1 Output	Connect to HP 8131A Channel 1 Output	Connect to HP 8131A Channel 2 Output
Pod 1, channel 3	Pod 1, channel 11	J-clock
Pod 2, channel 3	Pod 2, channel 11	K-clock
Pod 3, channel 3	Pod 3, channel 11	L-clock
Pod 4, channel 3	Pod 4, channel 11	M-clock



Verify the test signal

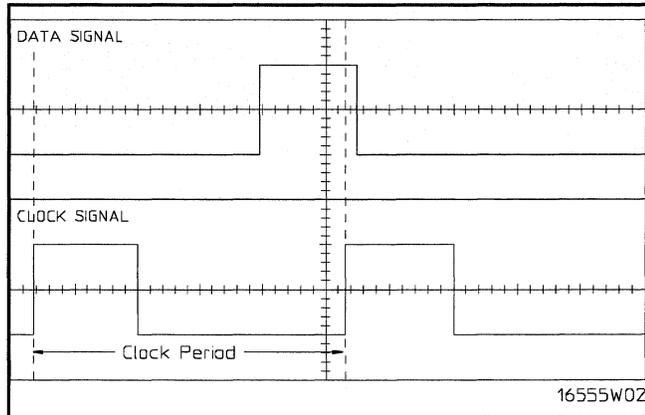
- 1 Check the clock pulse width. Using the oscilloscope, verify that the clock pulse width is 3.480 ns, +20 ps or -80 ps.
 - a Enable the pulse generator channel 1 and channel 2 outputs (LED off).
 - b In the oscilloscope Timebase menu, select Delay. Using the oscilloscope knob, position the clock waveform so that the waveform is centered on the screen.
 - c In the oscilloscope Delta V menu, select Marker 1 Position Chan 2, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - d In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop on Neg Edge 1.
 - e If the pulse width is outside the limits, adjust the pulse generator channel 2 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.



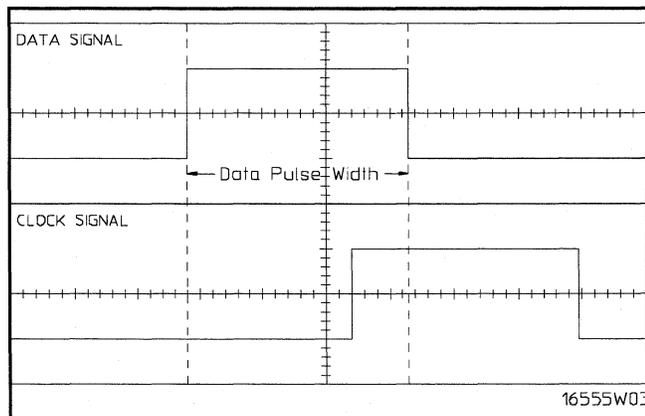
- 2 Check the clock period. Using the oscilloscope, verify that the master-to-master clock time is 9.05 ns. *
 - a In the oscilloscope Timebase menu, select Sweep Speed 3.00 ns/div.
 - b Select Delay. Using the oscilloscope knob, position the clock waveform so that a rising edge appears at the left of the display.
 - c In the oscilloscope Measure menu, select Measure Chan 2, then select Period. If the period is not less than 9.05 ns, go to step d. If the period is less than 9.05 ns, go to step 3.
 - d In the oscilloscope Timebase menu, add 9.000 ns to the delay.
 - e In the oscilloscope Measure menu, select Period. If the period is not less than 9.05 ns, decrease the pulse generator Chan 2 Doub in 10-ps increments until one of the two periods measured is less than 9.05 ns.

*If running operating system version v2.xx, measure a master-to-master clock time of 10 ns.

Testing Performance
To test the single-clock, single-edge, state acquisition



- 3** Check the data pulse width. Using the oscilloscope, verify that the data pulse width is 3.480 ns, +20 ps or -80 ps.
 - a** In the oscilloscope Timebase menu, select Sweep Speed 1.00 ns/div.
 - b** Select Delay. Using the oscilloscope knob, position the data waveform so that the waveform is centered on the screen.
 - c** In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 position Chan 1, marker 2 at -1.3000 V.
 - d** In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop on Neg Edge 1.
 - e** Select Precision Edge Find.
 - f** If the pulse width is outside the limits, adjust the pulse generator channel 1 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.



Check the setup/hold combination

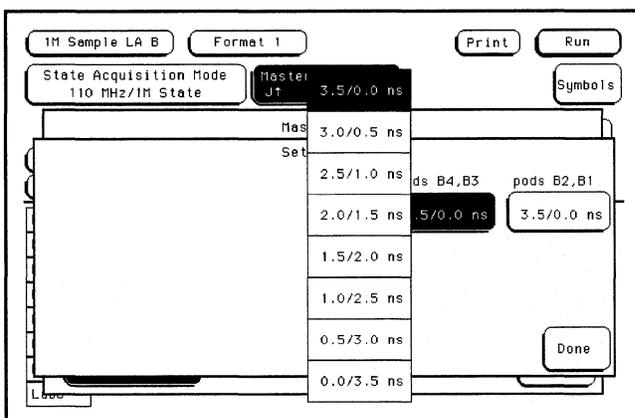
- 1 Select the logic analyzer setup/hold time.
 - a Touch Listing, then touch Format.
 - b In the logic analyzer Format menu, touch Master Clock.
 - c Touch the Setup/Hold field and select the setup/hold combination to be tested for all pods. The first time through this test, select the top combination in the following table.

Setup/Hold Combinations

3.5/0.0 ns

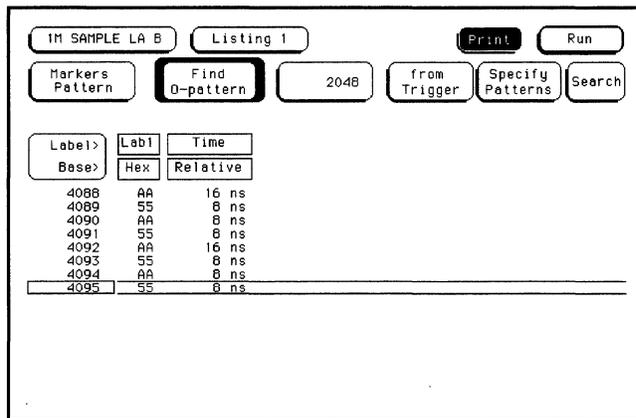
0.0/3.5 ns

1.5/2.0 ns

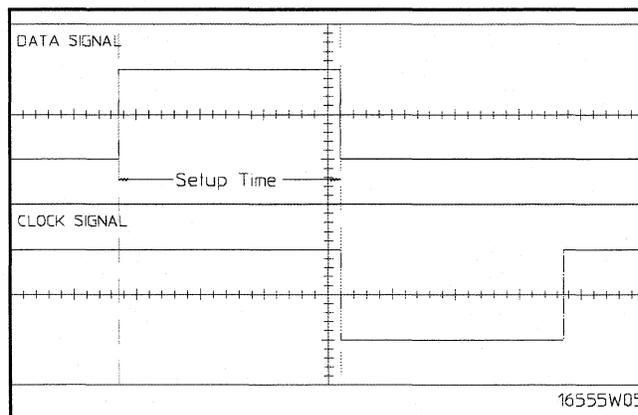


- d Touch Done to exit the setup/hold combinations.
- 2 Disable the pulse generator channel 2 COMP (LED off).

- 5 In the logic analyzer Format menu, touch Run. The display should show an alternating pattern of "AA" and "55." If the "Search Failed" yellow bar message does not appear, the test passes. Record the Pass or Fail in the performance test record.



- 6 Test the next clock.
- Touch Listing, then touch Format.
 - In the logic analyzer Format menu, touch Master Clock.
 - Turn off the clock just tested.
 - Repeat steps 4, 5, and 6 for the next clock edge listed in the table in step 4, until all listed clock edges have been tested.
- 7 Enable the pulse generator channel 2 COMP (LED on).
- 8 Using the Delay mode of the pulse generator channel 1, position the pulses according to the setup/hold combination selected, +0.0 ps or -100 ps.
- In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - In the oscilloscope Delta t menu, select Start on Pos Edge 1. Select Stop on Neg Edge 1.
 - Adjust the pulse generator channel 1 Delay and select Precision Edge Find in the oscilloscope Delta t menu until the pulses are aligned according to the setup time of the setup/hold combination selected.



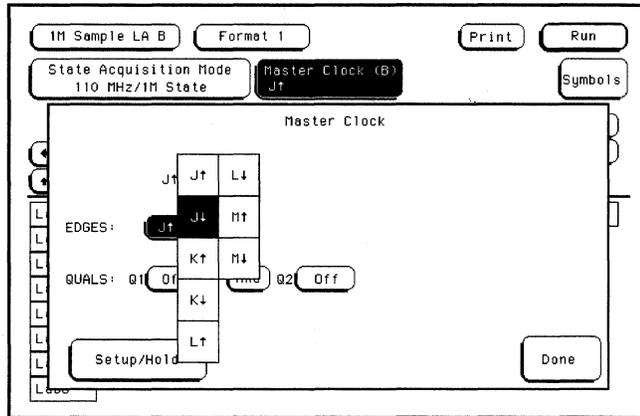
Testing Performance
To test the single-clock, single-edge, state acquisition

9 Select the clock to be tested.

- a** In the Master Clock menu, touch the clock field to be tested and then select the clock edge as indicated in the table. The first time through this test, select the top clock and edge.

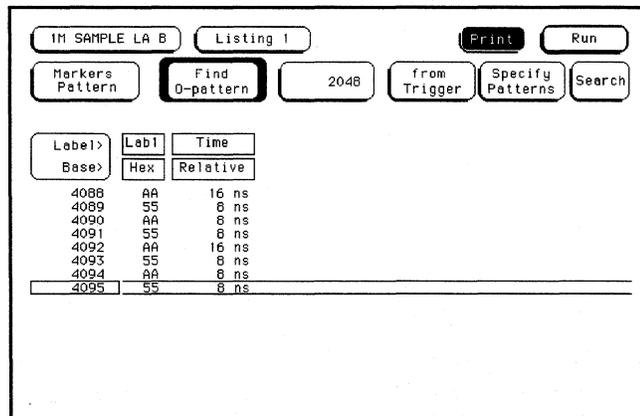
Clocks

- J↓
 K↓
 L↓
 M↓



- b** Touch Done to exit the Master Clock menu.

- 10** In the logic analyzer Format menu, touch Run. The display should show an alternating pattern of AA and 55. If the "Search Failed" yellow bar message does not appear, the test passes. Record the Pass or Fail results in the performance test record.



- 11 Test the next clock.**
- a** In the logic analyzer Format menu, touch Master Clock.
 - b** Turn off the clock just tested.
 - c** Repeat steps 9, 10, and 11 for the next clock edge listed in the table in step 9, until all listed clock edges have been tested.

- 12 Test the next setup/hold combination.**
- a** In the logic analyzer Format menu, touch Master Clock.
 - b** Turn off the clock just tested.
 - c** Repeat steps 1 through 12 for the next setup/hold combination listed in step 1 on page 3-25, until all listed setup/hold combinations have been tested.

When aligning the data and clock waveforms using the oscilloscope, align the waveforms according to the setup time of the setup/hold combination being tested, +0.0 ps or -100 ps.

To test the multiple-clock, multiple-edge, state acquisition

Testing the multiple-clock, multiple-edge, state acquisition verifies the performance of the following specifications:

- Minimum master to master clock time.
- Maximum state acquisition speed.
- Setup/Hold time.
- Minimum clock pulse width.

Multicard modules must be reconfigured as one-card modules for this test.

This test checks a combination of data channels using multiple clocks at three selected setup/hold times.

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part
Pulse Generator	100 MHz 3.5 ns pulse width, <600 ps rise time	HP 8131A option 020
Digitizing Oscilloscope	≥ 6 GHz bandwidth, <58 ps rise time	HP 54121T
Adapter	SMA(m)-BNC(f)	HP 1250-1200
SMA Coax Cable (Qty 3)		HP 8120-4948
Coupler (Qty 3)	BNC(m-m)	HP 1250-0216
BNC Test Connector, 6x2 (Qty 3)		

Set up the equipment

- 1 Turn on the equipment required and the logic analyzer. Let them warm up for 30 minutes before beginning the test if you have not already done so.
- 2 Set up the pulse generator according to the following table.

Pulse Generator Setup

Channel 1	Channel 2	Period
Delay: 0 ps	Doub: 10.0 ns	20.0 ns
Width: 4.5 ns	Width: 3.5 ns	
High: -0.9 V	High: -0.9 V	
Low: -1.7 V	Low: -1.7 V	
COMP: Disabled (LED off)	COMP: Disabled (LED off)	

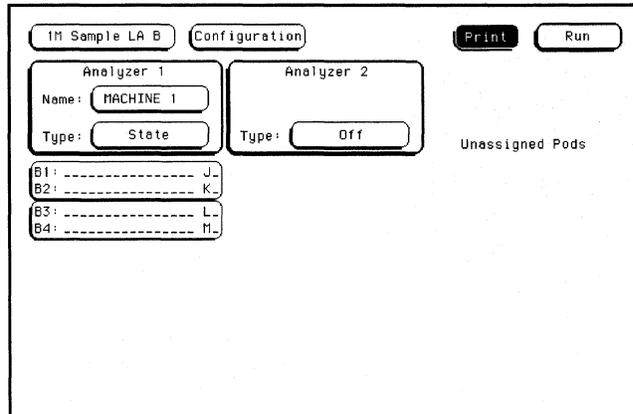
3 Set up the oscilloscope.

Oscilloscope Setup

Time Base	Display	Delta V	Delta t
Time/Div: 1.00 ns/div	avg	V markers on	T markers on
	# of avg: 16	marker 1 position: Chan 1	start on: Pos Edge 1
	screen: dual	marker 2 position: Chan 1	stop on: Neg Edge 1
Channel			
	Channel 1	Channel 2	
Display	on	on	
Probe Atten	20.00	20.00	
Offset	-1.3 V	-1.3 V	
Volts/Div	400 mV	400 mV	

Set up the logic analyzer

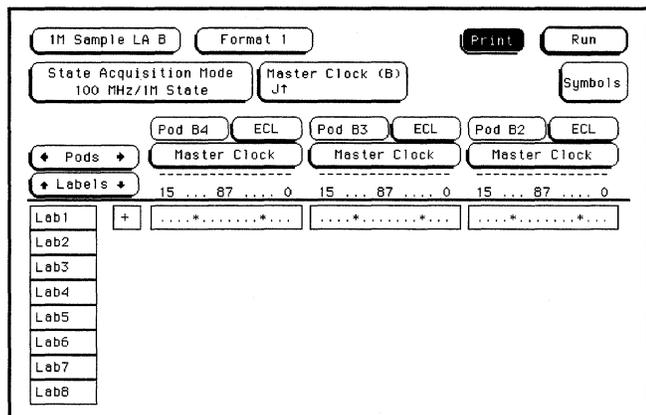
- 1 Set up the Configuration menu.**
 - a** In the System Configuration menu, touch System, then select 1M Sample LA.
 - b** In the Configuration menu, assign all pods to Machine 1. To assign all pods, touch the pod fields, then select Machine 1.
 - c** In the Analyzer 1 box, touch the Type field, then select State.



Testing Performance
To test the multiple-clock, multiple-edge, state acquisition

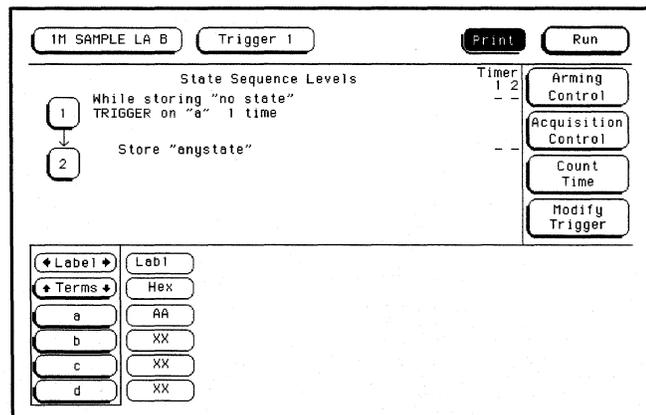
2 Set up the Format menu.

- a Touch Configuration, then select Format.
- b Touch the field to the right of each Pod field, then select ECL. The screen does not show all Pod fields at one time. To access more Pod fields, turn the knob.
- c Touch the field showing the channel assignments for one of the pods being tested. In the pop-up menu, touch Clear until all "." appear. Using the knob, move the cursor to the data channels to be tested (channel 11 and channel 3 of each pod). Touch the asterisk field to put asterisks in the channel positions, then touch Done. Follow this step for the remaining three pods.



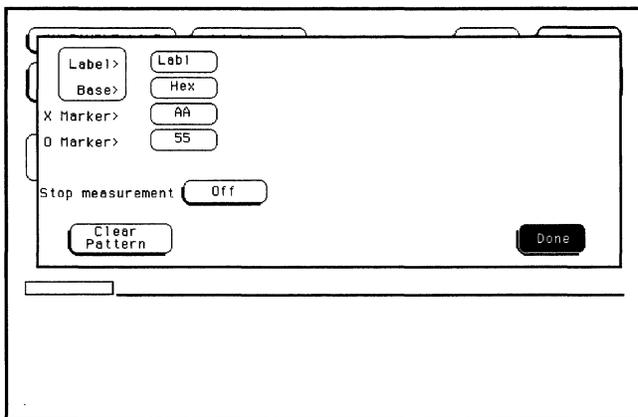
3 Set up the Trigger menu.

- a Touch Format, then select Trigger. In the Trigger menu, touch Modify Trigger, then select Clear Trigger, then select All.
- b Touch the Count Off field. In the Count menu, touch Off. In the pop-up, select Time, then touch Done to exit.
- c Touch the Acquisition Control field. In the Acquisition Control menu, touch Trigger Position then touch Start. Touch Memory Length, and at the numeric keypad, enter "4096" and Touch Done. Touch Done to exit the menu.
- d Touch the field labeled "1" under the State Sequence Levels. Touch the field labeled "anystate," then select "no state." Touch Done.
- e Touch the pattern recognizer "a." In the pop-up menu, type "AA," then touch Done.

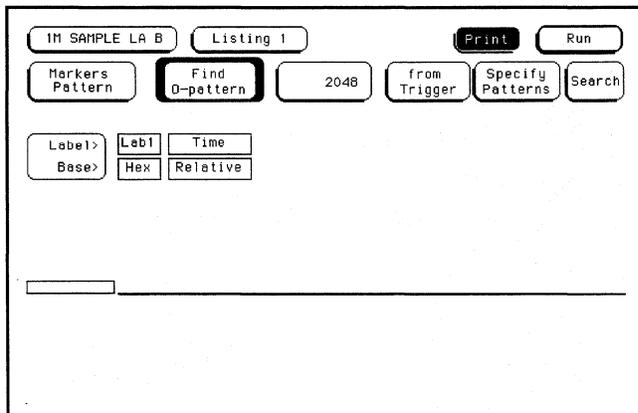


4 Set up the Listing menu.

- a Touch Trigger, then select Listing.
- b Touch the Markers field, then select Pattern.
- c Touch Specify Patterns. Select the X Marker > field. At the numeric keypad, enter "AA." Select the O Marker > field. At the numeric keypad, enter "55." Touch Done.



- d Touch the Find X-pattern occurrences field. At the numeric keypad, enter "2047." Touch Done.
- e Touch the Find X-pattern field. The field should toggle to Find O-pattern.
- f Touch the Find O-pattern occurrences field. At the numeric keypad, enter "2048." Touch Done.



Connect the logic analyzer

- 1 Using the 6-by-2 test connectors, connect the logic analyzer clock and data channels listed in the table below to the pulse generator.
- 2 Using SMA cables, connect channel 1, channel 2, and trigger of the oscilloscope to the pulse generator.

Connect the Logic Analyzer to the Pulse Generator

**Connect to HP 8131A
Channel 1 Output**

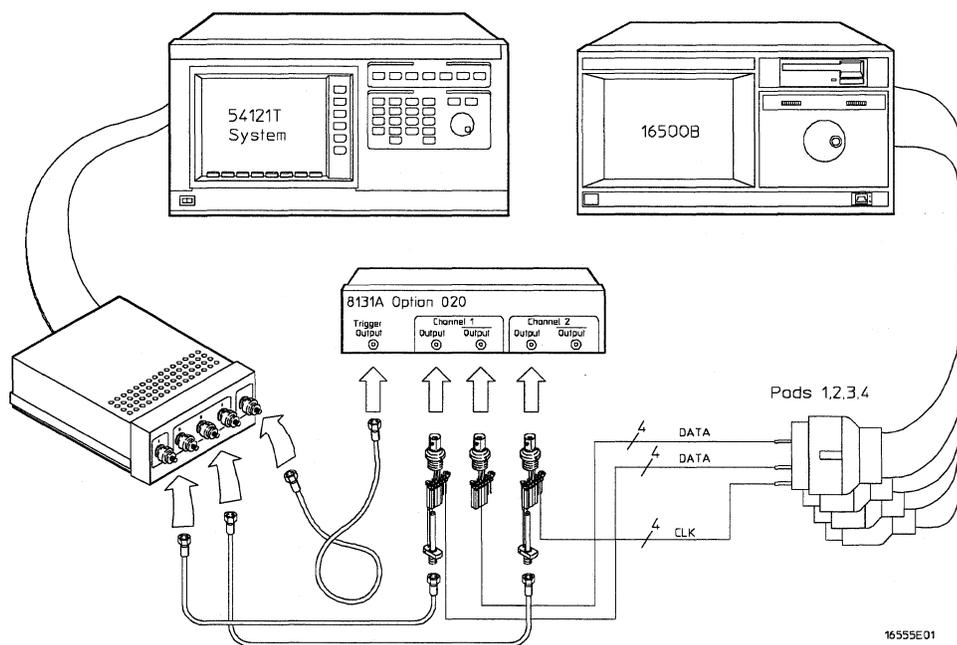
Pod 1, channel 3
Pod 2, channel 3
Pod 3, channel 3
Pod 4, channel 3

**Connect to HP 8131A
Channel 1 Output**

Pod 1, channel 11
Pod 2, channel 11
Pod 3, channel 11
Pod 4, channel 11

**Connect to HP 8131A
Channel 2 Output**

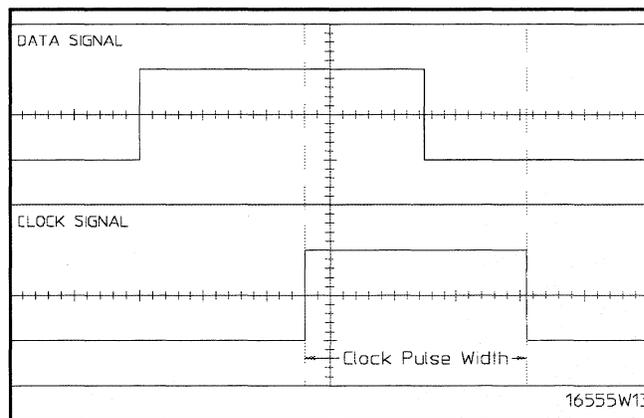
J-clock
K-clock
L-clock
M-clock



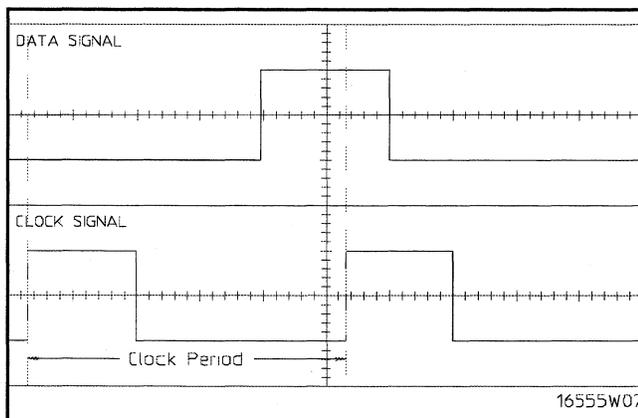
16555E01

Verify the test signal

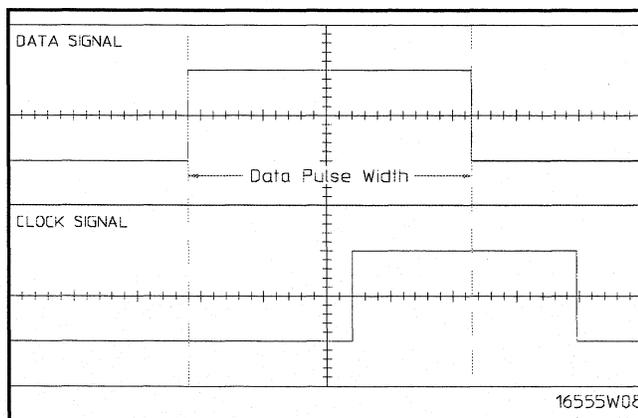
- 1 Check the clock pulse width. Using the oscilloscope, verify that the clock pulse width is 3.480 ns, +20 ps or -80 ps.
 - a Enable the pulse generator channel 1 and channel 2 outputs (LED off).
 - b In the oscilloscope Timebase menu, select Delay. Using the oscilloscope knob, position the clock waveform so that the waveform is centered on the screen.
 - c In the oscilloscope Delta V menu, select Marker 1 Position Chan 2, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - d In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop On Neg Edge 1.
 - e If the pulse width is outside of the limits, adjust the pulse generator channel 2 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.



- 2 Check the clock period.** Using the oscilloscope verify that the master-to-master clock time is 10.000 ns.
- In the oscilloscope Timebase menu, select Sweep Speed 2.00 ns/div.
 - Select Delay. Using the oscilloscope knob position the clock waveform so that a rising edge appears at the left of the display.
 - In the oscilloscope Measure menu, select Measure Chan 2, then select Period. If the period is not less than 10.000 ns, go to step d. If the period is less than 10.000 ns, go to step 3.
 - In the oscilloscope Timebase menu, add 10 ns to the Delay.
 - In the oscilloscope Measure menu, select Period. If the period is not less than 10.000 ns, decrease the pulse generator Chan 2 DOUB in 10 ps increments until one of the two periods measured is less than 10.000 ns.



- 3 Check the data pulse width.** Using the oscilloscope verify that the data pulse width is 4.480 ns, +20 ps or -80 ps.
- In the oscilloscope Timebase menu, select Sweep Speed 1.00 ns/div.
 - Select Delay. Using the oscilloscope knob, position the data waveform so that the waveform is centered in the screen.
 - In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 1, Marker 2 at -1.3000 V.
 - In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop on Neg Edge 1.
 - If the pulse width is outside of the limits adjust the pulse generator channel 1 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.

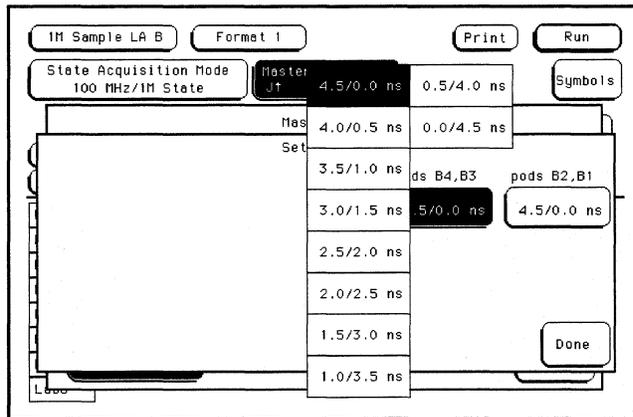


Check the setup/hold with single clock edges, multiple clocks

- 1 Select the logic analyzer setup/hold time.
 - a Touch Listing, then touch Format. In the logic analyzer Format menu, touch Master Clock.
 - b Select and activate any two clock edges.
 - c Touch the Setup/Hold field and select the setup/hold to be tested for all pods. The first time through this test, select the top combination in the following table.

Setup/Hold Combinations

4.5/0.0 ns
 0.0/4.5 ns
 2.0/2.5 ns

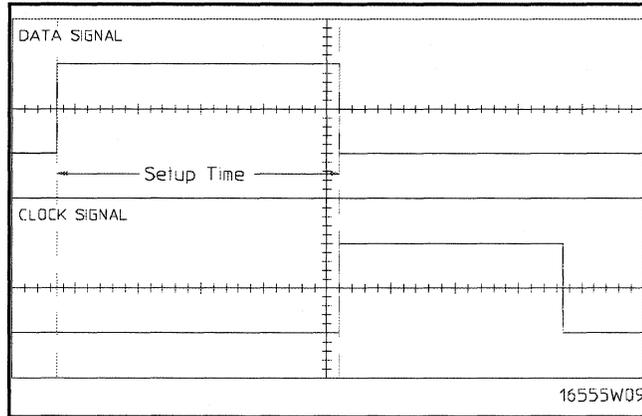


- d Touch Done to exit the setup/hold combinations.
- 2 Disable the pulse generator channel 2 COMP (LED off).
- 3 Using the Delay mode of the pulse generator channel 1, position the pulses according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.
 - a In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - b In the oscilloscope Delta t menu, select Start on Pos Edge 1. Select Stop on Pos Edge 1.

Testing Performance

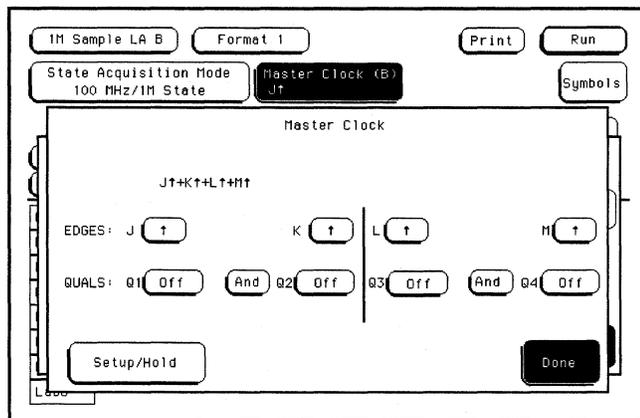
To test the multiple-clock, multiple-edge, state acquisition

- c Adjust the pulse generator channel 1 Delay and select Precision Edge Find in the oscilloscope Delta t menu until the pulses are aligned according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.



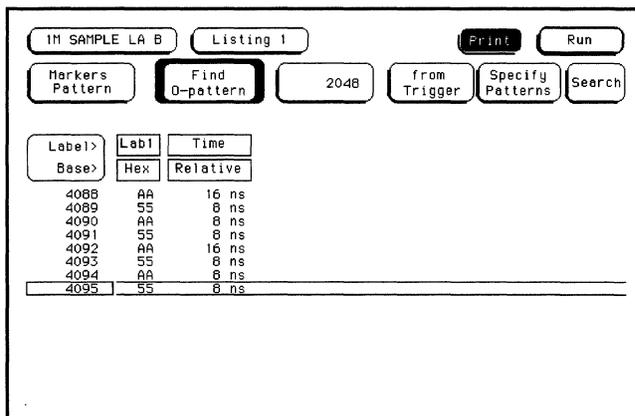
- 4 Select the clocks to be tested.

- a Touch the clock field to be tested, and then select the following combination of clock edges: $J\uparrow + K\uparrow + L\uparrow + M\uparrow$.

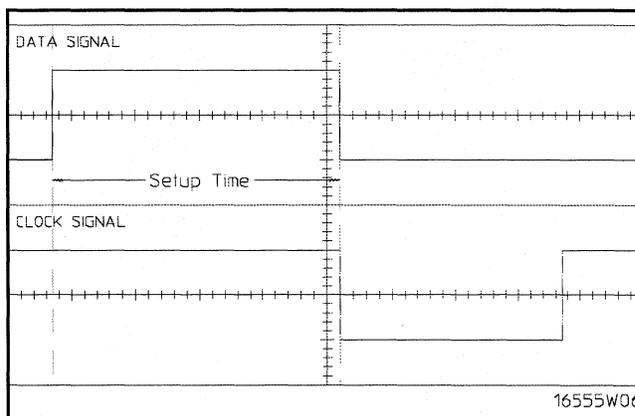


- b Touch Done to exit the Master Clock menu.

- 5 In the logic analyzer Format menu, touch Run. The display should show an alternating pattern of AA and 55. If the "Search Failed" yellow bar message does not appear, the test passes. Record the Pass or Fail results in the performance test record.



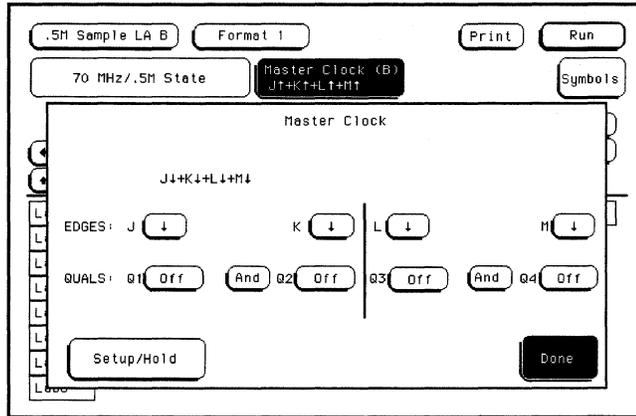
- 6 Enable the pulse generator channel 2 COMP (LED on).
- 7 Using the Delay mode of the pulse generator channel 1, position the pulses according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.
- In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop on Neg Edge 1.
 - Adjust the pulse generator channel 1 Delay and select Precision Edge Find in the oscilloscope Delta t menu until the pulses are aligned according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.



Testing Performance
To test the multiple-clock, multiple-edge, state acquisition

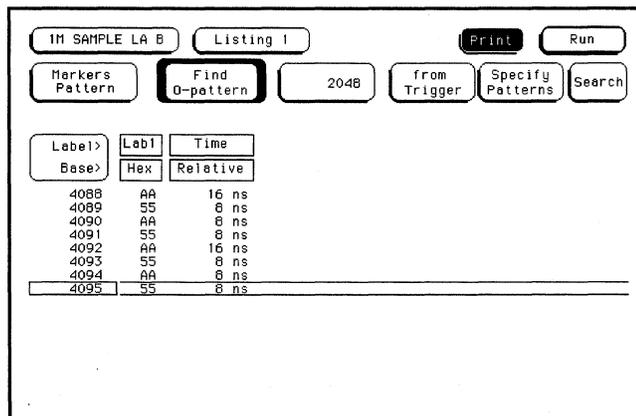
8 Select the clocks to be tested.

- a** Touch the clock field to be tested and then select the following combination of clock edges: J↓ + K↓ + L↓ + M↓.



- b** Touch Done to exit the Master Clock menu.

9 In the logic analyzer Format menu, touch Run. The display should show an alternating pattern of AA and 55. If the "Search Failed" yellow bar message does not appear, the test passes. Record the Pass or Fail results in the performance test record.



10 Test the next setup/hold combination.

- a** In the logic analyzer Format menu, touch Master Clock.
b Turn off the clocks just tested.
c Repeat steps 1 through 10 for the next setup/hold combination listed in step 1 on page 3-37, until all listed setup/hold combinations have been tested.

When aligning the data and clock waveforms using the oscilloscope, align the waveforms according to the setup time of the setup/hold combination being tested, +0.0 ps or -100 ps.

To test the single-clock, multiple-edge, state acquisition

Testing the single-clock, multiple-edge, state acquisition verifies the performance of the following specifications:

- Minimum master to master clock time.
- Maximum state acquisition speed.
- Setup/Hold time.
- Minimum clock pulse width.

Multicard modules must be reconfigured as one-card modules for this test.

This test checks a combination of data channels using a multiple-edge single clock at three selected setup/hold times.

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part
Pulse Generator	100 MHz 3.5 ns pulse width, <600 ps rise time	HP 8131A option 020
Digitizing Oscilloscope	≥ 6 GHz bandwidth, <58 ps rise time	HP 54121T
Adapter	SMA(m)-BNC(f)	HP 1250-1200
SMA Coax Cable (Qty 3)		HP 8120-4948
Coupler (Qty 3)	BNC(m-m)	HP 1250-0216
BNC Test Connector, 6x2 (Qty 3)		

Set up the equipment

- 1 Turn on the equipment required and the logic analyzer. Let them warm up for 30 minutes before beginning the test if you have not already done so.
- 2 Set up the pulse generator according to the following table.

Pulse Generator Setup

Channel 1	Channel 2	Period
Delay: 0 ps	Delay: 0 ps	20.0 ns
Width: 4.0 ns	Dcyc: 50%	
High: -0.9 V	High: -0.9 V	
Low: -1.7 V	Low: -1.7 V	
COMP: Disabled (LED off)	COMP: Disabled (LED off)	

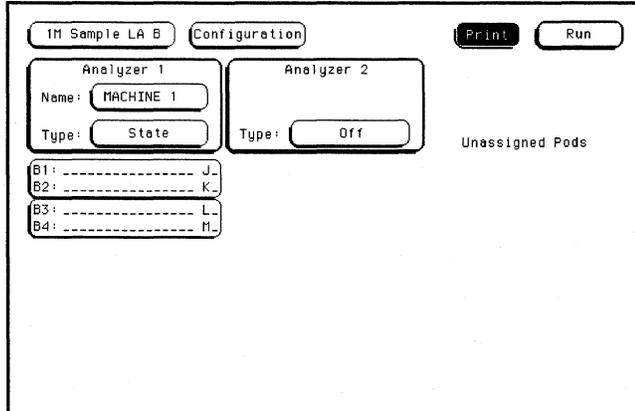
3 Set up the oscilloscope.

Oscilloscope Setup

Time Base	Display	Delta V	Delta t
Time/Div: 1.00 ns/div	avg	V markers on	T markers on
	# of avg: 16	marker 1 position: Chan 1	start on: Neg Edge 1
	screen: dual	marker 2 position: Chan 1	stop on: Neg Edge 2
Channel			
	Channel 1	Channel 2	
Display	on	on	
Probe Atten	20.00	20.00	
Offset	-1.3 V	-1.3 V	
Volts/Div	400 mV	400 mV	

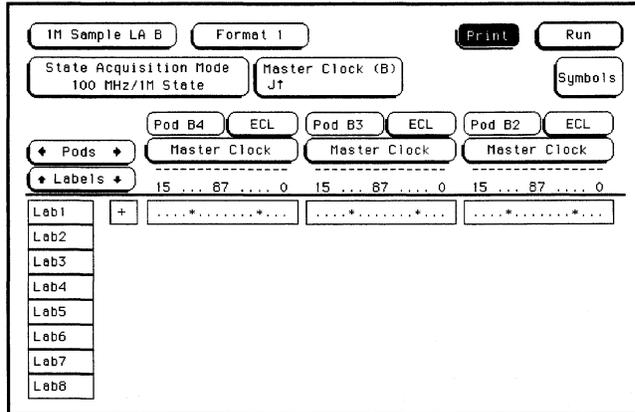
Set up the logic analyzer

- 1 Set up the Configuration menu.**
 - a** In the System Configuration menu, touch System, then select 1M Sample LA.
 - b** In the Configuration menu, assign all pods to Machine 1. To assign all pods, touch the pod fields, then select Machine 1.
 - c** In the Analyzer 1 box, touch the Type field, then select State.



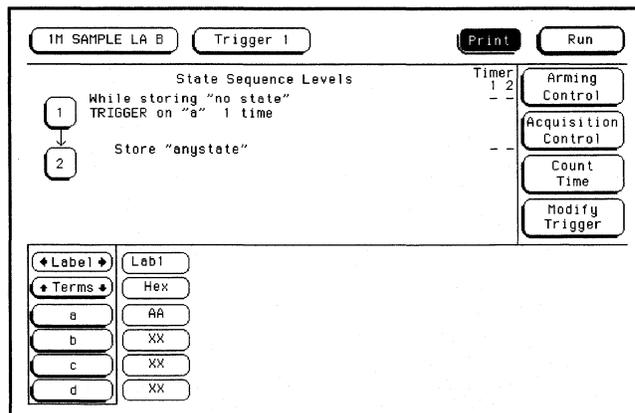
2 Set up the Format menu.

- a Touch Configuration, then select Format.
- b Touch the field to the right of each Pod field, then select ECL. The screen does not show all Pod fields at one time. To access more Pod fields, turn the knob.
- c Touch the field showing the channel assignments for one of the pods being tested. In the pop-up menu, touch Clear until all "." appear. Using the knob, move the cursor to the data channels to be tested (channel 11 and channel 3 of each pod). Touch the asterisk field to put asterisks in the channel positions, activating the channels, then touch Done. Follow this step for the remaining three pods.



3 Set up the Trigger menu.

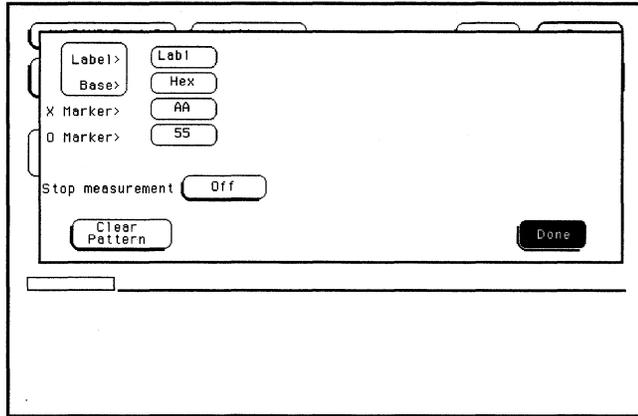
- a Touch Format, then select Trigger. In the Trigger menu, touch Modify Trigger, then select Clear Trigger, then select All.
- b Touch the Count Off field. In the Count menu, touch Off. In the pop-up, select Time, then touch Done to exit.
- c Touch the Acquisition Control field. In the Acquisition Control menu, touch Trigger Position then touch Start. Touch Memory Length, and at the numeric keypad, enter "4096" and Touch Done. Touch Done to exit the menu.
- d Touch the field labeled "1" under the State Sequence Levels. Touch the field labeled "anystate," then select "no state." Touch Done.
- e Touch the pattern recognizer "a." In the pop-up menu, type "AA," then touch Done.



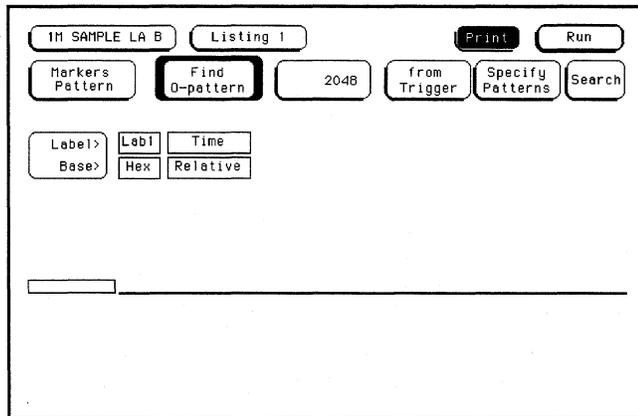
4 Set up the Listing menu.

Testing Performance
To test the single-clock, multiple-edge, state acquisition

- a Touch Trigger, then select Listing.
- b Touch the Markers field, then select Pattern.
- c Touch Specify Patterns. Select the X Marker > field. At the numeric keypad, enter "AA." Select the O Marker > field. At the numeric keypad, enter "55." Touch Done.



- d Touch the Find X-pattern occurrences field. At the numeric keypad, enter "2047." Touch Done.
- e Touch the Find X-pattern field. The field should toggle to Find O-pattern.
- f Touch the Find O-pattern occurrences field. At the numeric keypad, enter "2048." Touch Done.

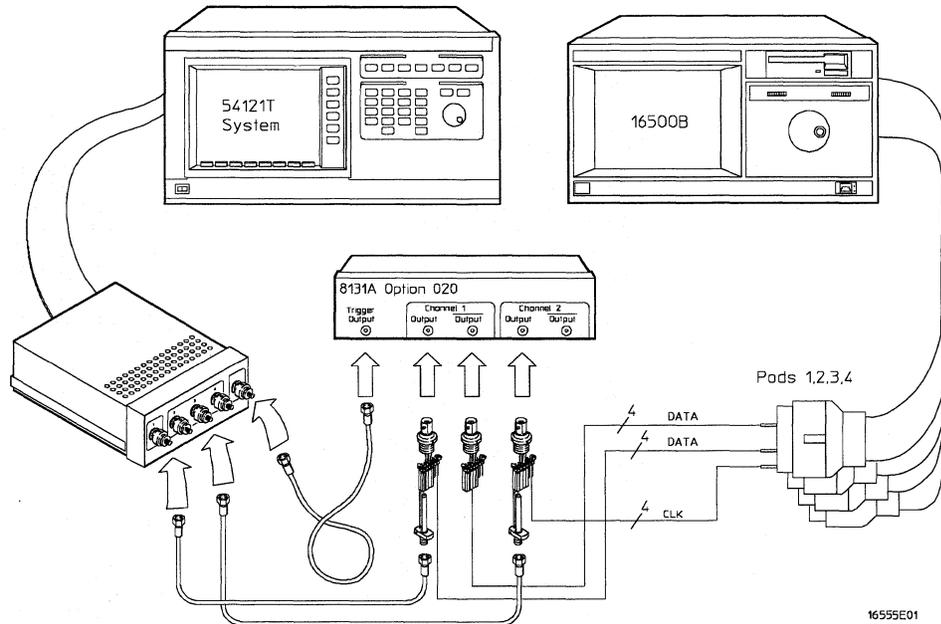


Connect the logic analyzer

- 1 Using the 6-by-2 test connectors, connect the logic analyzer clock and data channels listed in the table below to the pulse generator.
- 2 Using the SMA cables, connect channel 1, channel 2, and trigger from the oscilloscope to the pulse generator.

Connect the Logic Analyzer to the Pulse Generator

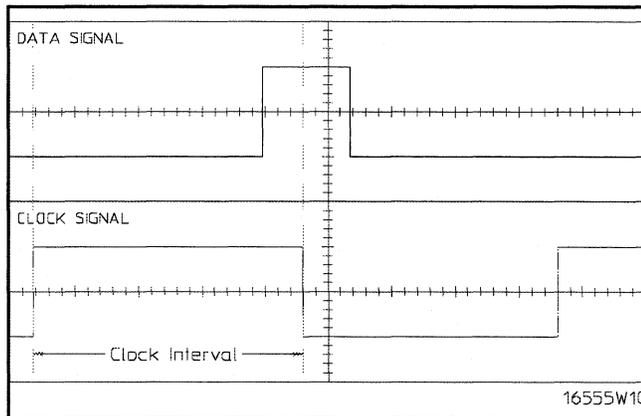
Connect to HP 8131A Channel 1 Output	Connect to HP 8131A Channel 1 Output	Connect to HP 8131A Channel 2 Output
Pod 1, channel 3	Pod 1, channel 11	J-clock
Pod 2, channel 3	Pod 2, channel 11	K-clock
Pod 3, channel 3	Pod 3, channel 11	L-clock
Pod 4, channel 3	Pod 4, channel 11	M-clock



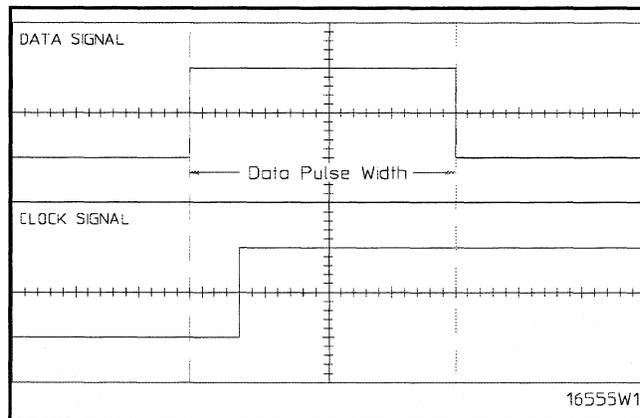
16595E01

Verify the test signal

- 1 Check the clock period. Using the oscilloscope, verify that the master-to-master clock time is 10.000 ns.
 - a In the oscilloscope Timebase menu, select Sweep Speed 2.00 ns/div.
 - b In the oscilloscope Timebase menu, select Delay. Using the oscilloscope knob, position the clock waveform (Channel 2) so that a rising edge appears at the left of the display.
 - c In the oscilloscope Measure menu, select Measure Chan 2, then select + Width. If the positive-going pulse width is more than 10.000 ns, go on to step d. If the positive-going pulse width is less than or equal to 10.000 ns, go to step 2.
 - d In the oscilloscope Measure menu, select - Width. If the negative-going pulse width is less than or equal to 10.000 ns, go to step 2.
 - e Decrease the pulse generator Period in 100 ps increments until the oscilloscope Measure + Width or Measure - Width read less than or equal to 10.000 ns.



- 2 Check the data pulse width. Using the oscilloscope, verify that the data pulse width is 3.980 ns, +20 ps or -80 ps.
 - a In the oscilloscope Timebase menu, select Sweep Speed 2.00 ns/div.
 - b Select Delay. Using the oscilloscope knob, position the data waveform so that the falling edge of the waveform is centered on the screen.
 - c In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 1, Marker 2 at -1.3000 V.
 - d In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop on Neg Edge 1.
 - e If the pulse width is outside of the limits, adjust the pulse generator channel 1 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.



Check the setup/hold with single clock, multiple clock edges

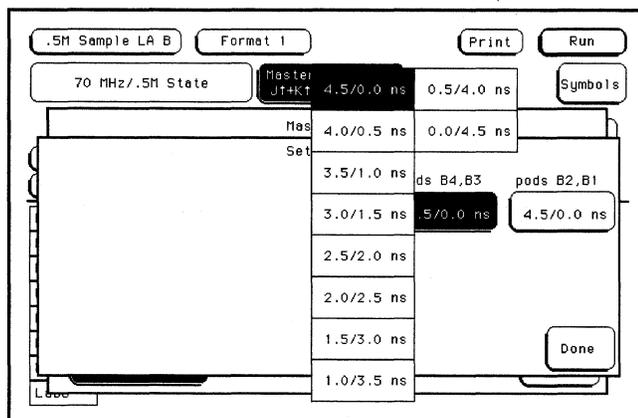
- 1 Select the logic analyzer setup/hold time.
 - a In the logic analyzer Format menu, touch Master Clock.
 - b Select and activate any multiple clock edge.
 - c Touch the Setup/Hold field and select the setup/hold to be tested for all pods. The first time through this test, select the top combination in the following table.

Setup/Hold Combinations

4.0/0.0 ns

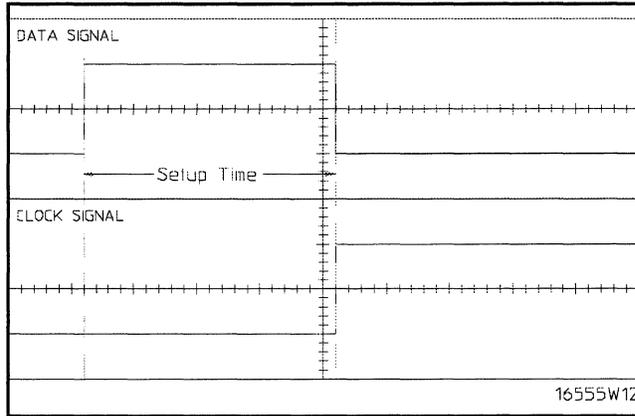
0.0/4.0 ns

2.0/2.0 ns



- d Touch Done to exit the setup/hold combinations.
- 2 Using the Delay mode of the pulse generator channel 2, position the pulses according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.
 - a In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - b In the oscilloscope Delta t menu, select Start on Pos Edge 1. Select Stop on Neg Edge 1.

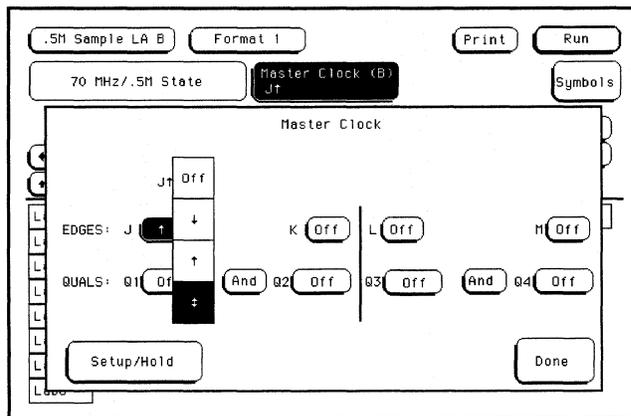
- c Adjust the pulse generator channel 2 Delay and select Precision Edge Find in the oscilloscope Delta t menu until the pulses are aligned according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.



- 3 Select the clock to be tested.
- a Touch the clock field to be tested and then select the clock as indicated in the table. The first time through this test, select the top multiple-edge clock.

Clocks

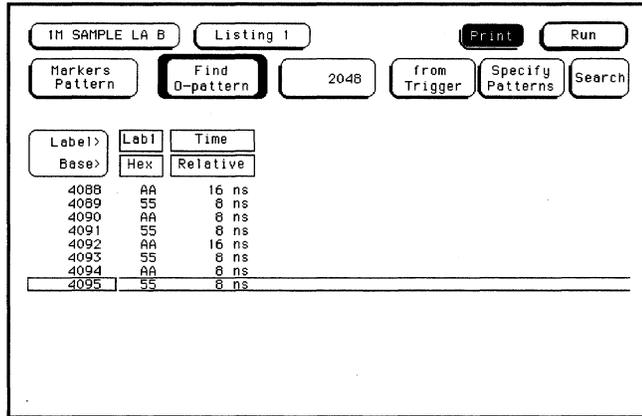
- J⇕
 K⇕
 L⇕
 M⇕



- b Touch Done to exit the Master Clock menu.

Testing Performance
To test the single-clock, multiple-edge, state acquisition

- 4 In the logic analyzer Format menu, touch Run. The display should show an alternating pattern of AA and 55. If the "Search Failed" yellow bar message does not appear, the test passes. Record the Pass or Fail results in the performance test record.



- 5 Test the next clock.
- In the logic analyzer Format menu, touch Master Clock.
 - Turn off the clock just tested.
 - Repeat steps 3, 4, and 5 for the next clock listed in the table in step 4, until all listed clocks have been tested.
- 6 Test the next setup/hold combination.
- In the logic analyzer Format menu, touch Master Clock.
 - Turn off the clock just tested.
 - Repeat steps 1 through 6 for the next setup/hold combination listed in step 1 on page 3–48, until all listed setup/hold combinations have been tested.

When aligning the data and clock waveforms using the oscilloscope, align the waveforms according to the setup time of the setup/hold combination being tested, +0.0 ps or –100 ps.

To test the time interval accuracy

Testing the time interval accuracy does not check a specification, but does check the following:

- 125 MHz oscillator

Multicard modules must be reconfigured as one-card modules for this test.

This test verifies that the 125 MHz timing acquisition synchronizing oscillator is operating within limits.

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part
Pulse Generator	100 MHz 3.5 ns pulse width, <600 ps rise time	HP 8131A Option 020
Function Generator	Accuracy $\leq (5)(10^{-6}) \times$ frequency	HP 3325B Option 002
SMA Cable		HP 8120-4948
Adapter	BNC(m)-SMA(f)	HP 1250-2015
BNC Test Connector, 6x2		

Set up the equipment

- 1 Turn on the equipment required and the logic analyzer. Let them warm up for 30 minutes if you have not already done so.
- 2 Set up the pulse generator according to the following table.

Pulse Generator Setup

Channel 1	Period	Mode	EXT TRIG
Delay: 0 ps	5 μ s	TRIG	Slope: Positive
Width: 2.5 μ s			THRE: 1.0 V
High: -0.9 V			
Low: -1.7 V			
COMP: Disabled (LED off)			

3 Set up the function generator according to the following table.

Function Generator Setup

Freq: 200 000 . 0 Hz

Main Function: Square wave

Amptd: 3.000 V

High Voltage: Disabled (LED Off)

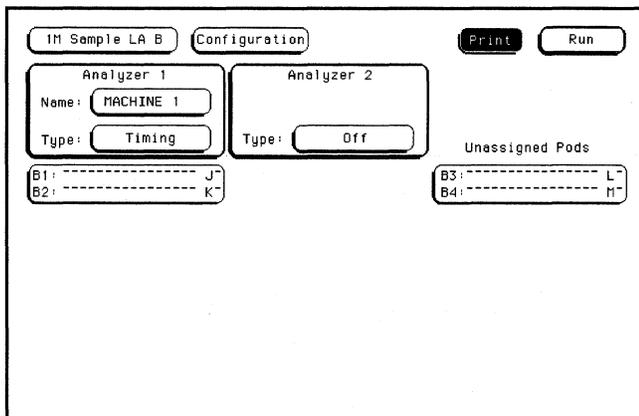
Phase: 0.0 deg

DC Offset: 0.0 V

Set up the logic analyzer

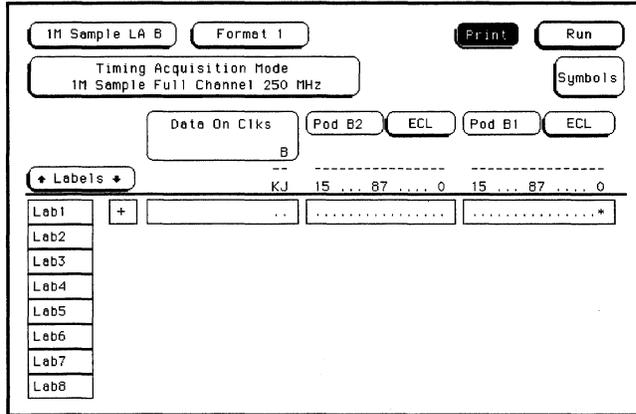
1 Set up the Configuration menu.

- a** In the System Configuration menu, touch System, then select 1M Sample LA.
- b** In the Configuration menu, assign Pod 1 to Machine 1. To assign Pod 1, touch the Pod 1 field, then select Machine 1.
- c** In the Analyzer 1 box, touch the Type field, then select Timing.

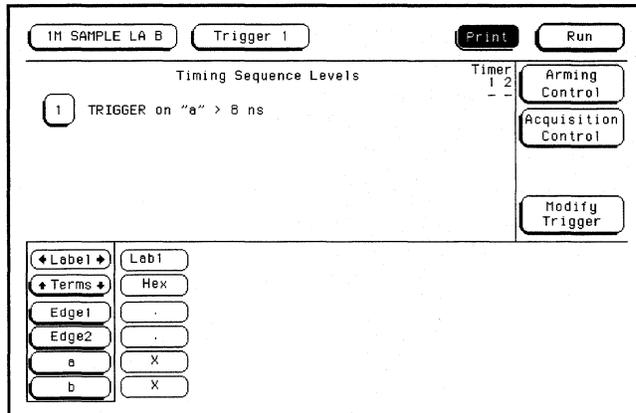


2 Set up the Format menu.

- a Touch Configuration, then select Format. In the Format menu, touch Timing Acquisition Mode, then select 1M Sample Full Channel 250 MHz.
- b Touch the field to the right of the Pod 1 field, then select ECL.
- c Touch the field showing the channel assignments for Pod 1. Deactivate all channels by selecting Clear. Using the knob, move the cursor to Channel 0. Touch the asterisk field to put an asterisk in the channel position, activating the channel, then touch Done.



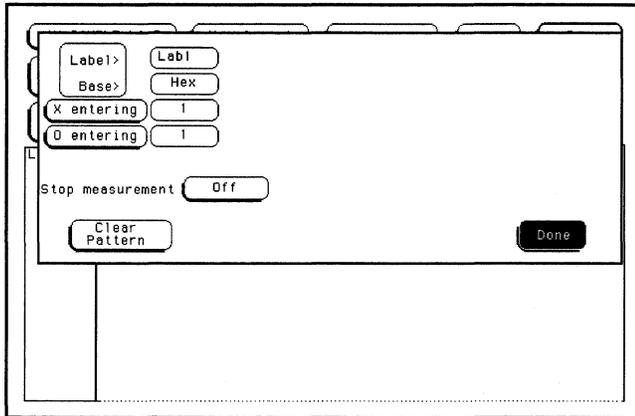
3 Touch Format, then select Trigger. In the Trigger menu, touch Modify Trigger, then select Clear Trigger, then select All.



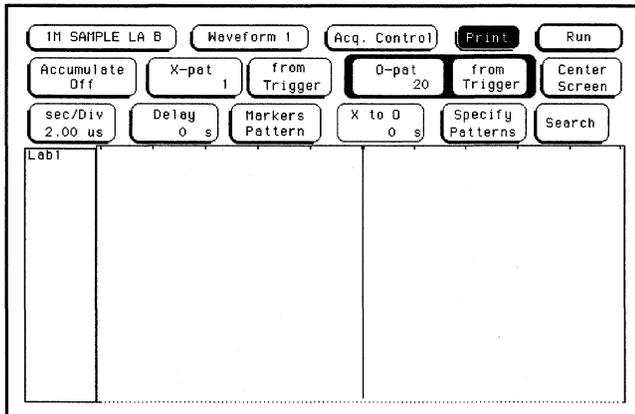
Testing Performance
To test the time interval accuracy

4 Set up the Waveform menu.

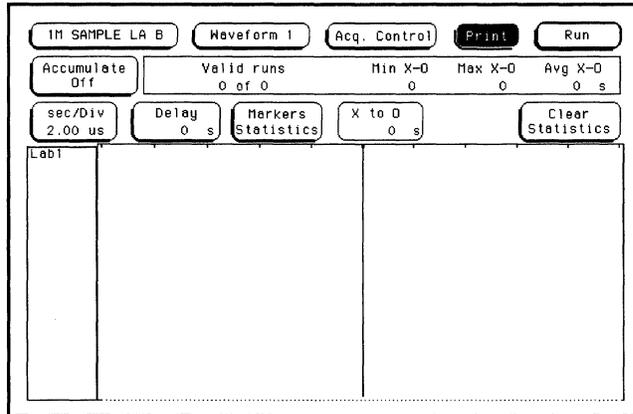
- a Touch Trigger, then select Waveform.
- b Touch the sec/Div field. In the pop-up menu, type 2 μ s, then touch Done.
- c Touch the Markers Off field, then select Pattern.
- d Touch the Specify Patterns field. Select X entering 1 and O entering 1.



- e Touch Done to exit the Specify Patterns menu.
- f Touch the X-pat field twice. In the pop-up menu, select "1" and touch Done.
- g Touch the O-pat field twice. In the pop-up menu, select "20" and touch Done.

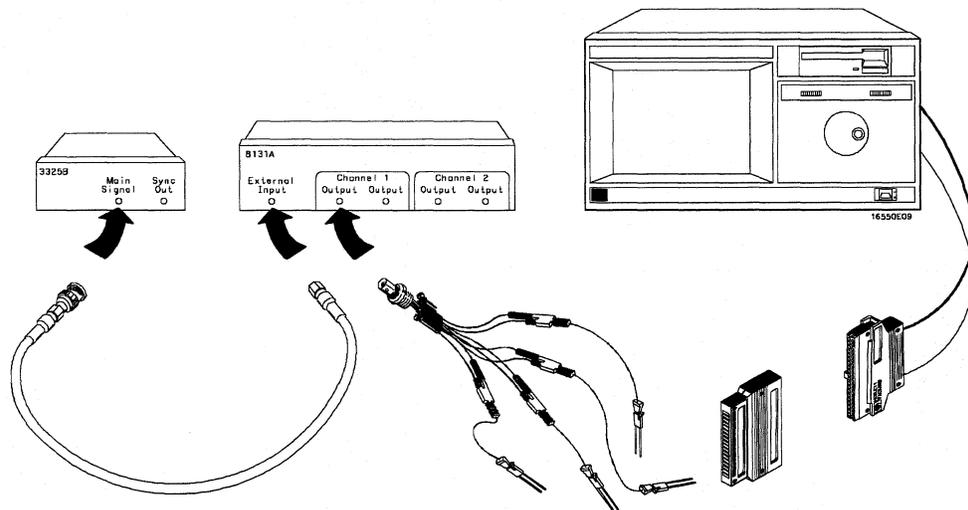


h Touch the Markers Patterns field and select Statistics. Touch Clear Statistics to initialize the statistics fields.



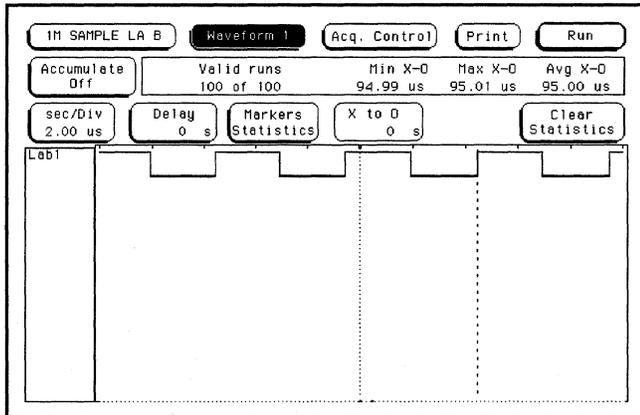
Connect the logic analyzer

- 1 Using a 6-by-2 test connector, connect channel 0 of Pod 1 to the pulse generator channel 1 output.
- 2 Using the SMA cable and the BNC adapter, connect the External Input of the pulse generator to the Main Signal of the function generator.



Acquire the data

- 1 Enable the pulse generator channel 1 output (LED off).
- 2 In the logic analyzer Waveform menu, touch Run-Repetitive. Allow the logic analyzer to acquire data for at least 100 valid runs as indicated in the pattern statistics field.
- 3 When the logic analyzer has acquired more than 100 valid runs, touch Stop. The Min X-O field in the logic analyzer Pattern Statistics menu should read 94.99–95.00 μs . The Max X-O field should read 95.00–95.01 μs . The Avg X-O field should read 95.00 μs . Record the results in the performance test record.



To perform the multiscard test

Performing the multiscard test verifies the performance of the following specifications:

- Minimum master to master clock time.
- Maximum state acquisition speed.

Multiscard modules that were changed to one-card modules for the previous performance tests need to be reconfigured as a multiscard module for this test.

This test checks a multiscard module using one combination of data channels and a single-edge clock at one setup/hold time.

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part
Pulse Generator	110 MHz 3.5 ns pulse width, <600 ps rise time	HP 8131A option 020
Digitizing Oscilloscope	≥ 6 GHz bandwidth, <58 ps rise time	HP 54121T
Adapter	SMA(m)-BNC(f)	HP 1250-1200
SMA Coax Cable (Qty 3)		HP 8120-4948
Coupler (Qty 3)	BNC(m-m)	HP 1250-0216
BNC Test Connector, 6x2 (Qty 3)		

Set up the equipment

- 1 Turn on the equipment required and the logic analyzer. Let them warm up for 30 minutes before beginning the test if you have not already done so.
- 2 Set up the pulse generator according to the following table.

Pulse Generator Setup

Channel 1	Channel 2	Period
Delay: 0 ps	Doub: 9.05 ns *	18.1 ns *
Width: 3.5 ns	Width: 3.5 ns	
High: -0.9 V	High: -0.9 V	
Low: -1.7 V	Low: -1.7 V	
COMP: Disabled (LED off)	COMP: Disabled (LED off)	

* If running software version v2.xx, set Channel 2 Doub: 10 ns, and Period to 20 ns. 110-MHz single-clock state acquisition mode is available with operating system v3.00 or higher. For information on operating system version, refer to page 1-3.

3 Set up the oscilloscope.

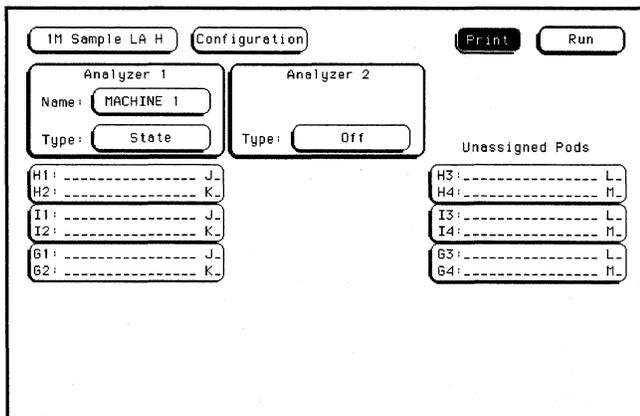
Oscilloscope Setup

Time Base	Display	Delta V	Delta t
Time/Div: 1.00 ns/div	avg	V markers on	T markers on
	# of avg: 16	marker 1 position: Chan 1	start on: Pos Edge 1
	screen: dual	marker 2 position: Chan 1	stop on: Neg Edge 1
Channel			
	Channel 1	Channel 2	
Display	on	on	
Probe Atten	20.00	20.00	
Offset	-1.3 V	-1.3 V	
Volts/Div	400 mV	400 mV	

Set up the logic analyzer

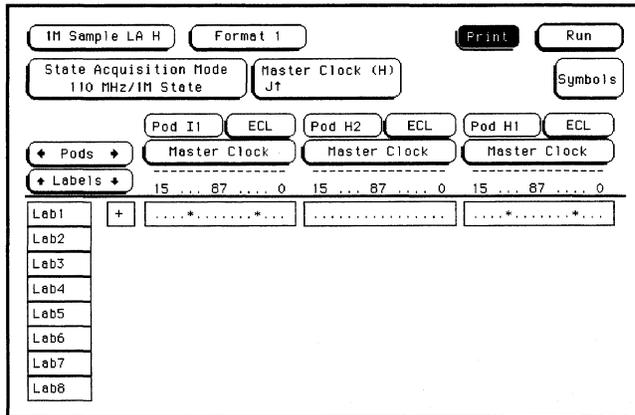
1 Set up the Configuration menu.

- a In the System Configuration menu, touch System, then select 1M Sample LA.
- b In the Configuration menu, assign pods 1 and 2 of the master and pods 1 and 2 of all expander cards to Machine 1. To assign the pods, touch the pod fields, then select Machine 1.
- c In the Analyzer 1 box, touch the Type field, then select State.



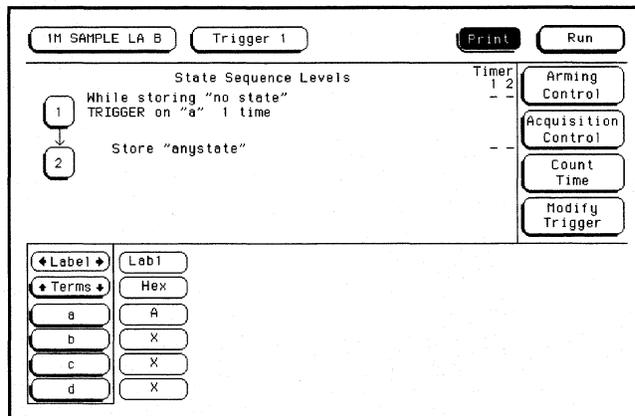
2 Set up the Format menu.

- a Touch Configuration, then select Format.
- b Touch the field to the right of each Pod field, then select ECL. The screen does not show all Pod fields at one time. To access more Pod fields, turn the knob.
- c Touch the field showing the channel assignments for Pod 1 on one of the boards being tested. In the pop-up menu, touch Clear until all "." appear. Using the knob, move the cursor to the data channels to be tested (channel 11 and channel 3 of Pod 1). Touch the asterisk field to put asterisks in the channel positions, activating the channels, then touch Done. Follow this step for Pod 1 on the remaining boards.
- d Touch the State Acquisition Mode field, then select 110MHz/1M State.



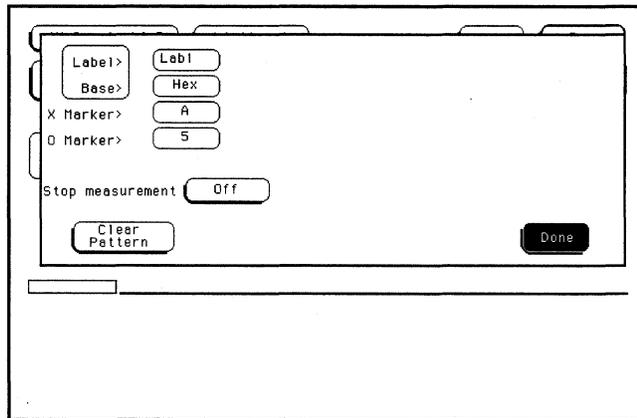
3 Set up the Trigger menu.

- a Touch Format, then select Trigger. In the Trigger menu, touch Modify Trigger, then touch Clear Trigger, then select All.
- b Touch the Count Off field. In the Count menu, touch Off. In the pop-up, select Time, then touch Done to exit.
- c Touch the Acquisition Control field. In the Acquisition Control menu, touch Trigger Position then touch Start. Touch Memory Length, and at the numeric keypad, enter "4096" and Touch Done. Touch Done to exit the menu.
- d Touch the field labeled "1" under the State Sequence Levels. Touch the field labeled "anystate," then select "no state." Touch Done.
- e Touch pattern recognizer "a." In the pop-up menu, type the pattern corresponding to the number of cards in the module, then touch Done.
For two-card module type "A", for three-card module type "2A."

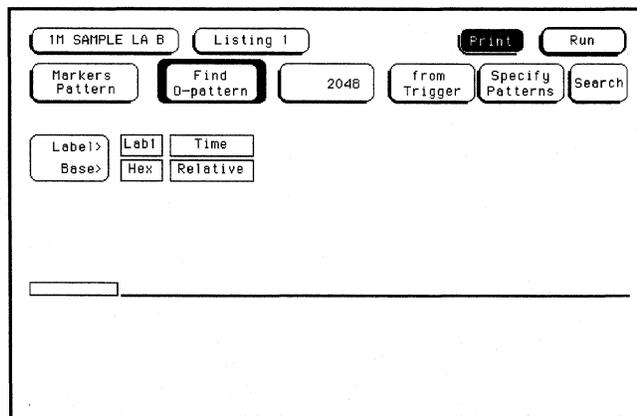


Testing Performance
To perform the multiscard test

- 4 Set up the Listing menu.
 - a Touch Trigger, then select Listing.
 - b Touch the Markers field, then select Pattern.
 - c Touch Specify Patterns. Select the X Marker > field. In the pop-up menu, type the pattern corresponding to the number of cards in the module, then touch Done.
two-card module, type "A"
three-card module, type "2A"
 - d Select the O Marker > field. In the pop-up menu, type the pattern corresponding to the number of cards in the module, then touch Done.
two-card module, type "5"
three-card module, type "15"



- e Touch the Find X-pattern occurrences field. At the numeric keypad, enter "2047." Touch Done.
- f Touch the Find X-pattern field. The field should toggle to Find O-pattern.
- g Touch the Find O-pattern occurrences field. At the numeric keypad, enter "2048." Touch Done.

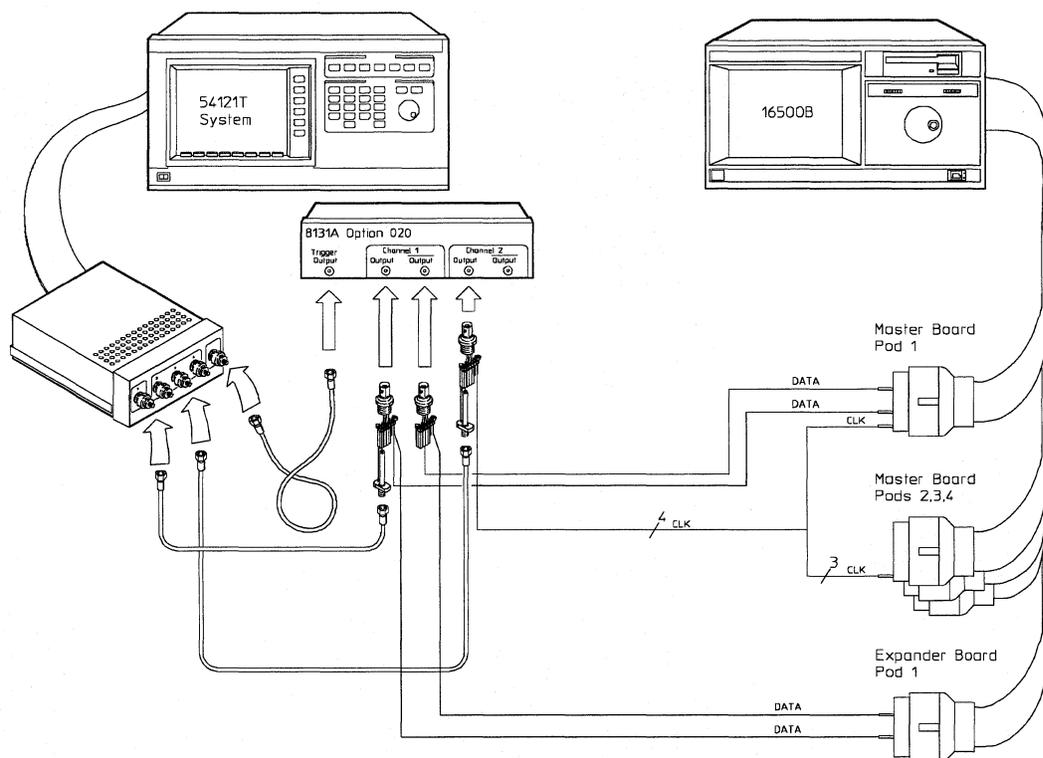


Connect the logic analyzer

- 1 Using the 6-by-2 test connectors, connect the logic analyzer clock and data channels listed the table below to the pulse generator.
- 2 Using SMA cables, connect channel 1, channel 2, and trigger from the oscilloscope to the pulse generator.

Connect the Logic Analyzer to the Pulse Generator

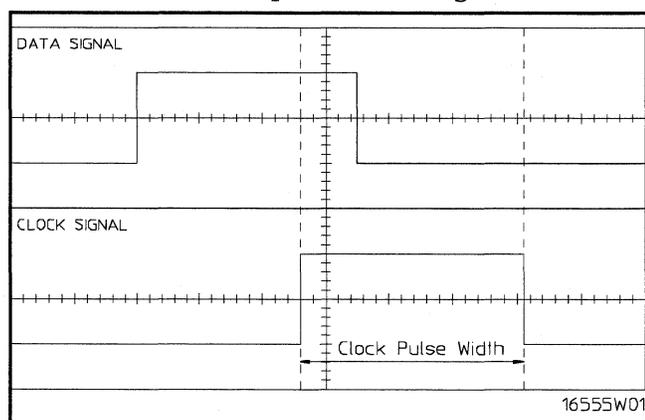
	Connect to HP 8131A Channel 1 Output	Connect to HP 8131A Channel 1 Output	Connect to HP 8131A Channel 2 Output
Master Board	Pod 1, channel 3	Pod 1, channel 11	J-clock K-clock L-clock M-clock
All Expander Boards	Pod 1, channel 3	Pod 1, channel 11	



16555E30

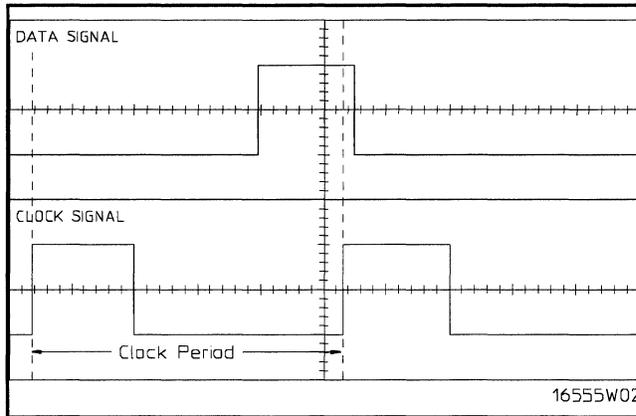
Verify the test signal

- 1 Check the clock pulse width. Using the oscilloscope, verify that the clock pulse width is 3.480 ns, +20 ps or -80 ps.
 - a Enable the pulse generator channel 1 and channel 2 outputs.
 - b In the oscilloscope Timebase menu, select Delay. Using the oscilloscope knob, position the clock waveform so that the waveform is centered on the screen.
 - c In the oscilloscope Delta V menu, select Marker 1 Position Chan 2, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - d In the oscilloscope Delta t menu, select Start On Pos Edge 1. Select Stop on Neg Edge 1.
 - e If the pulse width is outside the limits, adjust the pulse generator channel 2 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.



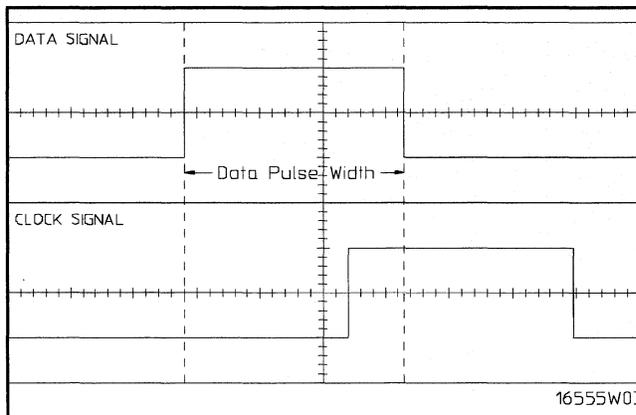
- 2 Check the clock period. Using the oscilloscope, verify that the master-to-master clock time is 9.05 ns. *
 - a In the oscilloscope Timebase menu, select Sweep Speed 3.00 ns/div.
 - b Select Delay. Using the oscilloscope knob, position the clock waveform so that a rising edge appears at the left of the display.
 - c In the oscilloscope Measure menu, select Measure Chan 2, then select Period. If the period is not less than 9.05 ns, go to step d. If the period is less than 9.05 ns, go to step 3.
 - d In the oscilloscope Timebase menu, add 9.000 ns to the delay.
 - e In the oscilloscope Measure menu, select Period. If the period is not less than 9.05 ns, decrease the pulse generator Chan 2 Doub in 10 ps increments until one of the two periods measured is less than 9.05 ns.

*If running software version v2.xx, then measure the master-to-master clock time of 10 ns.



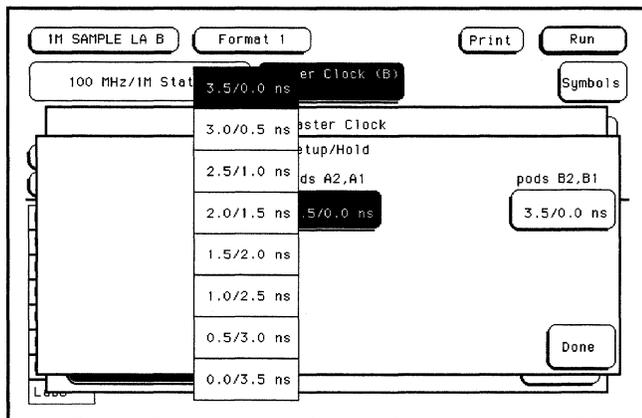
3 Check the data pulse width. Using the oscilloscope, verify that the data pulse width is 3.480 ns +20 ps or -80 ps.

- a** In the oscilloscope Timebase menu, select Sweep Speed 1.00 ns/div.
- b** Select Delay. Using the oscilloscope knob, position the data waveform so that the waveform is centered on the screen.
- c** In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.300 V. Select Marker 2 position Chan 1, marker 2 at -1.3000 V.
- d** In the oscilloscope Delta t menu, select Start On Pos Edge 1 and Stop on Neg Edge 1.
- e** Select Precision Edge Find.
- f** If the pulse width is outside the limits, adjust the pulse generator channel 1 width and select the oscilloscope Precision Edge Find until the pulse width is within limits.



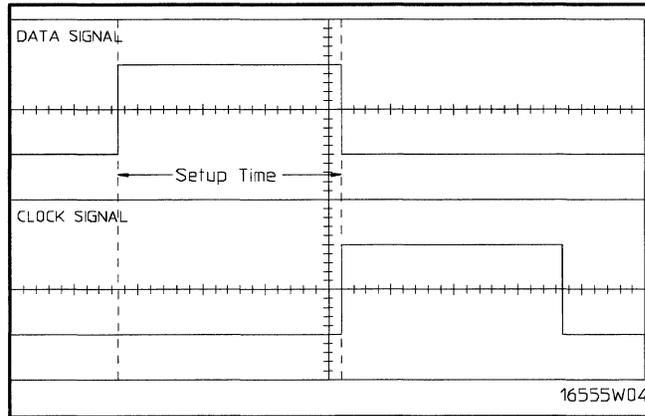
Check the setup/hold combination

- 1 Select the logic analyzer setup/hold time.
 - a In the logic analyzer Format menu, touch Master Clock.
 - b Touch the Setup/Hold field and select the 3.5/0.0 ns setup/hold combination to be tested for all pods.
 - c Touch Done to exit the setup/hold combinations.



- 2 Using the Delay mode of the pulse generator channel 1, position the pulses according to the setup/hold combination selected, +0.0 ps or -100 ps.
 - a In the oscilloscope Delta V menu, select Marker 1 Position Chan 1, Marker 1 at -1.3000 V. Select Marker 2 Position Chan 2, Marker 2 at -1.3000 V.
 - b In the oscilloscope Delta t menu, select Start on Pos Edge 1. Select Stop on Pos Edge 1.

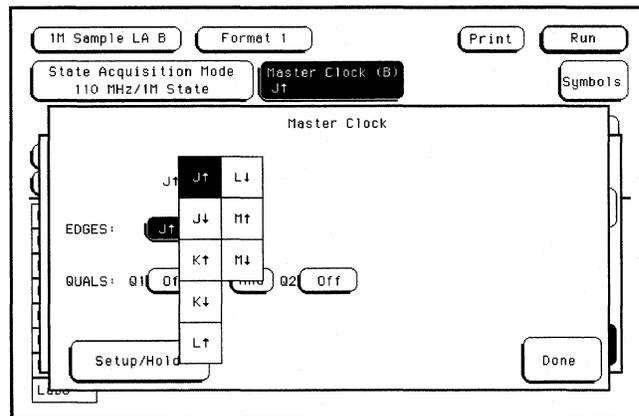
- c Adjust the pulse generator channel 1 Delay and select Precision Edge Find in the oscilloscope Delta t menu until the pulses are aligned according to the setup time of the setup/hold combination selected, +0.0 ps or -100 ps.



- 3 Select the clock to be tested.
 - a Touch the clock field to be tested and then select the clock edge as indicated in the table. The first time through this test, select the top clock and edge.

Clocks

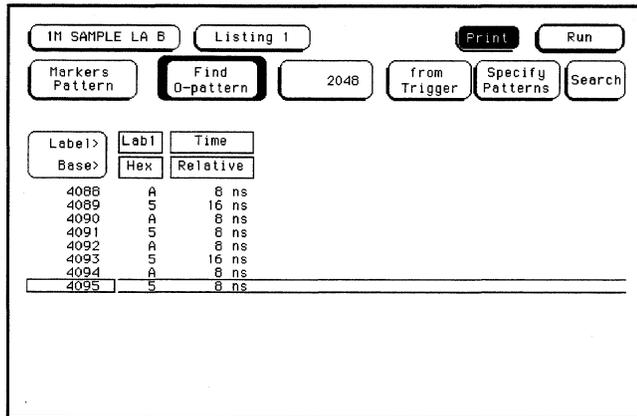
- J↑
- K↑
- L↑
- M↑



- b Touch Done to exit the Master Clock menu.

Testing Performance
To perform the multicard test

- 4 In the logic analyzer Format menu, touch Run. The display should show an alternating pattern of alternating A and 5 (or whatever pattern selected in step 4, page 3-60). If the "Search Failed" yellow bar message does not appear, the test passes. Record the Pass or Fail results in the performance test record.



- 5 Test the next clock.
- In the logic analyzer Format menu, touch Master Clock.
 - Turn off the clock just tested.
 - Repeat steps 3, 4, and 5 for the next clock edge listed in the table in step 3, until all listed clock edges have been tested.

Performance Test Record

Performance Test Record

	HEWLETT PACKARD	HP 16555A Logic Analyzer _____
Serial No. _____		Work Order No. _____
Recommended Test Interval - 2 Year/4000 hours		Date _____
Recommended next testing _____		Temperature _____

Test	Settings	Results		
Self-Tests	Board Verification Tests Acquisition IC Verification Tests	Pass/Fail _____ Pass/Fail _____		
Threshold Accuracy	\pm (100 mV + 3% of threshold setting)	Limits _____ Measured _____		
Pod 1	TTL, \pm 145 mV	TTL VL +1.355 V TTL VH +1.645 V		
	ECL, \pm 139 mV	ECL VL -1.439 V ECL VH -1.161 V		
	-User, \pm 280 mV	-User VL -6.280 V - User VH -5.720 V		
	+User, \pm 280 mV	+ User VL +5.720 V + User VH +6.280 V		
	0 V, \pm 100 mV	0 V User VL -100 mV 0 V User VH +100 mV		
	Pod 2	TTL, \pm 145 mV	TTL VL +1.355 V TTL VH +1.645 V	
		ECL, \pm 139 mV	ECL VL -1.439 V ECL VH -1.161 V	
		-User, \pm 280 mV	-User VL -6.280 V - User VH -5.720 V	
		+User, \pm 280 mV	+ User VL +5.720 V + User VH +6.280 V	
		0 V, \pm 100 mV	0 V User VL -100 mV 0 V User VH +100 mV	
		Pod 3	TTL, \pm 145 mV	TTL VL +1.355 V TTL VH +1.645 V
			ECL, \pm 139 mV	ECL VL -1.439 V ECL VH -1.161 V
			-User, \pm 280 mV	-User VL -6.280 V - User VH -5.720 V
			+User, \pm 280 mV	+ User VL +5.720 V + User VH +6.280 V
			0 V, \pm 100 mV	0 V User VL -100 mV 0 V User VH +100 mV

**Testing Performance
Performance Test Record**

Performance Test Record (continued)

Test	Settings		Results			
Threshold Accuracy (continued)			Limits	Measured		
Pod 4	TTL, ±145 mV	TTL VL TTL VH	+1.355 V +1.645 V	_____		
	ECL, ±139 mV	ECL VL ECL VH	-1.439 V -1.161 V	_____		
	-User, ±280 mV	-User VL - User VH	-6.280 V -5.720 V	_____		
	+User, ±280 mV	+ User VL + User VH	+5.720 V +6.280 V	_____		
	0 V, ±100 mV	0 V User VL 0 V User VH	-100 mV +100 mV	_____		
Single-Clock, Single-Edge Acquisition			Disable pulse generator, channel 2 COMP (LED off)	Enable pulse generator, channel 2 COMP (LED on)		
			Pass/Fail		Pass/Fail	
All Pods	Setup/Hold Time	3.5/0.0 ns	J↑ K↑ L↑ M↑	_____ _____ _____ _____	J↓ K↓ L↓ M↓	_____ _____ _____ _____
	Setup/Hold Time	0.0/3.5 ns	J↑ K↑ L↑ M↑	_____ _____ _____ _____	J↓ K↓ L↓ M↓	_____ _____ _____ _____
	Setup/Hold Time	1.5/2.0 ns	J↑ K↑ L↑ M↑	_____ _____ _____ _____	J↓ K↓ L↓ M↓	_____ _____ _____ _____
Multiple-Clock, Multiple-Edge Acquisition			Disable pulse generator, channel 2 COMP (LED off)	Enable pulse generator, channel 2 COMP (LED on)		
			Pass/Fail		Pass/Fail	
All Pods	Setup/Hold Time	4.5/0.0 ns	J↑ + K↑ + L↑ + M↑	_____ _____	J↓ + K↓ + L↓ + M↓	_____ _____
	Setup/Hold Time	0.0/4.5 ns	J↑ + K↑ + L↑ + M↑	_____ _____	J↓ + K↓ + L↓ + M↓	_____ _____
	Setup/Hold Time	2.0/2.5 ns	J↑ + K↑ + L↑ + M↑	_____ _____	J↓ + K↓ + L↓ + M↓	_____ _____

Performance Test Record (continued)

Test	Settings	Results	
Single-Clock, Multiple-Edge Acquisition All Pods	Setup/Hold Time 4.0/0.0 ns	<p style="text-align: right;">Pass/Fail</p> J↕ _____ K↕ _____ L↕ _____ M↕ _____	
	Setup/Hold Time 0.0/4.0 ns	J↕ _____ K↕ _____ L↕ _____ M↕ _____	
	Setup/Hold Time 2.0/2.0 ns	J↕ _____ K↕ _____ L↕ _____ M↕ _____	
	Time Interval Accuracy	min X-0 94.99-95.00 μs	<p style="text-align: right;">Measured</p> _____
		max X-0 95.00-95.01 μs	_____
		avg X-0 94.99-95.01 μs	_____
	Multi-Card Test	Setup/Hold Time 3.5/0.0 ns	<p style="text-align: right;">Pass/Fail</p> J↑ _____ K↑ _____ L↑ _____ M↑ _____

Calibrating

Calibrating

This chapter gives you instructions for calibrating the logic analyzer.



Calibration Strategy

The HP 16555A logic analyzer does not require an operational accuracy calibration. To test the module against the module specifications, refer to "Testing Performance" in chapter 3.

To use the flowcharts 5-2

To run the self-tests 5-7

To run the Board Verification tests 5-8

To run the Acquisition IC Verification tests 5-10

To test the cables 5-13

To test the auxiliary power 5-17

Troubleshooting

This chapter helps you troubleshoot the module to find defective assemblies. The troubleshooting consists of flowcharts, self-test instructions, a cable test, and a test for the auxiliary power supplied by the probe cable. This information is not intended for component-level repair.

If you suspect a problem, start at the top of the first flowchart. During the troubleshooting instructions, the flowcharts will direct you to perform the self-tests or the cable test.

The service strategy for this instrument is the replacement of defective assemblies. This module can be returned to Hewlett-Packard for all service work, including troubleshooting. Contact your nearest Hewlett-Packard Sales Office for more details.

CAUTION

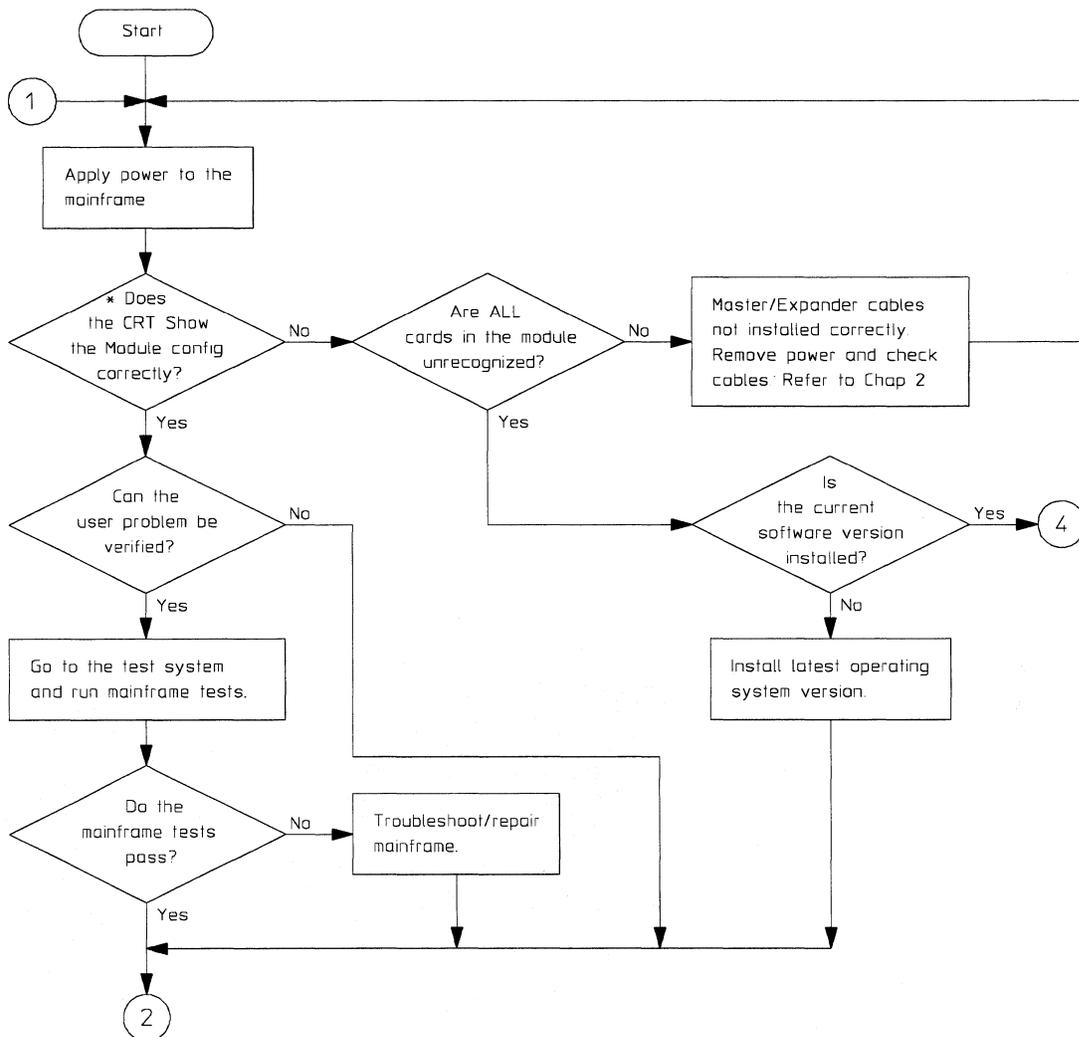
Electrostatic discharge can damage electronic components. Use grounded wriststraps and mats when you perform any service to this instrument or to the cards in it.

To use the flowcharts

Flowcharts are the primary tool used to isolate defective assemblies. The flowcharts refer to other tests to help isolate the trouble. The circled letters on the charts indicate connections with the other flowcharts. Start your troubleshooting at the top of the first flowchart.

Before starting the troubleshooting, ensure that operating system v3.00 or later is installed on the mainframe. To check the operating system version number, enter the Test menu.

If v3.00 or later is not loaded, obtain a copy of the v3.00 operating system firmware and install it on the logic analyzer hard drive. After installation, recycle power on the mainframe.

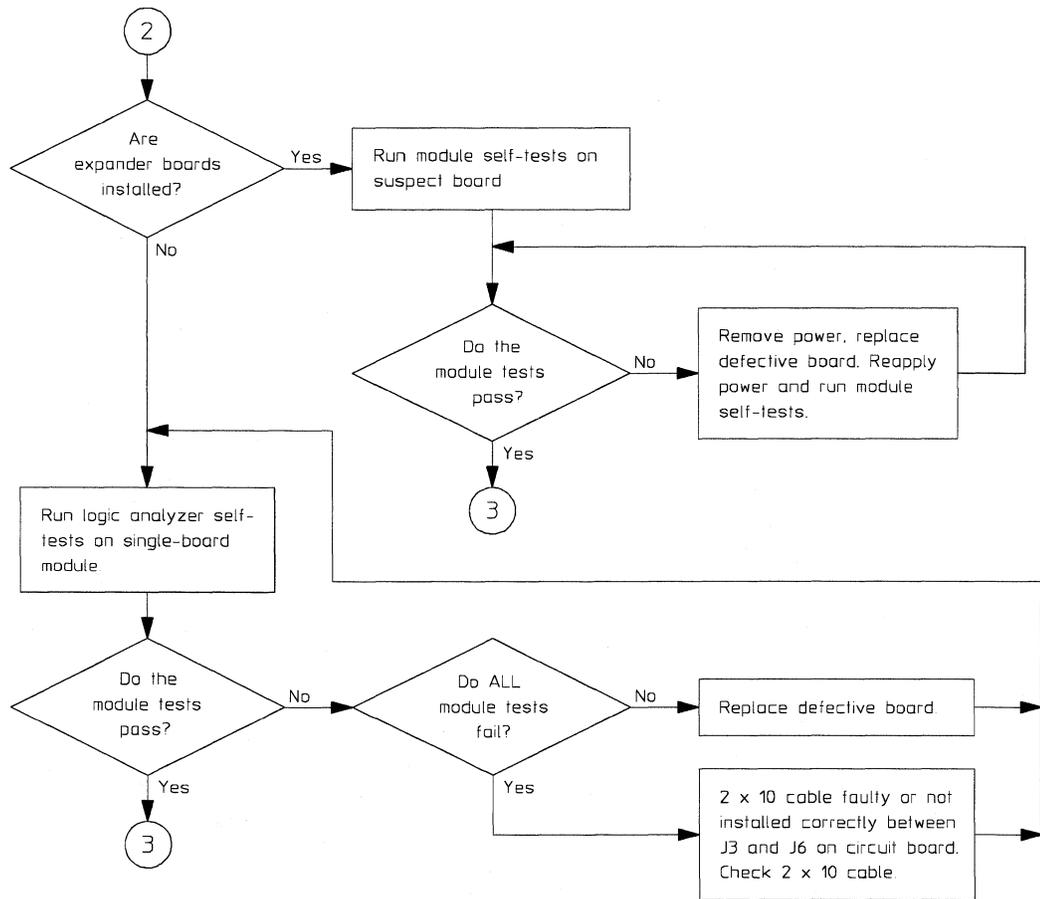


* Look at the pwer-up menu on the mainframe to see if the module Master/Expander configuration displayed matches the actual configuration in the card cage

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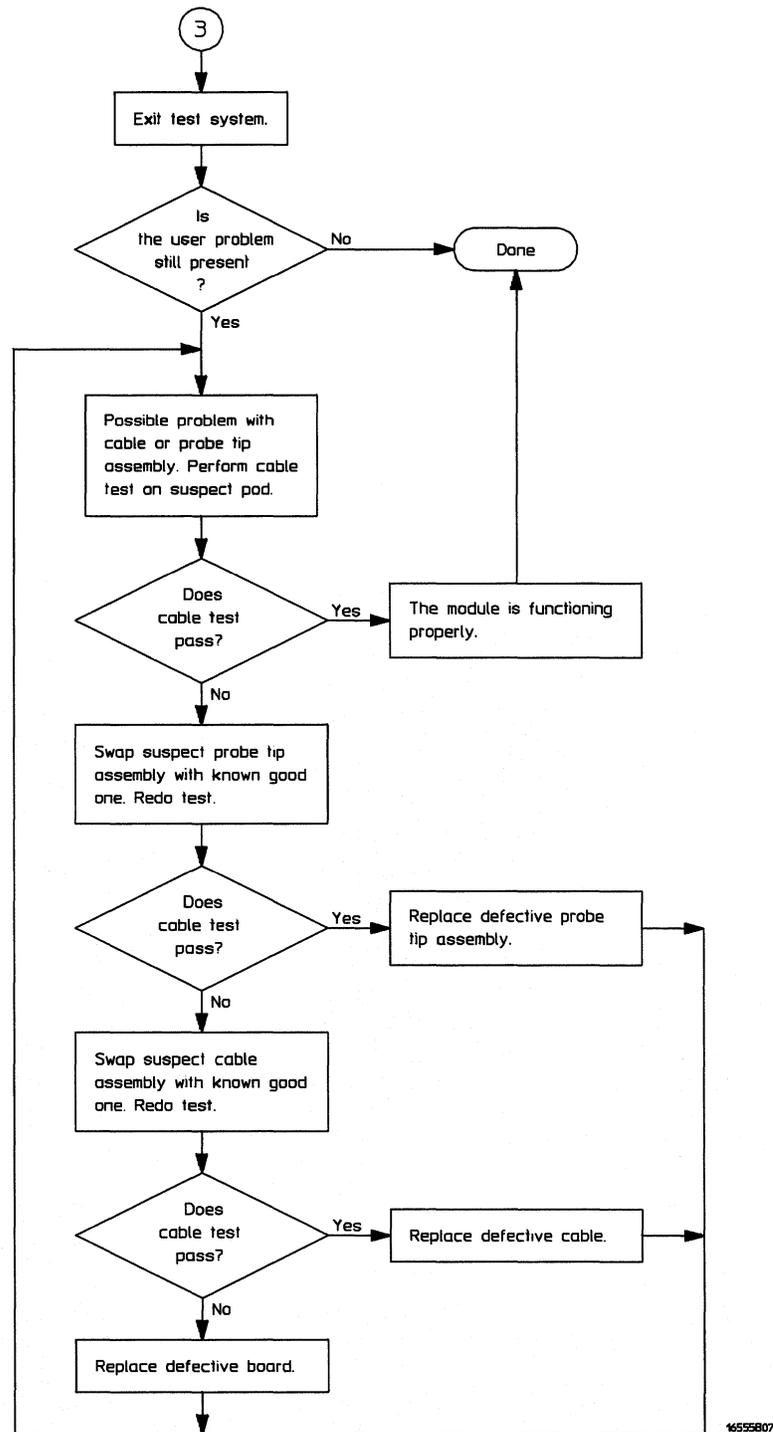
Troubleshooting Flowchart 1

**Troubleshooting
To use the flowcharts**



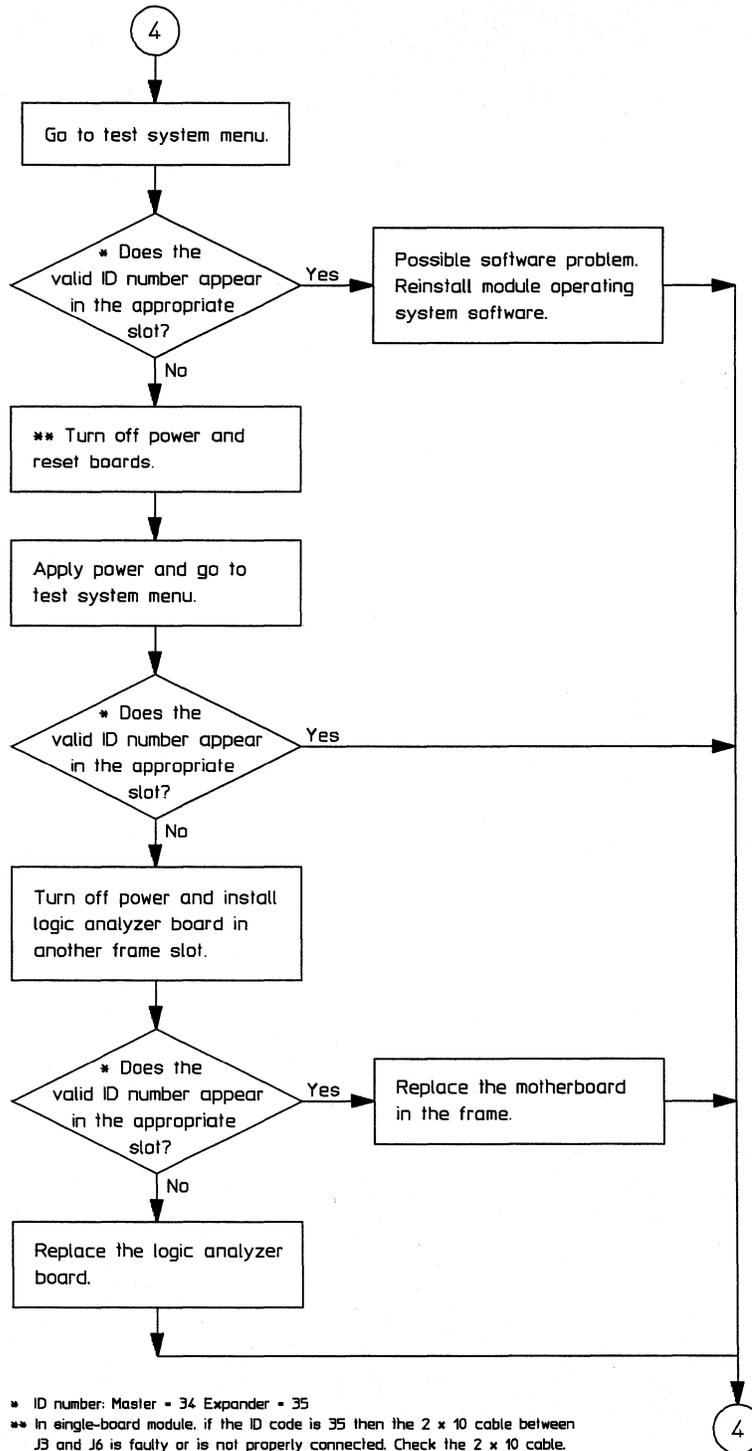
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Troubleshooting Flowchart 2



Troubleshooting Flowchart 3

Troubleshooting
To use the flowcharts



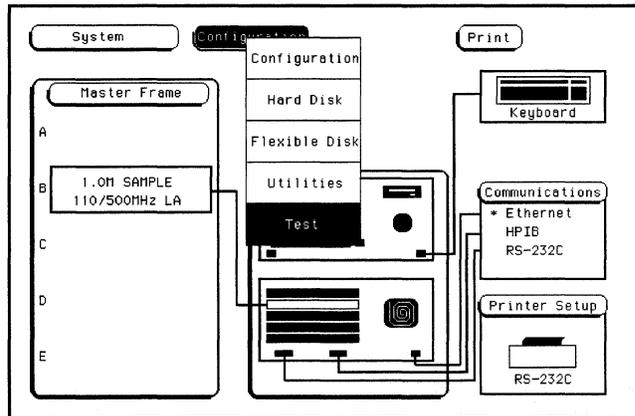
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Troubleshooting Flowchart 4

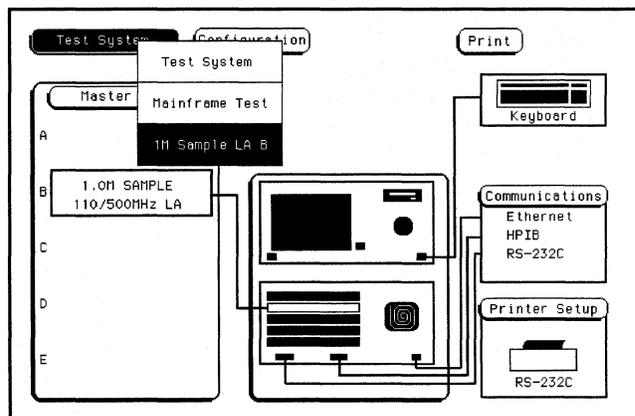
To run the self-tests

Self-tests for the module identify the correct operation of major functional areas of the module. The self-tests consist of Board Verification tests and Chip Verification tests. You can run all self-tests without accessing the interior of the instrument. If a self-test fails, the troubleshooting flowcharts instruct you to change a card or cable of the module.

- 1 Disconnect all inputs, then turn on the power switch.
- 2 In the System Configuration menu, touch Configuration. In the pop-up menu, touch Test.

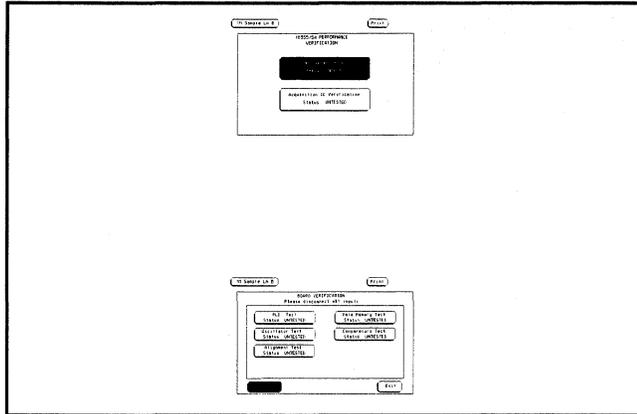


- 3 In the Test menu, touch the box labeled Touch box to Load Test System.
- 4 In the test system screen, touch Test System. Select the 1M Sample LA module to be tested.



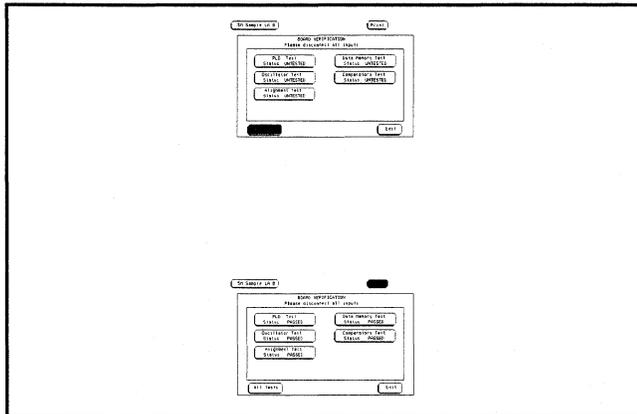
To run the Board Verification tests

- 1 In the Performance Verification menu, touch Board Verification.



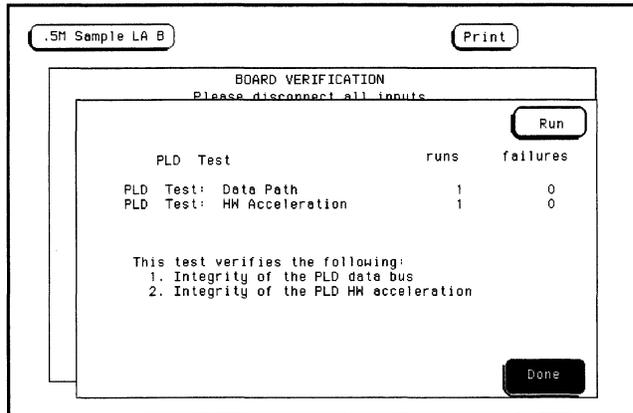
- 2 In the Board Verification menu, touch PLD test.

You can run all tests at one time by touching All Tests. To see more details about each test, you can run each test individually. This example shows how to run the PLD Test. The Data Memory Test, Oscillator Test, and Comparators Test operate the same as the PLD Test.



3 In the PLD Test menu, touch Run. The test runs one time, and the screen shows the result.

To run a test continuously, touch and hold your finger on Run. Drag your finger to Repetitive, then lift your finger. Touch Stop to stop Run Repetitive.



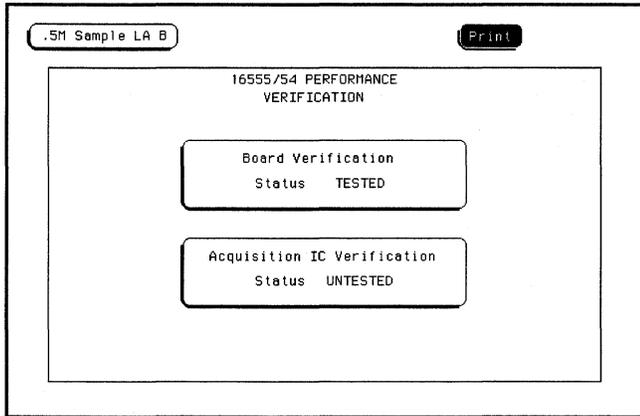
4 When the test is finished, touch Done. Then, perform the Deep Memory, Oscillator, Comparators, and Alignment tests.

5 Touch Exit to leave the Board Verification tests.

To run the Acquisition IC Verification tests

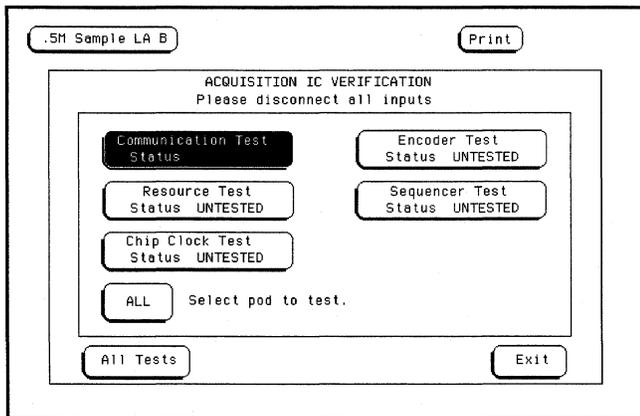
- 1 In the Performance Verification menu, touch Acquisition IC Verification.

Instead of testing all of the pods, each pod pair can be tested individually. To test a specific pod pair, first touch the field labeled "All." Then touch the field labeled "Xn," where "X" corresponds to the slot in the card cage where the card resides, and "n" refers to the pod pair (either "0" for pods 1 and 2 or "1" for pods 3 and 4).



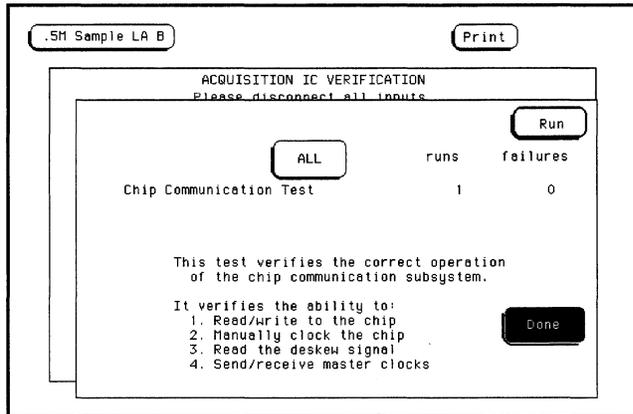
- 2 In the Acquisition IC Verification menu, touch Communication Test.

You can run all tests at one time by touching All Tests. To see more details about each test, you can run each test individually. This example shows how to run the Communication Test. The Resource Test, Encoder Test, Sequencer Test, and Chip Clock Test operate the same as the Communication Test.



3 In the Communication Test menu, touch Run. The test runs one time, and the screen shows the result.

To run a test continuously, touch and hold your finger on Run. Drag your finger to Repetitive, then lift your finger. Touch Stop to stop Run Repetitive.

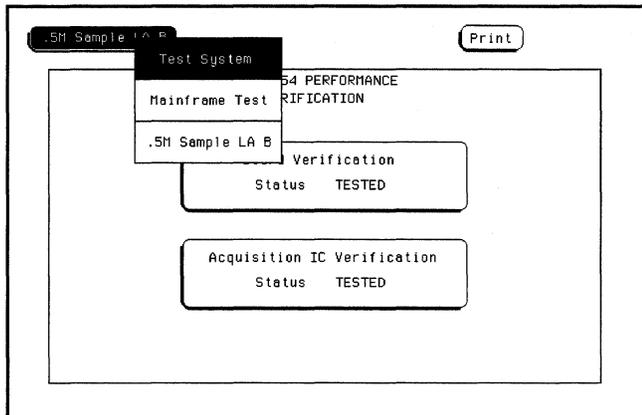


4 When the test is finished, touch Done. Then, perform the Resource, Encoder, Sequencer, and Chip Clock tests.

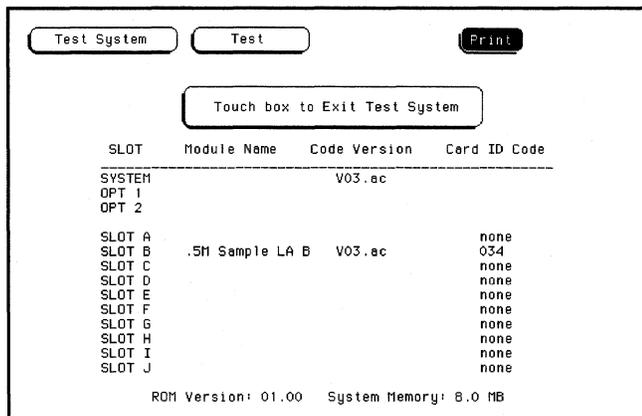
5 Touch Exit to leave the Acquisition IC Verification tests.

To exit the test system

- 1 To exit the Performance Verification menu, touch 1M Sample LA, then select Test System.



- 2 To exit the test system, touch Configuration, then select Test. Touch the box labeled Touch box to Exit Test System.



- 3 If you are performing the self-tests as part of the troubleshooting flowchart, return to troubleshooting flowchart 2, page 5-4.

To test the cables

This test allows you to functionally verify the probe cable and probe tip assembly of any of the logic analyzer pods. Only one probe cable can be tested at a time. Repeat this test for each probe cable to be tested.

Equipment Required

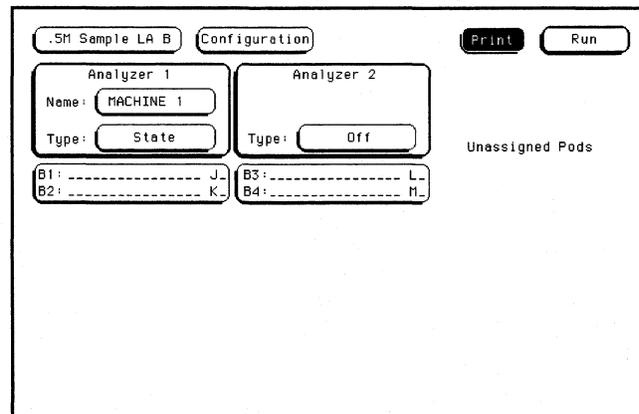
Equipment	Critical Specification	Recommended Model/Part
Pulse Generator	100 MHz, 3.5 ns pulse width, < 600 ps rise time	HP 8131A Option 020
6x2 Test Connectors (Qty 4)		

- 1 Turn on the equipment required and the logic analyzer.
- 2 Set up the pulse generator.
 - a Set up the pulse generator according to the following table.

Pulse Generator Setup

Channel 1	Channel 2	Period
Delay: 0 ps	Delay: 0 ps	100 ns
Dcyc: 50%	Dcyc: 50%	
High: 3.00 V	High: 3.00 V	
Low: 0.00 V	Low: 0.00 V	

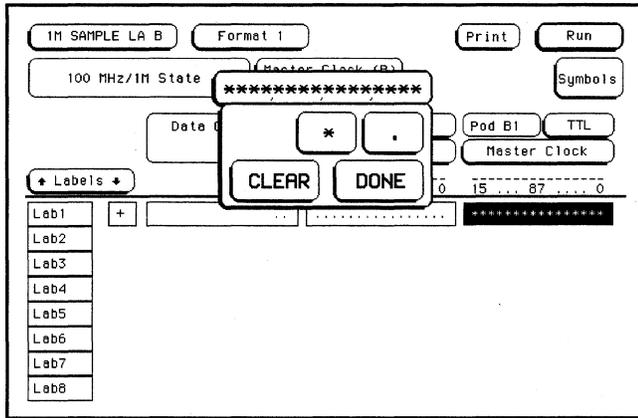
- b Enable the pulse generator channel 1 and channel 2 outputs (LED off).
- 3 Set up the logic analyzer Configuration menu.
 - a In the System Configuration menu, touch System, then select 1M Sample LA.
 - b In the Analyzer 1 box, touch the field to the right of Type, then select State.



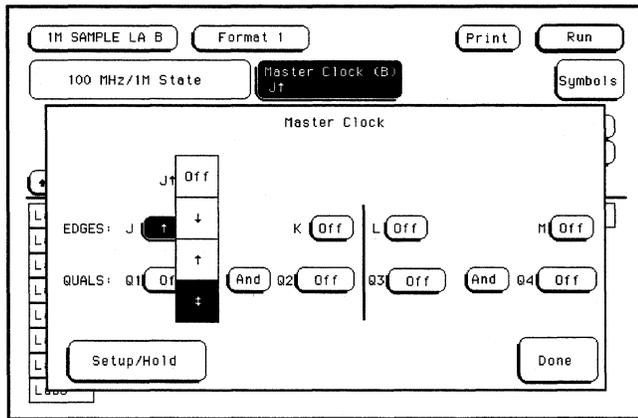
Troubleshooting
To test the cables

4 Set up the Format menu.

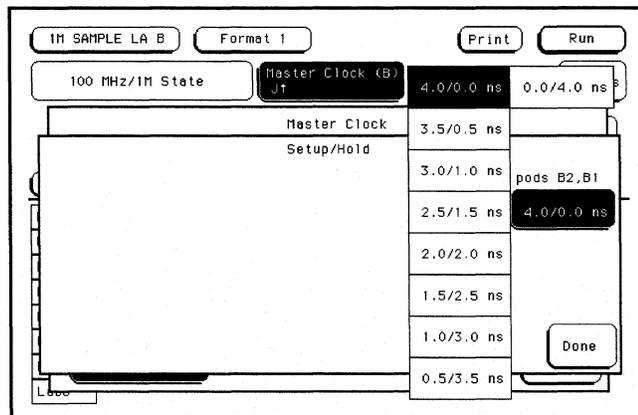
- a** Touch Configuration, then select Format.
- b** Touch the field showing the channel assignments for the pod under test. In the pop-up menu, touch the asterisk field to put asterisks in the channel positions, activating the channels. Touch Done.



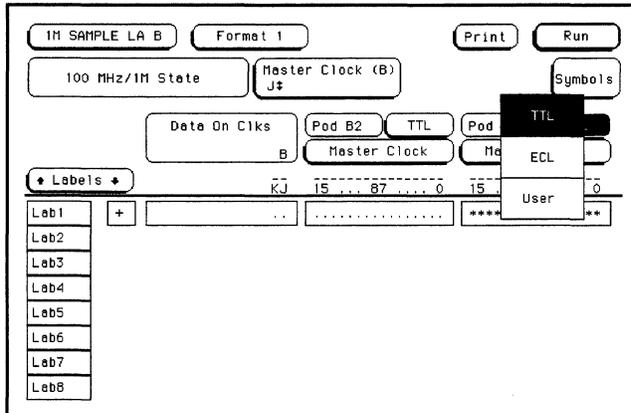
- c** Touch Master Clock, then select a double edge for the clock of the pod under test. Turn off the other clocks.



- d** Touch Setup/Hold, then select 4.0 ns/0.0 ns for the pod being tested. Touch Done. Touch Done again to exit the Master Clock menu.



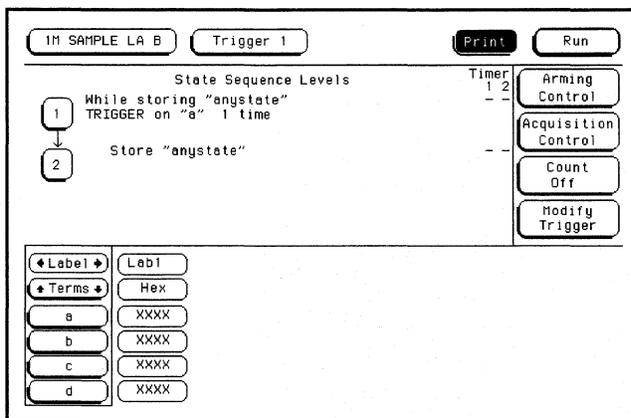
e Touch the field to the right of the pod being tested, then select TTL.



5 Set up the Trigger menu.

a Touch Format, then select Trigger.

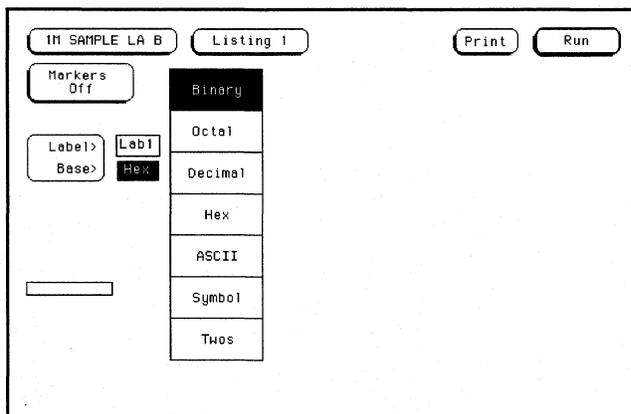
b Touch Modify Trigger, then select Clear Trigger, then select All.



6 Set up the Listing menu.

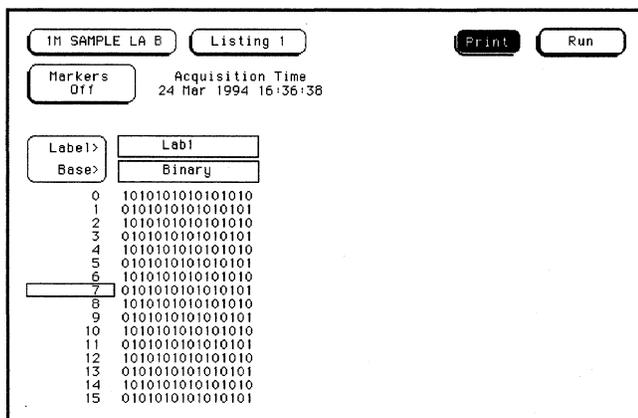
a Touch Trigger, then select Listing.

b Touch the field to the right of Base, then select Binary.



Troubleshooting
To test the cables

- 7 Using four 6-by-2 test connectors, connect the logic analyzer to the pulse generator channel outputs. To make the test connectors, 'see chapter 3, "Testing Performance."
 - a Connect the even-numbered channels of the lower byte of the pod under test to the pulse generator channel 1 Output.
 - b Connect the odd-numbered channels of the lower byte of the pod under test to the pulse generator channel 1 $\overline{\text{Output}}$.
 - c Connect the even-numbered channels of the upper byte of the pod under test and the clock channel to the pulse generator channel 2 Output.
 - d Connect the odd-numbered channels of the upper byte of the pod under test to the pulse generator channel 2 $\overline{\text{Output}}$.
- 8 On the logic analyzer, touch Run. The display should look similar to the figure below.



- 9 If the display looks like the figure, then the cable passed the test.
If the display does not look similar to the figure, then there is a possible problem with the cable or probe tip assembly. Causes for cable test failures include:
 - open channel.
 - channel shorted to a neighboring channel.
 - channel shorted to either ground or a supply voltage.Return to the troubleshooting flowchart.

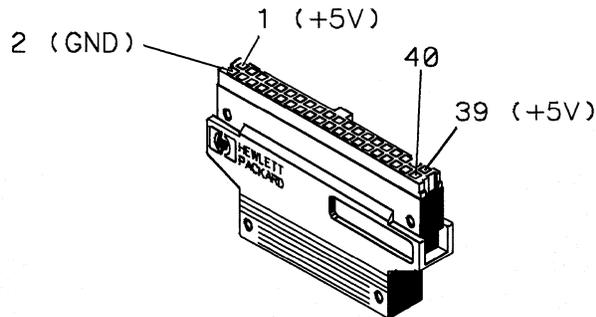
To test the auxiliary power

The +5 V auxiliary power is protected by a current overload protection circuit. If the current on pins 1 and 39 exceed 0.33 amps, the circuit will open. When the short is removed, the circuit will reset in approximately 1 minute. There should be +5 V after the 1 minute reset time.

Equipment Required

Equipment	Critical Specifications	Recommended Model/Part
Digital Multimeter	0.1 mV resolution, better than 0.005% accuracy	HP 3478A

- Using the multimeter, verify the +5 V on pins 1 and 39 of the probe cables.



MISC/EX50

- To remove the module 6-2
- To replace the circuit board 6-3
- To replace the module 6-3
- To replace the probe cable 6-5
- To replace the Reference Clock cable 6-6
- To return assemblies 6-7

Replacing Assemblies

This chapter contains the instructions for removing and replacing the logic analyzer module, the circuit board of the module, and the probe cables of the module. Also in this chapter are instructions for returning assemblies.

CAUTION

Turn off the instrument before installing, removing, or replacing a module in the instrument.

Tools Required

A T10 TORX screwdriver is required to remove screws connecting the probe cables and screws connecting the back panel.

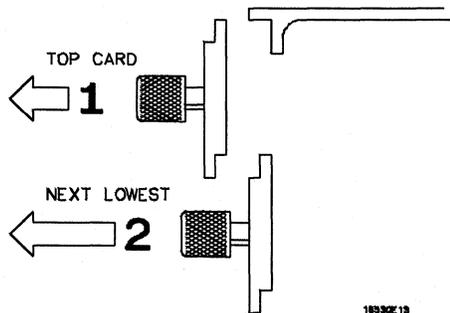
To remove the module

CAUTION

Electrostatic discharge can damage electronic components. Use grounded wriststraps and mats when performing any service to this module.

- 1 Turn off the instrument power switch, then unplug the power cord. Disconnect any input or output connections.
- 2 Loosen the thumb screws.

Starting from the top, loosen the thumb screws on the filler panels and cards located above the module and the thumb screws of the module.



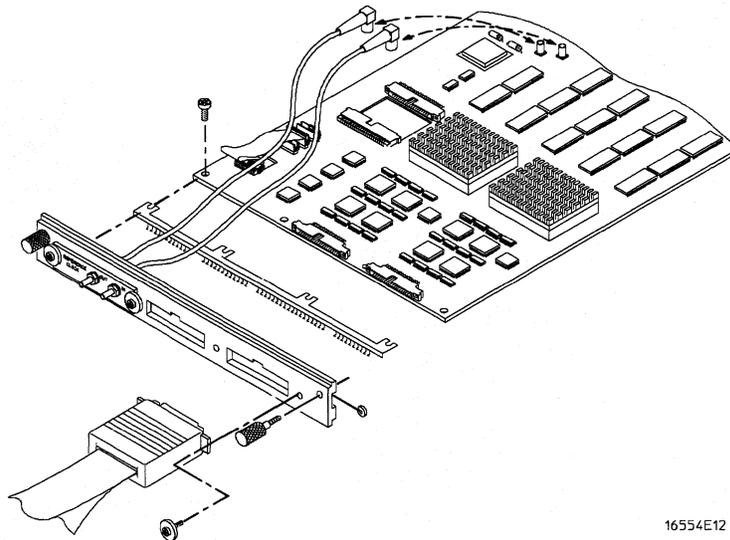
- 3 Starting from the top, pull the cards and filler panels located above the module half-way out.
- 4 If the module consists of a single card, pull the card completely out.
If the module consists of multiple cards, pull all cards completely out.
- 5 Push all other cards into the card cage, but not completely in.
This is to get them out of the way for removing and replacing the module.
- 6 If the module consist of a single card, remove the faulty card.
If the module consists of multiple cards, remove the cables from J9 and J10 of all cards. Remove the 2x10 cables from J5 and J7 from the master card. Remove the faulty card.

To replace the circuit board

- 1 Remove the three screws connecting the probe cables to the back panel, then disconnect the probe cables.
- 2 Remove the Reference Clock cables from connectors J12 and J13 on the circuit board.
- 3 Remove the four screws attaching the ground spring and back panel to the circuit board, then remove the back panel and the ground spring.
- 4 Replace the faulty circuit board with a new circuit board. On the faulty board, make sure the 20-pin ribbon cable is connected between J3 and J6.
- 5 Position the ground spring and back panel on the back edge of the replacement circuit board. Install four screws to connect the back panel and ground spring to the circuit board.
- 6 Connect the Reference Clock In cable to connector J13 on the circuit board. Connect the Reference Clock Out cable to J12 on the circuit board.
- 7 Connect the probe cables, then install three screws to connect the cables to the back panel.

CAUTION

If you over tighten the screws, the threaded inserts on the back panel might break off of the back panel. Tighten the screws only enough to hold the cable in place.

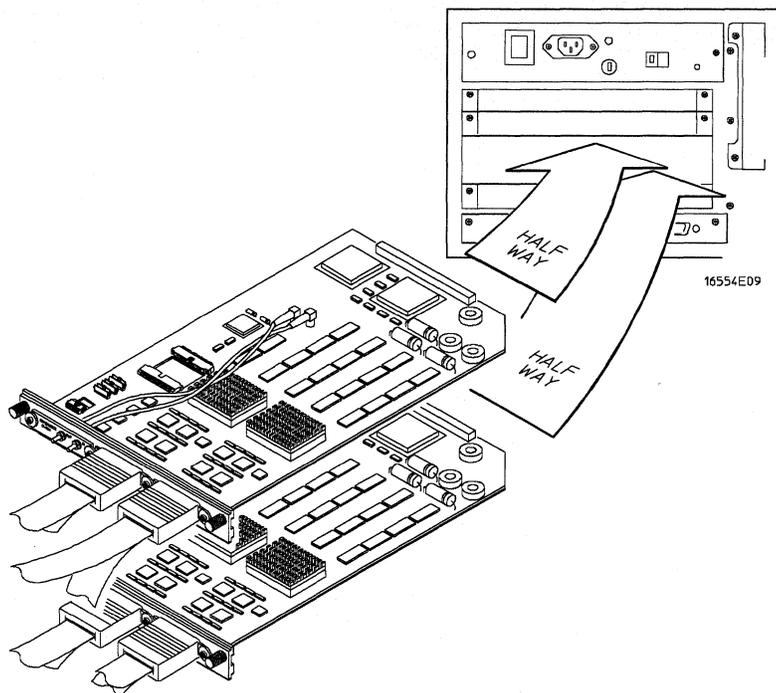


To replace the module

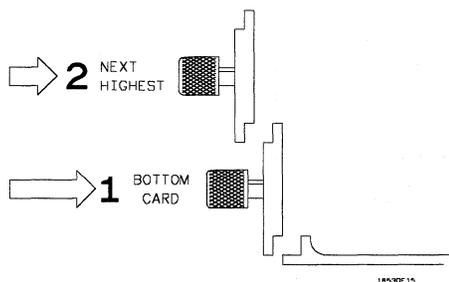
- 1 If the module consists of one card, go to step 2.
If the module consists of more than one card, connect the cables together in a master/expander configuration. Follow the procedure "To configure a multichannel module" in chapter 2.
- 2 Slide the cards above the slots for the module about halfway out of the mainframe.

Replacing Assemblies To replace the module

- 3 With the probe cables facing away from the instrument, slide the module approximately halfway into the mainframe.



- 4 Slide the complete module into the mainframe, but not completely in.
Each card in the instrument is firmly seated and tightened one at a time in step 6.
- 5 Position all cards and filler panels so that the endplates overlap.



- 6 Seat the cards and tighten the thumbscrews.

Starting with the bottom card, firmly seat the cards into the backplane connector of the mainframe. Keep applying pressure to the center of the card endplate while tightening the thumbscrews finger-tight. Repeat this for all cards and filler panels starting at the bottom and moving to the top.

CAUTION

Correct air circulation keeps the instrument from overheating. For correct air circulation, filler panels must be installed in all unused card slots. Keep any extra filler panels for future use.

To replace the probe cable

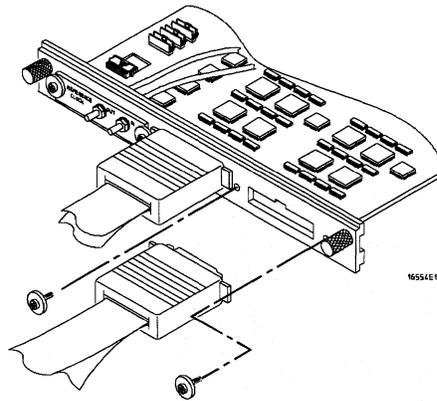
- 1 Turn off the instrument power switch, then unplug the power cord. Disconnect any input or output connections.
- 2 Remove the screws that hold the probe cable to the rear panel of the module.
- 3 Remove the faulty probe cable from the connector and install the replacement cable.
- 4 Install the label on the new probe.

If you order a new probe cable, you will need to order new labels. Probe cables shipped with the module are labeled. Probe cables shipped separately are not labeled. Refer to chapter 7, "Replaceable Parts," for the part numbers and ordering information.

- 5 Install the screws connecting the probe cable to the rear panel of the module.

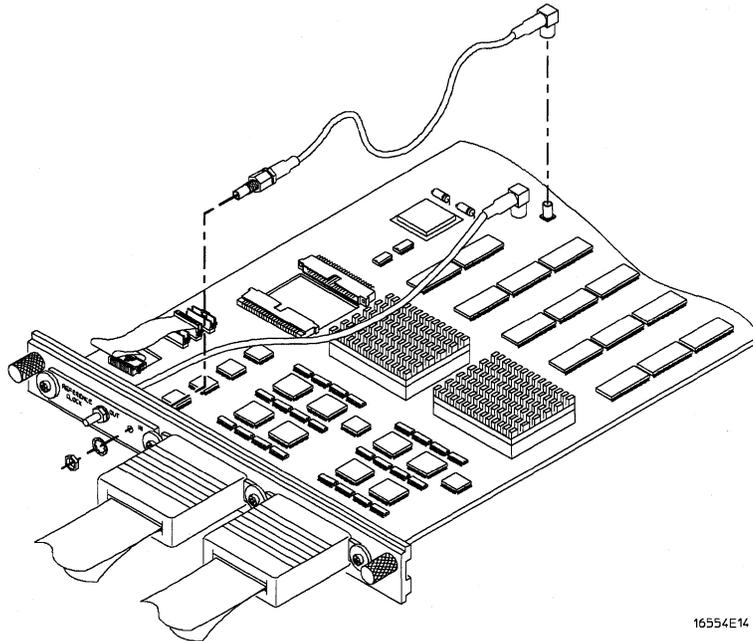
CAUTION

If you over tighten the screws, the threaded inserts on the back panel might break off of the back panel. Tighten the screws only enough to hold the cable in place.



To replace the Reference Clock cable

- 1 Remove the module from the mainframe. Follow the procedure "To remove the module" on page 6-2.
- 2 Unplug the faulty Reference Clock cable from the circuit board REF CLK OUT (J12) or REF CLK IN (J13) connector.
- 3 Using a 1/4 inch hollow shaft nutdriver, remove the nut that holds the cable to the module panel insert.
- 4 Remove and replace the faulty Reference Clock cable. Insert the connector nut and gently tighten the nut using the nutdriver.
- 5 Plug the replacement cable into the board REF CLK OUT (J12) or REF CLK IN (J13) connector.
- 6 Follow the procedure "To replace the module" to reinstall the module into the mainframe.



16554E14

To return assemblies

Before shipping the module to Hewlett-Packard, contact your nearest Hewlett-Packard sales office for additional details.

1 Write the following information on a tag and attach it to the module.

- Name and address of owner
- Model number
- Serial number
- Description of service required or failure indications

2 Remove accessories from the module.

Only return accessories to Hewlett-Packard if they are associated with the failure symptoms.

3 Package the module.

You can use either the original shipping containers, or order materials from an HP sales office.

For protection against electrostatic discharge, package the module in electrostatic material.

CAUTION

4 Seal the shipping container securely, and mark it FRAGILE.

Replaceable Parts Ordering 7-2
Replaceable Parts List 7-3
Exploded View 7-5

Replaceable Parts

This chapter contains information for identifying and ordering replaceable parts for your module.

Replaceable Parts Ordering

Parts listed

To order a part on the list of replaceable parts, quote the Hewlett-Packard part number, indicate the quantity desired, and address the order to the nearest Hewlett-Packard Sales Office.

Parts not listed

To order a part not on the list of replaceable parts, include the model number and serial number of the module, a description of the part (including its function), and the number of parts required. Address the order to your nearest Hewlett-Packard Sales Office.

Direct mail order system

To order using the direct mail order system, contact your nearest Hewlett-Packard Sales Office.

Within the USA, Hewlett-Packard can supply parts through a direct mail order system. The advantages to the system are direct ordering and shipment from the HP Part Center in Mountain View, California. There is no maximum or minimum on any mail order. (There is a minimum amount for parts ordered through a local Hewlett-Packard Sales Office when the orders require billing and invoicing.) Transportation costs are prepaid (there is a small handling charge for each order) and no invoices.

In order for Hewlett-Packard to provide these advantages, a check or money order must accompany each order. Mail order forms and specific ordering information are available through your local Hewlett-Packard Sales Office. Addresses and telephone numbers are located in a separate document shipped with the *HP 16500B/16501A Logic Analysis System Service Manual*.

Exchange Assemblies

Some assemblies are part of an exchange program with Hewlett-Packard.

The exchange program allows you to exchange a faulty assembly with one that has been repaired and performance verified by Hewlett-Packard.

After you receive the exchange assembly, return the defective assembly to Hewlett-Packard. A United States customer has 30 days to return the defective assembly. If you do not return the defective assembly within the 30 days, Hewlett-Packard will charge you an additional amount. This amount is the difference in price between a new assembly and that of the exchange assembly. For orders not originating in the United States, contact your nearest Hewlett-Packard Sales Office for information.

See Also

"To return assemblies," page 6-7.

Replaceable Parts List

The replaceable parts list is organized by reference designation and shows exchange assemblies, electrical assemblies, then other parts.

Information included for each part on the list consists of the following:

- Reference designator
- Hewlett-Packard part number
- Check Digit (CD)
- Total quantity included with the module (Qty)
- Description of the part

Reference designators used in the parts list are as follows:

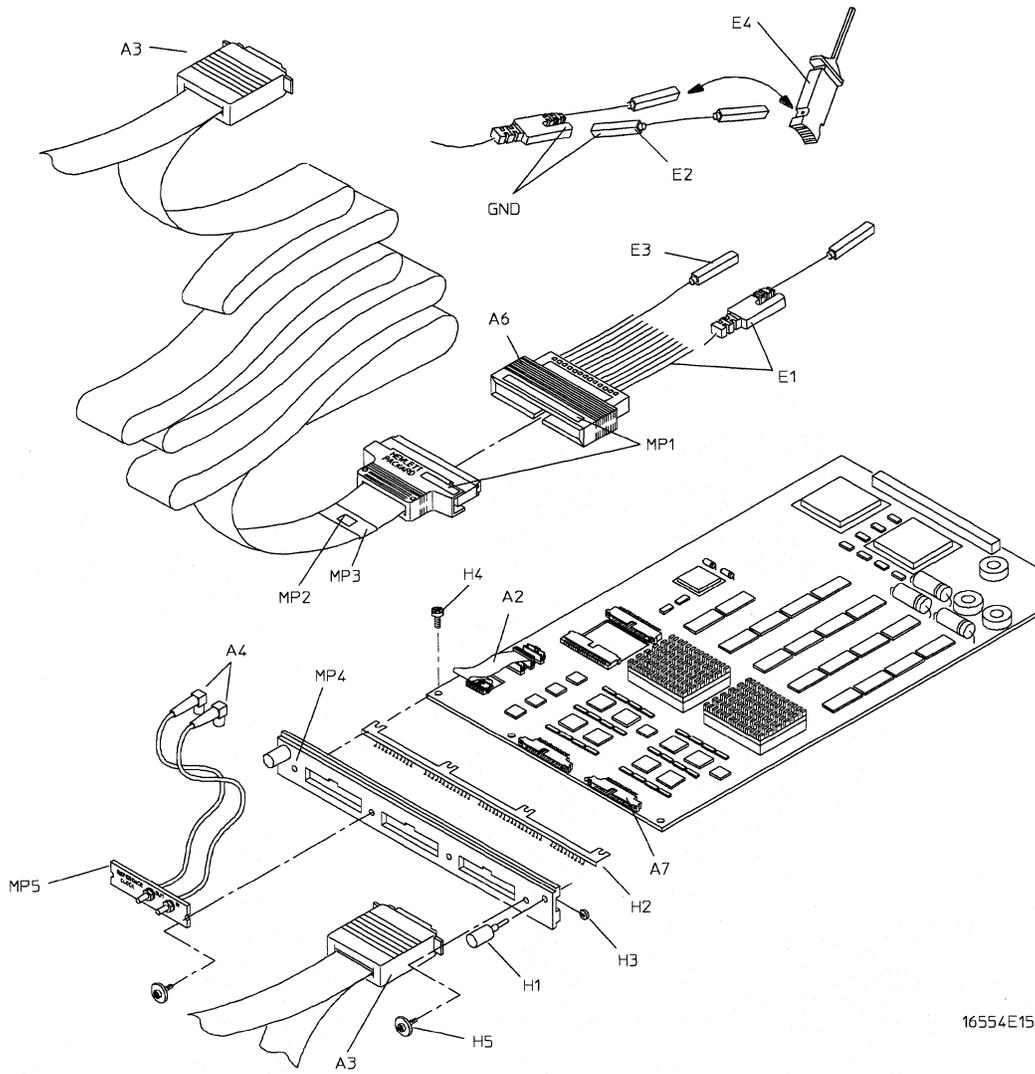
- A Assembly
- H Hardware
- J Connector
- MP Mechanical Part
- W Cable

Replaceable Parts
Replaceable Parts List

Replaceable Parts

Ref. Des.	HP Part Number	QTY	Description
	16555-69503	1	Exchange Board Assembly (HP 16555A)
A1	16555-66503	1	Board Assembly (HP 16555A)
A2	16555-61605	1	Cable Assembly (2x10)
A3	16555-61606	2	Cable Assembly-Logic Analyzer
A4	16555-61607	1	Cable Assembly-Internal Reference
A5	16555-61608	1	Cable Assembly-External Reference
A6	01650-61608	4	Probe Tip Assembly
A7	1252-4181	2	Probe Cable Socket - 50 pin
A8	16542-61607	1	Double Probe Adapter
A9	16555-68701	1	Cable Kit-Master/Expander
E1	5959-9333	1	Probe Leads Replace (5 Per Package)
E2	5959-9334	4	Probe Ground Replace (5 Per Package)
E3	5959-9335	0	Pod Ground Replace (2 Per Package)
E4	5090-4356	4	Grabber Kit Assembly (20 Grabbers Per Package)
H1	16500-22401	2	Panel Screw
H2	16550-29101	1	Ground Spring
H3	0510-0684	2	Retaining Ring
H4	0515-0430	4	MS M3.0X0.5X6MM PH T10 (Endplate Screw)
H5	0515-2306	4	Screw Sems M3 X 0.5X10mm (Cable Retaining Screw)
MP1	01650-94310	1	Label-Probe and Cable
MP2	16500-94303	1	Label-Cable Numbering
MP3	16500-41201	4	Ribbon Cable ID Clip
MP4	16550-40501	1	Module Panel
MP5	16555-07201	1	Module Panel Insert
MP6	16555-94301	1	Label-ID (HP 16555A)
MP7	7121-0850	4	Label-Antistatic
MP8	16555-60001	2	Ferrite Core Assembly

Exploded View



16554E15

Exploded view of the HP 16555A logic analyzer.

Block-Level Theory 8-2
Self-Tests Description 8-6

Theory of Operation

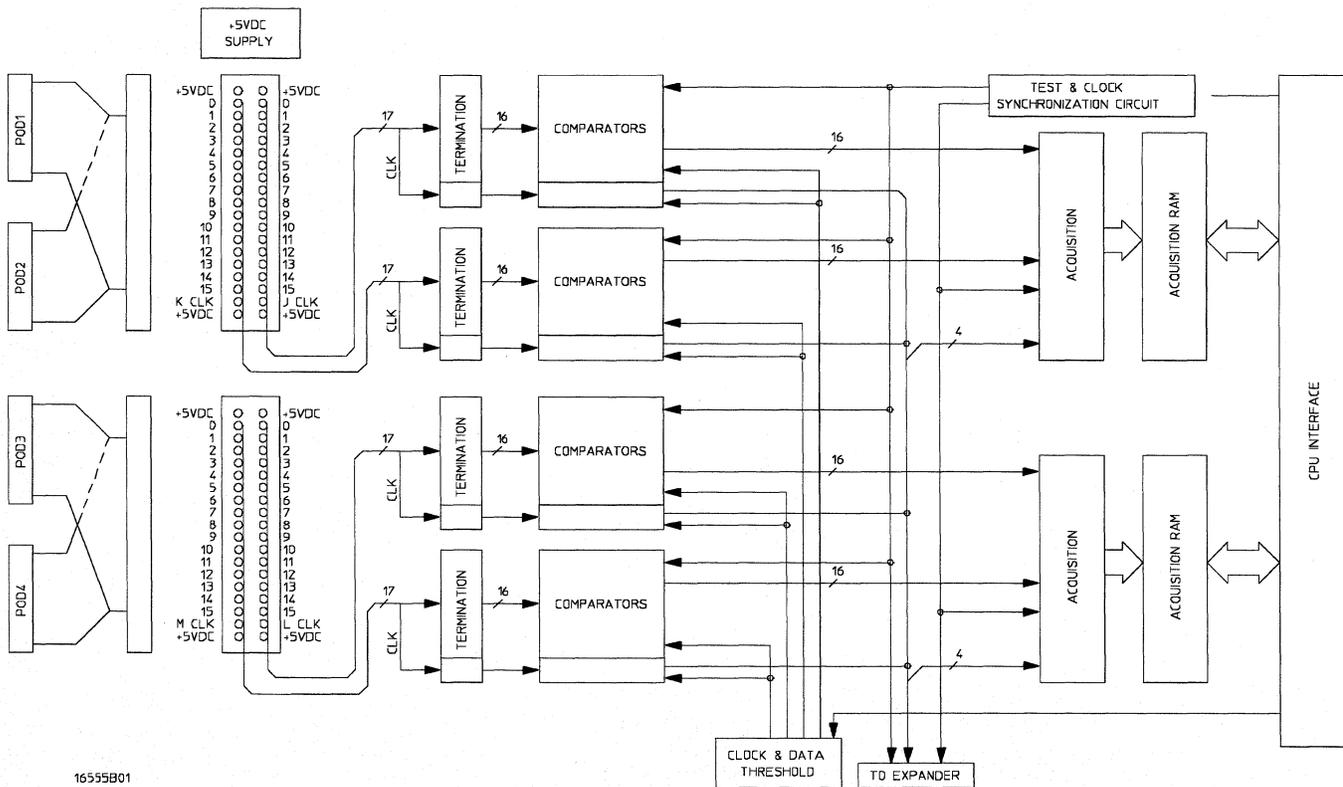
Theory of Operation

This chapter presents the theory of operation for the logic analyzer module and describes the self-tests. The information in this chapter is to help you understand how the module operates and what the self-tests are testing. This information is not intended for component-level repair.

Block-Level Theory

The block-level theory of operation is divided into two parts: theory for the logic analyzer used as a single-card module or as a master card in a multicard module, and theory for the logic analyzer used as an expander card in a multicard module. A block diagram is shown before each theory.

The HP 16555A logic analyzer



Probing The probing system consists of a tip network, a probe cable, and terminations which reside on the analyzer card. Each probe cable is made up of two woven cables, each one carrying 16 data channels and 1 clock/data channel. The four clock/data channels on each logic analyzer plus the 64 data channels on each logic analyzer card results in a maximum of 68 available data acquisition channels for each card.

Each channel of the probing system has its own ground. In addition the pod has a single ground. For applications where many channels are used (greater than three) and signal risetimes are less than 3 ns, individual channel grounds should be used.

The probe tip networks comprise a series of resistors (250 Ohm) connected to a parallel combination of a 90 K resistor and a 8.5 pF capacitor. The parallel 90 K and 8.5 pF capacitor along with the lossy cable and terminations form a divide-by-ten probe system. The 250 Ohm tip resistor is used to buffer (or raise the impedance of) the 8.5 pF capacitor that is in series with the cable capacitance.

Comparators Two 9-channel comparators interpret the incoming data and clock signals as either high or low, depending on where the user-programmable threshold is set. The threshold voltage of each pod is individually programmed, and the voltage selected applies to the clock channel as well as the data channels of each pod.

Each of the comparators has a serial test input port used for testing purposes. A test bit pattern is sent from the Test and Clock Synchronization Circuit to the comparators. The comparators then propagate the test signal on each of the nine channels of the comparator. Consequently, the operating system software can test all data and clock channel pipelines on the circuit board through the comparator.

Acquisition Each acquisition circuit is made up of a single acquisition IC. Each acquisition IC is a 34-channel state/timing logic analyzer. Two acquisition ICs are included on every logic analyzer card for a total of 64 data channels and 4 clock/data channels. All of the sequencing, storage qualification, pattern/range recognition and event counting functions are performed by the acquisition IC.

Also, the acquisition ICs perform master clocking functions. All four state acquisition clocks are sent to each acquisition IC, and the acquisition ICs generate their own sample clocks. Every time the user selects RUN, the acquisition ICs individually perform a clock optimization before data is stored.

Clock optimization involves using programmable delays in the acquisition ICs to position the master clock transition where valid data is captured. This procedure greatly reduces the effects of channel-to-channel skew and other propagation delays.

In the timing acquisition mode, an oscillator-driven clock circuit provides a four-phase 125-MHz clock signal to each of the acquisition ICs. For high speed timing acquisition (125 MHz and faster), the four-phase 125-MHz clock signal determines the sample period. For slower sample rates, one of the two acquisition ICs divides the 125-MHz clock signal to the appropriate sample rate. The sample clock is then sent to the other acquisition ICs.

Acquisition RAM The acquisition RAM is external to the acquisition IC. In the HP 16555A, the acquisition RAM consists of 18 RAM ICs (128K x 16). A memory management circuit controls RAM addressing during an acquisition run and during data upload to the HP 16500B CPU.

Test and Clock Synchronization Circuit ECLinPS (ECL in pico seconds) ICs are used in the Test and Clock Synchronization Circuit for reliability and low channel-to-channel skew. Test patterns are generated and sent to the comparators during software operation verification (self-tests). The test patterns are propagated across all data and clock channels and read by the acquisition ICs to verify that the data and clock pipelines are operating correctly.

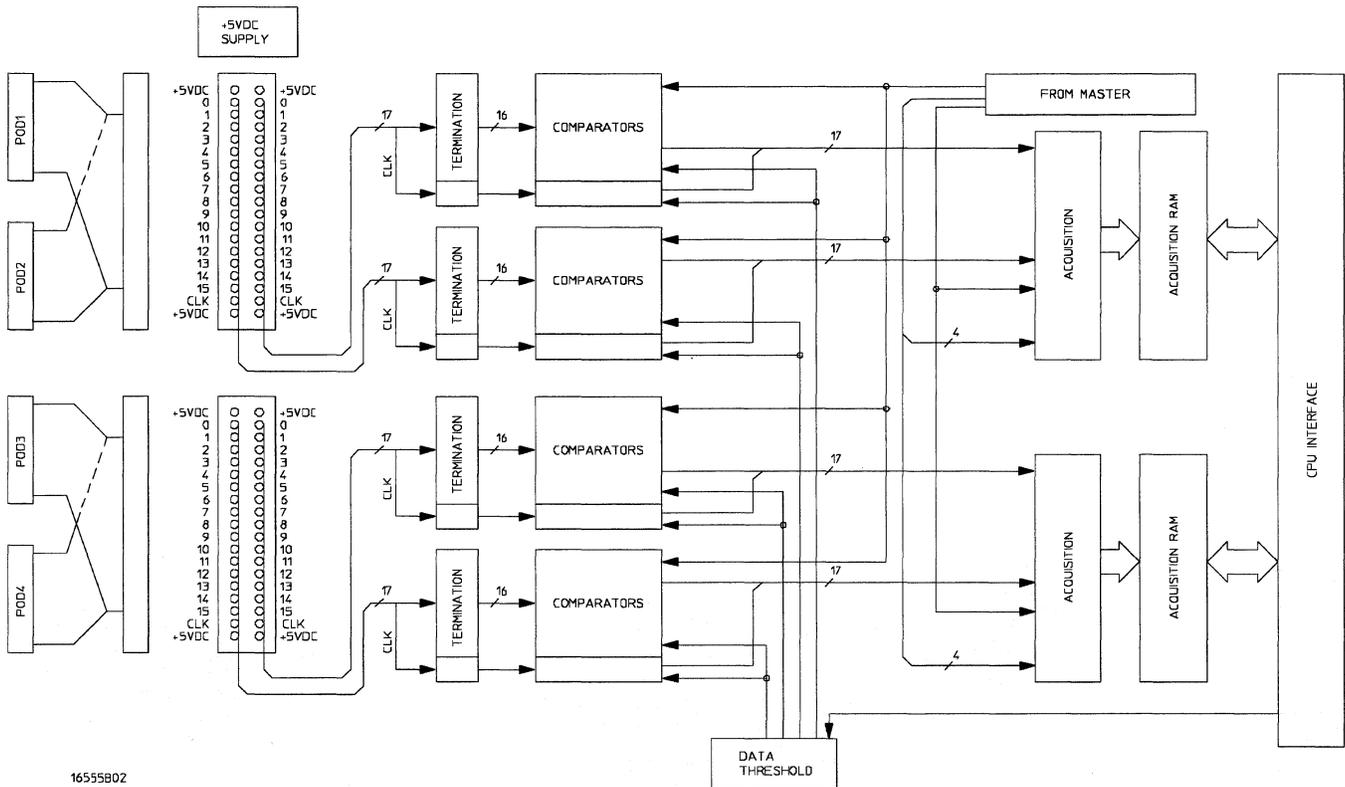
Also, the Test and Clock Synchronization Circuit generates a four-phase 125-MHz sample/synchronization signal for the acquisition ICs operating in the timing acquisition mode. At fast sample rates, the synchronizing signal keeps the internal clocking of the individual acquisition ICs locked in step with the other acquisition ICs in the module. At slower sample rates, one of the acquisition ICs divides the 125-MHz clock signal to the appropriate sample rate. The slow speed sample clock is then used by both acquisition ICs.

Clock and Data Threshold The threshold circuit includes a precision octal DAC and precision op amp drivers. Each of the eight channels of the DAC is individually programmable which allows the user to set the thresholds of the individual pods. The 16 data channels and the clock/data channel of each pod are all set to the same threshold voltage.

CPU Interface The CPU interface is a programmable logic device that converts the bus signals generated by the microprocessor on the HP 16500B mainframe CPU card into control signals for the logic analyzer card. All functions of the state and timing card can be controlled from the backplane of the mainframe system including storage qualification, sequencing, assigning clocks and qualifiers, RUN and STOP, and thresholds. Data transfer between the logic analyzer card and the mainframe CPU card is also accomplished through the CPU interface.

+5 VDC supply The +5 VDC supply circuit supplies power to active logic analyzer accessories such as preprocessors. Thermistors on the +5 VDC supply lines and on the ground return line protect the logic analyzer and the active accessory from overcurrent conditions. When an overcurrent condition is sensed, the thermistors create an open that shuts off the current from the +5 VDC supply. After a reset time of approximately 1 minute, the thermistor closes the circuit and makes the supply current available.

The HP 16555A logic analyzer as an expander



16555B02

The logic analyzers can be connected together in multi-card master/expander configuration. All of the functions of the logic analyzer configured as a master are retained by the logic analyzer configured as an expander with a few exceptions. As a master and expander multi-card logic analyzer module, most of the supporting circuitry on the expander configured card is disabled to allow both the master and expander cards to operate together as one module with no compromise in functionality in 136-channel or 204-channel configurations. The same signals that drive the acquisition ICs on the master configured card also drive the acquisition ICs on the expander configured card.

Acquisition The four clocks sent to the master card are also sent to the acquisition ICs on the expander card. The acquisition ICs on the expander card individually generate their own sample clock for the state acquisition mode. For timing acquisition mode, the master card also passes the synchronization signal to the expander card.

The four clock/data lines on the expander card pods are not available for either state mode clocking or state clock qualification. However, the four clock/data lines are still available as data channels.

Test and Clock Synchronization Circuit The signals generated by the Test and Clock Synchronization Circuit of the master card are sent to the expander card. Consequently, the Test and Clock Synchronization Circuit on the expander card is disabled to allow the master configured card to drive the expander configured card. The functionality of the Test and Clock Synchronization Circuit remains the same, but the circuit drives up to four more Acquisition IC and up to eight more comparator test inputs.

Threshold The thresholds of each of the expander card pods are individually programmable, as with the master card pods. The threshold of the data and clock/data channels of each pod is set to the same threshold voltage. The clock/data channel on each pod of the expander card is available only as a data channel.

Self-Tests Description

The self-tests for the logic analyzer identify the correct operation of major functional areas in the module. There are two sets of self-tests: the Board Verification Tests and the Acquisition IC Verification Tests. The self-tests are not intended for component-level diagnostics.

Board Verification Tests

The Board Verification Tests functionally verify the main subsystems of the module other than the acquisition ICs. Four tests are performed on the module subsystems. The tests are the PLD, Oscillator, Data Memory, and Comparators Tests

PLD Test Programmable Logic Devices (PLD) are utilized as an interface between the HP 16500B Logic Analysis System backplane and the logic analyzer module. The PLD Test verifies the operation of the data bus through the PLD. Test patterns are sent to the module and are written to a block of module memory. The patterns are then read and compared with known values. Also, a HW acceleration test verifies the PLD's high speed pattern search operation.

Passing the PLD Test implies that the PLD is not corrupted and that data can be passed between the logic analyzer module and the backplane of the 16500B mainframe.

Oscillator Test The Oscillator Test functionally verifies the two oscillators and the oscillator internal pathways on the logic analyzer module. The oscillators are checked using the event counter on one of the acquisition ICs. The event counter will count the number of oscillator periods within a pre-determined time window. The count of oscillator periods is then compared with a known value.

Passing the Oscillator Test implies that both oscillators on the logic analyzer module are operating properly.

Data Memory Test After verifying the integrity of the memory address bus, the acquisition RAM is checked by filling the RAM with a checkerboard pattern of "1s" and "0s," then reading each memory location and comparing the test pattern with known values. Then the RAM is filled with an inverse checkerboard pattern, read, and compared with known values. The acquisition ICs are then used to generate a walking "1s" pattern, which is stored in RAM. The patterns are then read and compared with known values.

Passing the memory test implies that the acquisition RAM is functioning and that each memory location bit can hold either a logic "1" or logic "0." Passing this test also implies that the RAM is addressable by both the acquisition ICs and the mainframe CPU system through the CPU interface.

Alignment Test The alignment test exercises the clock optimization circuit on-board the acquisition IC. A test signal is generated by the comparators and sent to the acquisition IC. A test run is then done to see if the clock optimization circuit aligns the data signal with the master clock signal.

Passing the alignment test implies the clock optimization circuit that resides on the acquisition IC operates properly. Consequently the acquisition IC can properly sample data with minimal channel-to-channel skew.

Comparators Test The comparators in the logic analyzer front end are checked by varying the threshold voltage and reading the state of the activity indicators. The output of the comparator DAC is set to the upper voltage limit and the activity indicators for all the pod channels are read to see if they are all in a low state.

The DAC output is then set to the lower voltage limit, and the activity indicators are read to see if they are in a high state. The DAC output is then set to 0.0 V, allowing the comparators to recognize the test signal being routed to the test input pin of all of the comparators. Consequently, the activity indicators are read to see if they show activity on all channels of all the pods.

If the Comparators Test reveals that a logic analyzer channel is not recognizing the test data, a message will appear alerting the user that the channel is not operating as expected. If the module cannot be immediately serviced, then the user is alerted so that the failed channel would not be used until the module can be serviced.

Passing the Comparators Test implies that the logic analyzer front end is operating properly and all channels are capable of passing data to the acquisition ICs.

Acquisition IC Verification Tests

During the Acquisition IC Verification Tests, five tests are performed on the acquisition ICs. The tests are the Communications, Encoder, Resource, Sequencer, and Clock Tests.

Communication Test The communication test verifies that communications pipeline between the various subsystems of the IC are operating. Checkerboard patterns of "1s" and "0s" are routed to the address and data busses and to the read/write registers of each chip. After verifying the communications pipelines, the acquisition clock synchronization signals that are routed from IC to IC are checked. Finally, the IC master clock optimization path is checked and verified.

Passing the communication test implies that the communications pipelines running from subsystem to subsystem on the acquisition IC are functioning and that the clock optimization circuit on the IC is functioning. Also, passing this test implies that the acquisition clock synchronization signals are functioning and appear at the synchronization signal output pins of the acquisition IC.

Encoder Test The encoder is tested and verified using a walking "1" and walking "0" pattern. The walking "1" and "0" is used to stimulate all of the encoder output pins which connect directly to the memory ICs. Additionally, the post-store counter in each of the acquisition ICs is tested.

Passing the encoder test implies that the encoder is functioning and can properly route the acquired data to the acquisition memory. Also, passing this test implies that the post-store counter on the acquisition ICs is functioning.

Resource Test The pattern, range, edge, and glitch recognizers are tested and verified. First, an on-chip test register is verified for correct operation. Next, the pattern comparators are tested to ensure that each bit in the recognizer as well as the logic driver/receiver are operating. The edge and glitch pattern detectors are then verified in a similar manner. The range detectors are verified with their combinational logic to ensure that the in- and out-of-range conditions are recognized.

Passing the resource test implies that all of the pattern, range, edge, and glitch resources are operating and that an occurrence of the pattern, edge, or glitch of interest is recognized. Also, passing this test implies that the range recognizers will detect and report in- and out-of-range acquisition data to the sequencer or storage qualifier. The drivers and receivers at the recognizer input and output pins of the acquisition IC are also checked to be sure they are functioning.

Sequencer Test The sequencer, the state machine that controls acquisition storage, is tested by first verifying that all of the sequencer registers are operating. After the registers are checked, the combinational logic of the storage qualification is verified. Then, both the occurrence counter and the sequencer level counter is checked.

Passing the sequencer test implies that all 12 available sequence levels are functioning and that all possible sequence level jumps can occur. Also, passing this test implies that user-defined ANDing and ORing of storage qualified data patterns will occur, and that the occurrence counter that appears at each sequence level is functioning.

Chip Clock Test The sample clock generator on the acquisition ICs are tested by first checking the operation of the clock optimization circuit. The state acquisition clock paths are then checked to ensure that each state clock and clock qualifier are operating by themselves and in all possible clock and qualifier combinations. The timing acquisition optimization circuit is then operationally verified. Finally, the timing acquisition frequency divider (for slower timing sample rates) is checked.

Passing the chip clock test implies that each acquisition IC can generate its own master clock whether the clock is generated using a combination of external clocking signals (state mode) or internal sample clock signals (timing mode).

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Safety Symbols



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Hazardous voltage symbol.



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All pages original edition

